

Company: Samsung Electronics Co., Ltd.

Test of: WEA524i

To: FCC CFR 47 Part 15 Subpart E 15.407, ISSED RSS-247

Report No.: CTKL04-U2 Rev A (Limited to DFS testing)

DFS TEST REPORT



DFS TEST REPORT



Test of: Samsung Electronics Co., Ltd. WEA524i

to

To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS 247

Test Report Serial No.: CTKL04-U2 Rev A (Limited to DFS testing)

This report supersedes: NONE

Applicant: Samsung Electronics Co., Ltd.
129, Samsung-ro Yeongtong-gu,
Suwon-si, Gyeonggi-do
16677 South Korea

Issue Date: 16th August 2017

This Test Report is Issued Under the Authority of:

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MiCOM Labs is an ISO 17025 Accredited Testing Laboratory



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 3 of 177

Table of Contents

1. ACCREDITATION, LISTINGS & RECOGNITION.....	4
1.1. TESTING ACCREDITATION.....	4
1.2. RECOGNITION	5
1.3. PRODUCT CERTIFICATION	6
2. DOCUMENT HISTORY	7
3. TEST RESULT CERTIFICATE.....	8
4. REFERENCES AND MEASUREMENT UNCERTAINTY	9
4.1. Normative References	9
4.2. Test and Uncertainty Procedure	10
5. PRODUCT DETAILS AND TEST CONFIGURATIONS.....	11
5.1. Technical Details	11
5.2. Scope Of Test Program	12
5.3. Equipment Model(s) and Serial Number(s)	13
5.4. Antenna Details	13
5.5. Cabling and I/O Ports	13
5.6. Test Configurations.....	14
5.7. Equipment Modifications	14
5.8. Deviations from the Test Standard	14
6. TEST SUMMARY	15
7. TEST EQUIPMENT CONFIGURATION(S)	16
7.1. DFS - Radiated	16
8. MEASUREMENT AND PRESENTATION OF TEST DATA	19
9. TEST RESULTS	20
9.1. Dynamic Frequency Selection (DFS)	20
9.1.1. Master Devices	21
9.1.2. Client Devices	22
9.1.3. DFS Detection Thresholds.....	22
9.1.4. Response Requirements	23
9.1.5. Radar Test Waveforms	24
9.1.5.1. Short Radar Pulses	24
9.1.5.2. Long Radar Pulse Test.....	25
9.1.5.3. Frequency Hopping Radar Test Waveform.....	27
9.1.6. Radar Waveform Calibration.....	27
9.1.7. Channel Availability Check	28
9.1.7.1. Initial CAC.....	28
9.1.7.2. Beginning CAC	30
9.1.7.3. End CAC.....	32
9.1.8. Channel Close / Transmission Time	34
9.1.9. Non-Occupancy Period.....	36
9.1.10. Probability of Detection	38
9.1.11. Detection Bandwidth	65
A. APPENDIX – RADAR SIGNATURES	71

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 4 of 177

1. ACCREDITATION, LISTINGS & RECOGNITION

1.1. TESTING ACCREDITATION

MiCOM Labs, Inc. is an accredited Electrical testing laboratory per the international standard ISO/IEC 17025:2005. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.01. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-01.pdf>



Accredited Laboratory

A2LA has accredited

MICOM LABS

Pleasanton, CA

for technical competence in the field of

Electrical Testing

This laboratory is accredited in accordance with the recognized International Standard ISO/IEC 17025:2005 General requirements for the competence of testing and calibration laboratories. This accreditation demonstrates technical competence for a defined scope and the operation of a laboratory quality management system (refer to joint ISO-ILAC-IAF Communiqué dated 8 January 2009).



Presented this 4th day of February 2016.

Senior Director of Quality & Communications
For the Accreditation Council
Certificate Number 2381.01
Valid to November 30, 2017

For the tests or types of tests to which this accreditation applies, please refer to the laboratory's Electrical Scope of Accreditation.

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 5 of 177

1.2. RECOGNITION

MiCOM Labs, Inc. has widely recognized wireless testing capabilities. Our international recognition includes Conformity Assessment Body designation by APEC MRA countries. MiCOM Labs test reports are accepted globally.

Country	Recognition Body	Status	Phase	Identification No.
USA	Federal Communications Commission (FCC)	TCB	-	US0159 Listing #: 102167
Canada	Industry Canada (IC)	FCB	APEC MRA 2	US0159 Listing #: 4143A-2 4143A-3
Japan	MIC (Ministry of Internal Affairs and Communication)	CAB	APEC MRA 2	RCB 210
	VCCI	--	--	A-0012
Europe	European Commission	NB	EU MRA	NB 2280
Australia	Australian Communications and Media Authority (ACMA)	CAB	APEC MRA 1	US0159
Hong Kong	Office of the Telecommunication Authority (OFTA)	CAB	APEC MRA 1	
Korea	Ministry of Information and Communication Radio Research Laboratory (RRL)	CAB	APEC MRA 1	
Singapore	Infocomm Development Authority (IDA)	CAB	APEC MRA 1	
Taiwan	National Communications Commission (NCC) Bureau of Standards, Metrology and Inspection (BSMI)	CAB	APEC MRA 1	
Vietnam	Ministry of Communication (MIC)	CAB	APEC MRA 1	

EU MRA – European Union Mutual Recognition Agreement.

NB – Notified Body

APEC MRA – Asia Pacific Economic Community Mutual Recognition Agreement. Recognition agreement under which test lab is accredited to regulatory standards of the APEC member countries.

Phase I - recognition for product testing

Phase II – recognition for both product testing and certification

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1.3. PRODUCT CERTIFICATION

MiCOM Labs, Inc. is an accredited Product Certification Body per the international standard ISO/IEC 17065:2012. The company is accredited by the American Association for Laboratory Accreditation (A2LA) www.a2la.org test laboratory number 2381.02. MiCOM Labs test schedule is available at the following URL; <http://www.a2la.org/scopepdf/2381-02.pdf>



United States of America – Telecommunication Certification Body (TCB)
Industry Canada – Certification Body, CAB Identifier – US0159
Europe – Notified Body (NB), NB Identifier - 2280
Japan – Recognized Certification Body (RCB), RCB Identifier - 210



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 7 of 177

2. DOCUMENT HISTORY

Document History		
Revision	Date	Comments
Draft	9 th August 2017	Report limited to DFS testing only.
Rev A	16 th August 2017	Initial Release

In the above table the latest report revision will replace all earlier versions.

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 8 of 177

3. TEST RESULT CERTIFICATE

Manufacturer: Samsung Electronics Co., Ltd. 129, Samsung-ro Yeongtong-gu, Suwon-si, Gyeonggi-do 16677 South Korea	Tested By: MiCOM Labs, Inc. 575 Boulder Court Pleasanton California 94566 USA
Model: WEA524i	Telephone: +1 925 462 0304 Fax: +1 925 462 0306
Type Of Equipment: WLAN Access Point	
S/N's: S633503266	
Test Date(s): 31 st July 2017 – 8 th August 2017	Website: www.micomlabs.com

STANDARD(S)	TEST RESULTS
FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS 247 (DFS Testing Only)	EQUIPMENT COMPLIES

MiCOM Labs, Inc. tested the equipment mentioned in accordance with the requirements set forth in the above standards. Test results indicate that the equipment tested is capable of demonstrating compliance with the requirements as documented within this report.

Notes:

1. This document reports conditions under which testing was conducted and the results of testing performed.
2. Details of test methods used have been recorded and kept on file by the laboratory.
3. Test results apply only to the item(s) tested.

Approved & Released for MiCOM Labs, Inc. by:

Graeme Grieve
Quality Manager MiCOM Labs, Inc.

Gordon Hurst
President & CEO MiCOM Labs, Inc.



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4. REFERENCES AND MEASUREMENT UNCERTAINTY

4.1. Normative References

REF.	PUBLICATION	YEAR	TITLE
I	KDB 662911 D01 & D02	Oct 31 2013	Guidance for measurement of output emission of devices that employ single transmitter with multiple outputs or systems with multiple transmitters operating simultaneously in the same frequency band
II	KDB 905462 D07 v02	22nd August 2016	Test guidance to demonstrate compliance for U-NII devices subject to DFS requirements.
III	KDB 926956 D01 v02	22nd August 2016	U-NII Device Transition Plan
IV	KDB 789033 D02 v01r04	2nd May 2017	Guidelines for compliance testing of Unlicensed National Information Infrastructure (U-NII) Devices (Part 15, Subpart E)
V	A2LA	June 2015	R105 - Requirement's When Making Reference to A2LA Accreditation Status
VI	ANSI C63.10	2013	American National Standard for Testing Unlicensed Wireless Devices
VII	ANSI C63.4	2014	American National Standards for Methods of Measurement of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the Range of 9 kHz to 40 GHz
VIII	CISPR 32	2012	Electromagnetic compatibility of multimedia equipment - Emission requirements
IX	ETSI TR 100 028	2001-12	Parts 1 and 2 Electromagnetic compatibility and Radio Spectrum Matters (ERM); Uncertainties in the measurement of mobile radio equipment characteristics
X	FCC 06-96	Jun 30 2006	Memorandum Opinion and Order
XI	FCC 47 CFR Part 15.407	2016	Radio Frequency Devices; Subpart E –Unlicensed National Information Infrastructure Devices
XII	ICES-003	Issue 6 Jan 2016	Spectrum Management and Telecommunications; Interference-Causing Equipment Standard. Information Technology Equipment (Including Digital Apparatus) – Limits and methods of measurement.
XIII	M 3003	Edition 3 Nov.2012	Expression of Uncertainty and Confidence in Measurements
XIV	RSS-247 Issue 2	Feb 2017	Digital Transmission Systems (DTSS), Frequency Hopping System (FHSs) and License-Exempt Local Area Network (LE-LAN) Devices
XV	RSS-Gen Issue 4	November 2014	General Requirements and Information for the Certification of Radiocommunication Equipment
XVI	KDB 644545 D03 v01	August 14th 2014	Guidance for IEEE 802.11ac New Rules
XVII	FCC 47 CFR Part 2.1033	2016	FCC requirements and rules regarding photographs and test setup diagrams.
XVIII	KDB 905462 D02 v02	April 8 2016	Compliance Measurement Procedures for Unlicensed National Information Infrastructure devices operating in the 5250 to 5350 MHz and 5470 to 5725 MHz bands incorporating Dynamic Frequency Selection.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 10 of 177

4.2. Test and Uncertainty Procedure

Conducted and radiated emission measurements were conducted in accordance with American National Standards Institute ANSI C63.4, listed in the Normative References section of this report.

Measurement uncertainty figures are calculated in accordance with ETSI TR 100 028 Parts 1 and 2.

Measurement uncertainties stated are based on a standard uncertainty multiplied by a coverage factor $k = 2$, providing a level of confidence of approximately 95 % in accordance with UKAS document M 3003 listed in the Normative References section of this report.

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 11 of 177

5. PRODUCT DETAILS AND TEST CONFIGURATIONS

5.1. Technical Details

Details	Description
Purpose:	Test of the Samsung Electronics Co., Ltd. WEA524i to FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS 247 Compliance Measurement Procedures for Unlicensed National Information Infrastructure devices operating in the 5250 to 5350 MHz and 5470 to 5725 MHz bands incorporating Dynamic Frequency Selection.
Applicant:	Samsung Electronics Co., Ltd. 129, Samsung-ro Yeongtong-gu, Suwon-si, Gyeonggi-do 16677 South Korea
Manufacturer:	Samsung Electronics Co., Ltd.
Laboratory performing the tests:	MiCOM Labs, Inc. 575 Boulder Court Pleasanton California 94566 USA
Test report reference number:	CTKL04-U2
Date EUT received:	19 th July 2017
Standard(s) applied:	FCC CFR 47 Part 15 Subpart E 15.407, ISSED RSS-247
Dates of test (from - to):	31 st July 2017 – 8 th August 2017
No of Units Tested:	1
Product Family Name:	WEA524i
Model(s):	WEA524i
Location for use:	Indoor and Outdoor
Frequency Range(s):	5250 - 5350 MHz; 5470 - 5725 MHz
Type of Modulation:	OFDM
EUT Modes of Operation:	802.11a, 802.11n HT-20, 802.11n HT-40, 802.11ac-20, 802.11ac-40, 802.11ac-80, 802.11ac-160,
Declared Nominal Output Power	22.54 dBm
Transmit/Receive Operation:	Transceiver
Rated Input Voltage and Current:	48 Vdc @ 0.5 A
Operating Temperature Range:	0°C to 45°C
ITU Emission Designator:	20MD2D, 40MD2D, 80MD2D, 160MD2D
Equipment Dimensions:	203 x 203 x 45 mm
Weight:	0.55 Kg
Software Rev:	0.9.8.T

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5.2. Scope Of Test Program

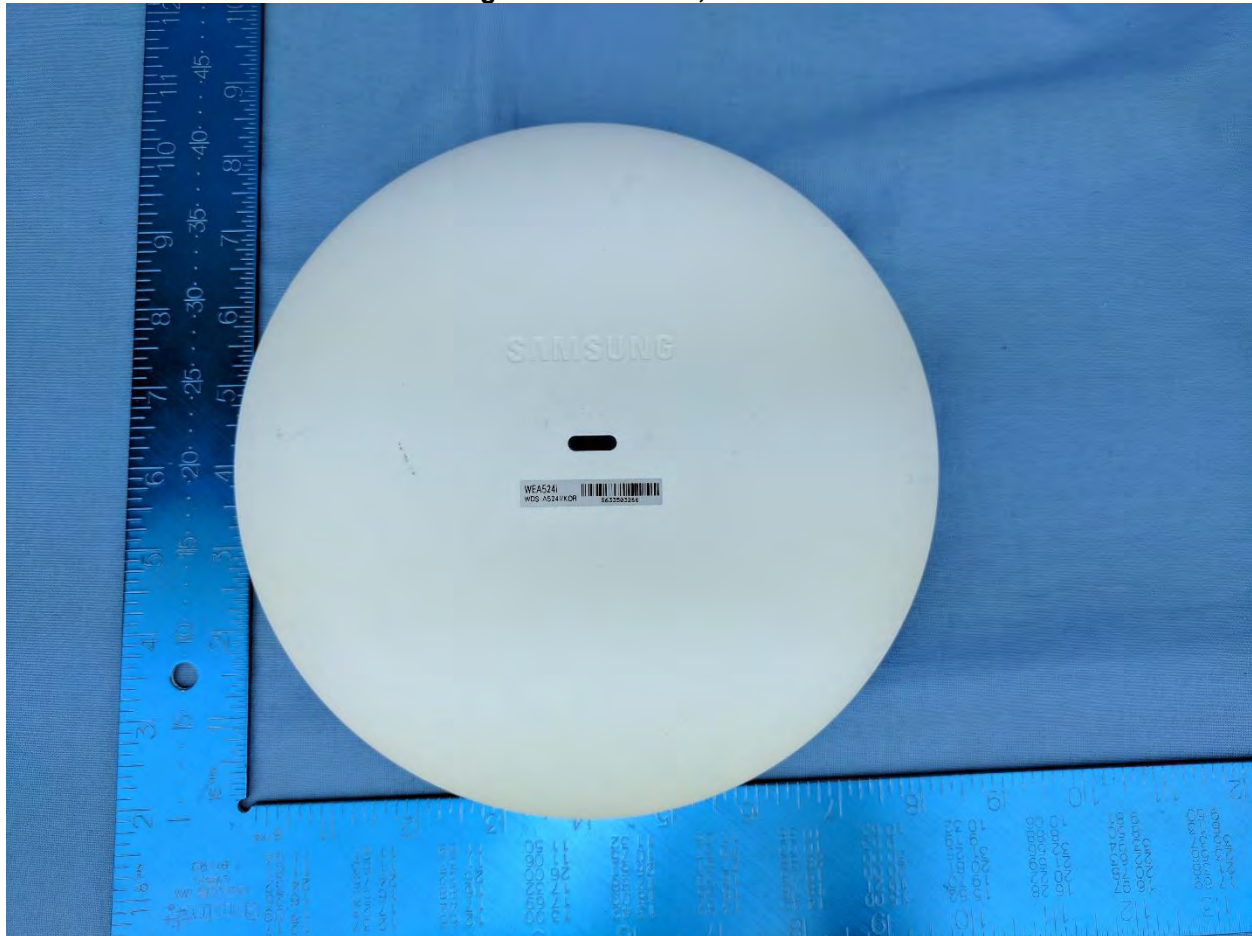
Samsung Electronics Co., Ltd. WEA524i

The scope of the test program was to test the Samsung Electronics Co., Ltd. WEA524i, WEA524i configurations in the frequency ranges 5250 - 5350 MHz; 5470 - 5725 MHz; for DFS compliance against the following specification:

FCC CFR 47 Part 15 Subpart E 15.407

Compliance Measurement Procedures for Unlicensed National Information Infrastructure devices operating in the 5250 to 5350 MHz and 5470 to 5725 MHz bands incorporating Dynamic Frequency Selection.

Samsung Electronics Co., Ltd. WEA524i



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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 13 of 177

5.3. Equipment Model(s) and Serial Number(s)

Type	Description	Manufacturer	Model	Serial no.	Delivery Date
EUT	802.11a/n/ac Hotspot Access Point	Samsung Electronics Co., Ltd	WEA524i	S633503266	19 th July 2017
Support	802.11a/n/ac Hotspot Access Point	Samsung Electronics Co., Ltd	WEA524i	S633503334	19 th July 2017

5.4. Antenna Details

Type	Manufacturer	Model	Family	Gain (dBi)	BF Gain	Dir BW	X-Pol	Frequency Band (MHz)
integral	Samsung Electronics Co., Ltd	a51(CH3)	F Type	4.2	-	360	-	5250 – 5350 5470 – 5725
integral	Samsung Electronics Co., Ltd	a52(CH0), a53(CH1), a54(CH2)	Dipole	6.7	-	360	-	5250 – 5350 5470 – 5725

BF Gain - Beamforming Gain
Dir BW - Directional BeamWidth
X-Pol - Cross Polarization

5.5. Cabling and I/O Ports

Port Type	Max Cable Length	# or Ports	Screened	Conn Type	Data Type	Bit Rate
Ethernet	> 100 m	1	No	RJ-45	Packet Data	10/100/1000
Ethernet	> 100 m	1	No	RJ-45	Packet Data + PoE	10/100/1000
USB	<= 3 m	1	No	USB	Digital	
DC Jack	<= 3 m	1	No	DC Jack	Power	
UART	<= 3 m	1	No	RJ-45	Digital	

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 14 of 177

5.6. Test Configurations

Results for the following configurations are provided in this report:

Operational Mode(s) (802.11a/b/g/n/ac)	Data Rate MBit/s	Channel Frequency (MHz)		
		Low	Mid	High
5470 - 5725 MHz				
a	6	5,500.00	--	--
HT-40	18.5	5,510.00	--	--
ac80	29.5	5,530.00	--	--
ac160	260	5,570.00	--	--

5.7. Equipment Modifications

The following modifications were required to bring the equipment into compliance:

1. NONE

5.8. Deviations from the Test Standard

The following deviations from the test standard were required in order to complete the test program:

1. NONE



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 15 of 177

6. TEST SUMMARY

List of Measurements

Test Header	Result	Data Link
Dynamic Frequency Selection (DFS)	Complies	-
Channel Availability Check	Complies	-
Initial CAC	Complies	View Data
Beginning CAC	Complies	View Data
End CAC	Complies	View Data
Channel Close / Transmission Time	Complies	View Data
Non-Occupancy Period	Complies	View Data
Probability of Detection	Complies	View Data
Detection Bandwidth	Complies	View Data

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 16 of 177

7. TEST EQUIPMENT CONFIGURATION(S)

7.1. DFS - Radiated

EUT Type: Master

Frequency band(s): 5,250 - 5,350 MHz and 5,470 – 5,725 MHz

Uniform Loading: For the above frequency band(s) the manufacturer declared that the device provides an aggregate uniform loading of the spectrum across all devices by selecting an operating channel among the available channels using a random algorithm.

Test Environment: Radiated

Antenna Gain used for Testing: 4.2 dBi

802.11a: Transmit Power: 21 dBm Data Rate: 6 Mbit/s Duty Cycle: 17%

802.11n HT-40: Transmit Power: 21 dBm Data Rate: 18 Mbit/s Duty Cycle: 17%

802.11ac80: Transmit Power: 21 dBm Data Rate: 29 Mbit/s Duty Cycle: 17%

802.11ac160: Transmit Power: 21 dBm Data Rate: 260 Mbit/s Duty Cycle: 17%

Number of Antenna Chains: 4

Test Communication Throughput Methodology

The requisite MPEG video file ("TestFile.mpg" available on the NTIA website at the following link <http://ntiacsd.ntia.doc.gov/dfs/>) is used during this video stream.

EUT Software Version: 0.9.8.T

EUT Software Build: 7-5-17 22:56:18 KST

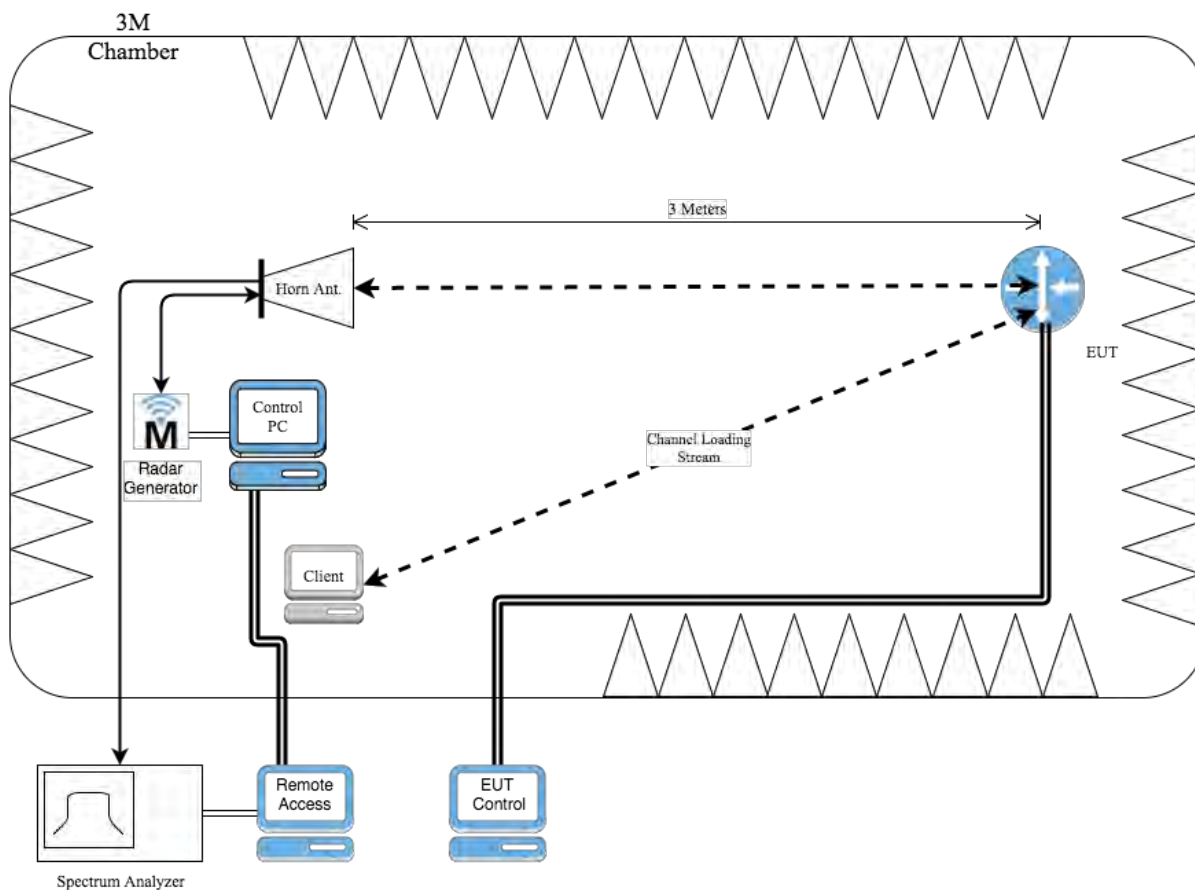
Test Environmental Conditions - Ambient:

Temperature: 17 to 23 °C

Relative humidity: 31 to 57%

Pressure: 999 to 1012 mbar

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A full system calibration was performed on the test station and any resulting system losses (or gains) were taken into account in the production of all final measurement data.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 18 of 177

Asset#	Description	Manufacturer	Model#	Serial#	Calibration Due Date
104	Antenna Horn 1-18GHz	Electro-Mechanics	3115	9205-3882	15 Aug 2017
117	Low Power Sensor - 70dBm to -20dBm 50 MHz - 50GHz	HP	8487D	3318A00371	17 Oct 2017
158	Barometer/Thermometer	Control Company	4196	E2846	30 Nov 2017
207	Semi-Anechoic Chamber, Radiated Immunity & DFS testing.	ETS Lingren	ETS/Lingren 25	SL12462	15 Aug 2017
223	Power Meter	HP	EPM-442A	US37480256	19 Oct 2017
299	Test Software DFS Test System	Aeroflex	DFS test Software	V2.7.0	Not Required
359	DFS System	Aeroflex	PXI-1042	300001/004	10 Jan 2018
417	Laptop for DFS with DFS software	Lenovo	W520	DFS	Not Required
418	PCI-e interface card	National Instruments	Express 8360	174AAC5	Not Required
444	SMA Cable Assembly	ETS-Lindgren	RFC-NMS-100-SMS-256 IN	001	Cal when used
71	Spectrum Analyzer 9KHz-50GHz	HP	8565E	3425A00181	6 Aug 2018
DFS PCIe#1	PCIe cable for Aeroflex	National Instruments	PCIe cable	None	Not Required

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8. MEASUREMENT AND PRESENTATION OF TEST DATA

The measurement and graphical data presented in this test report was generated automatically using state-of-the-art technology creating an easy to read report structure. Numerical measurement data is separated from supporting graphical data (plots) through hyperlinks. Numerical measurement data can be reviewed without scrolling through numerous graphical pages to arrive at the next data matrix.

Plots have been relegated into the Appendix 'Graphical Data'.

Test and report automation was performed by [MiTest](#). [MiTest](#) is an automated test system developed by MiCOM Labs. [MiTest](#) is the first cloud based modular test system enabling end-to-end automation of regulatory compliance testing for conducted RF testing.



The MiCOM Labs "[MiTest](#)" Automated Test System" (Patent Pending)

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9. TEST RESULTS

9.1. Dynamic Frequency Selection (DFS)

A U-NII network will employ a DFS function to detect signals from radar systems and to avoid co-channel operation with these systems. This applies to the 5250-5350 MHz and/or 5470-5725 MHz bands. Within the context of the operation of the DFS function, a U-NII device will operate in either Master Mode or Client Mode. U-NII devices operating in Client Mode can only operate in a network controlled by a U-NII device operating in Master Mode. The following tables summarize the requirements.

Requirement	Master Device or Client with Radar Detection	Client without Radar Detection
	Operational Mode	
DFS Detection Threshold	Yes	Not Required
Channel Closing Transmission Time	Yes	Yes
Channel Move Time	Yes	Yes
U-NII Detection Bandwidth	Yes	Not Required

Additional requirements for devices with multiple bandwidth modes	Master Device or Client with Radar Detection	Client without Radar Detection
U-NII Detection Bandwidth and Statistical Performance Check	All BW modes must be tested	Not required
Channel Move Time and Channel Closing Transmission Time	Test using widest BW mode available	Test using the widest BW mode available for the link
All other tests	Any single BW mode	Not required

NOTE: Frequencies selected for statistical performance check should include several frequencies within the radar detection bandwidth and frequencies near the edge of the radar detection bandwidth. For 802.11 devices it is suggested to select frequencies in each of the bonded 20 MHz channels and the channel center frequency.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 21 of 177

The operational behavior and individual DFS requirements associated with these modes are as follows:

9.1.1. Master Devices

- a) The Master Device will use DFS in order to detect Radar Waveforms with received signal strength above the DFS Detection Threshold in the 5250 – 5350 MHz and 5470 – 5725 MHz bands. DFS is not required in the 5150 – 5250 MHz or 5725 – 5850 MHz bands.
- b) Before initiating a network on a Channel, the Master Device will perform a Channel Availability Check for a specified time duration (Channel Availability Check Time) to ensure that there is no radar system operating on the Channel, using DFS described under subsection a) above.
- c) The Master Device initiates a U-NII network by transmitting control signals that will enable other U-NII devices to Associate with the Master Device.
- d) During normal operation, the Master Device will monitor the Channel (In-Service Monitoring) to ensure that there is no radar system operating on the Channel, using DFS described under a).
- e) If the Master Device has detected a Radar Waveform during In-Service Monitoring as described under d), the Operating Channel of the U-NII network is no longer an Available Channel. The Master Device will instruct all associated Client Device(s) to stop transmitting on this Channel within the Channel Move Time. The transmissions during the Channel Move Time will be limited to the Channel Closing Transmission Time.
- f) Once the Master Device has detected a Radar Waveform it will not utilize the Channel for the duration of the Non-Occupancy Period.
- g) If the Master Device delegates the In-Service Monitoring to a Client Device, then the combination will be tested to the requirements described under d) through f) above.



9.1.2. Client Devices

A Client Device will not transmit before having received appropriate control signals from a Master Device.

b) A Client Device will stop all its transmissions whenever instructed by a Master Device to which it is associated and will meet the Channel Move Time and Channel Closing Transmission Time requirements. The Client Device will not resume any transmissions until it has again received control signals from a Master Device.

c) If a Client Device is performing In-Service Monitoring and detects a Radar Waveform above the DFS Detection Threshold, it will inform the Master Device. This is equivalent to the Master Device detecting the Radar Waveform and d) through f) of section 5.1.1 apply.

d) Irrespective of Client Device or Master Device detection the Channel Move Time and Channel Closing Transmission Time requirements remain the same.

e) The client test frequency must be monitored to ensure no transmission of any type has occurred for 30 minutes. Note: If the client moves with the master, the device is considered compliant if nothing appears in the client non-occupancy period test. For devices that shutdown (rather than moving channels), no beacons should appear.

9.1.3. DFS Detection Thresholds

The table below provides the DFS Detection Thresholds for Master Devices as well as Client Devices incorporating In-Service Monitoring.

DFS Detection Thresholds for Master Devices and Client Devices with Radar Detection

Maximum Transmit Power	Value (see Notes 1, 2 and 3)
EIRP $\geq$ 200 milliwatt	-64 dBm
EIRP 200 milliwatt and power density +10 dBm/MHz	-62 dBm
EIRP 200 milliwatt that do not meet the power spectral density requirement	-64 dBm

NOTE 1: This is the level at the input of the receiver assuming a 0 dBi receive antenna

NOTE 2: Throughout these test procedures an additional 1 dB has been added to the amplitude of the test transmission waveforms to account for variations in measurement equipment. This will ensure that the test signal is at or above the detection threshold level to trigger a DFS response.

NOTE 3: EIRP is based on the highest antenna gain. For MIMO devices refer to KDB Publication 662911 D01.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 23 of 177

9.1.4. Response Requirements

The following table provides the response requirements for Master and Client Devices incorporating DFS.

DFS Response Requirement Values

Parameter	Value
Non-Occupancy Period	Minimum 30 minutes
Channel Availability Check Time	60 seconds
Channel Move Time	10 seconds, see NOTE 1
Channel Closing Transmission Time	200 milliseconds + an aggregate of 60 milliseconds over remaining 10 second period, see NOTES 1 and 2
U-NII Detection Bandwidth	Minimum 100% of the U-NII 99% transmission power bandwidth, see NOTE 3

NOTE 1: Channel Move Time and the Channel Closing Transmission Time should be performed with Radar Type 0. The measurement timing begins at the end of the Radar Type 0 burst.

NOTE 2: The Channel Closing Transmission Time is comprised of 200 milliseconds starting at the beginning of the Channel Move Time plus any additional intermittent control signals required to facilitate a Channel move (an aggregate of 60 milliseconds) during the remainder of the 10 second period. The aggregate duration of control signals will not count quiet periods in between transmissions.

NOTE 3: During the U-NII Detection Bandwidth detection test, radar type 0 should be used. For each frequency step the minimum percentage of detection is 90 percent. Measurements are performed with no data traffic.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 24 of 177

9.1.5. Radar Test Waveforms

This section provides the parameters for required test waveforms, minimum percentage of successful detections, and the minimum number of trials that must be used for determining DFS conformance. Step intervals of 0.1 microsecond for Pulse Width, 1 microsecond for PRI, 1 MHz for chirp width and 1 for the number of pulses will be utilized for the random determination of specific test waveforms.

9.1.5.1. Short Radar Pulses

Short Pulse Radar Test Waveforms

Radar Type	Pulse Width (μS)	PRI (μS)	Number of Pulses	Minimum Percentage of Successful Detection	Minimum Number of Trials
0	1	1428	18	See Note 1	See Note 1
1	1	Test A: 15 unique PRI values randomly selected from the list of 23 PRI values in Table 5a	$\text{Roundup}\left\{\left(\frac{1}{360}\right) \cdot \left(\frac{19 \cdot 10^6}{\text{PRI}_{\mu\text{sec}}}\right)\right\}$	60%	30
		Test B: 15 unique PRI values randomly selected in the range 518-3066 μS, with a minimum increment of 1 μS, excluding PRI values selected in Test A			
2	1-5	150-230	23-29	60%	30
3	6-10	200-500	16-18	60%	30
4	11-20	200-500	12-16	60%	30
Aggregate (Radar Types 1-4)				80%	120

Note 1: Short Radar Pulse Type 0 should be used for the Detection Bandwidth test, Channel Move Time and Channel Closing Time tests

A minimum of 30 unique waveforms are required for each of the Short Pulse Radar Types 2 through 4. If more than 30 waveforms are used for Short Pulse Radar Types 2 through 4, then each additional waveform must also be unique and not repeated from the previous waveforms. If more than 30 waveforms are used for Short Pulse Radar Type 1, then each additional waveform is generated with Test B and must also be unique and not repeated from the previous waveforms in Tests A or B.



9.1.5.2. Long Radar Pulse Test

Long Pulse Radar Test Waveforms

Radar Type	Pulse Width (µsec)	Chirp Width (MHz)	PRI (µsec)	Number of Pulses per Burst	Number of Bursts	Minimum Percentage of Successful Detection	Minimum Trials
5	50-100	5-20	1000-2000	1-3	8-20	80%	30

The parameters for this waveform are randomly chosen. Thirty unique waveforms are required for the Long Pulse radar test signal. If more than 30 waveforms are used for the Long Pulse radar test signal, then each additional waveform must also be unique and not repeated from the previous waveforms.

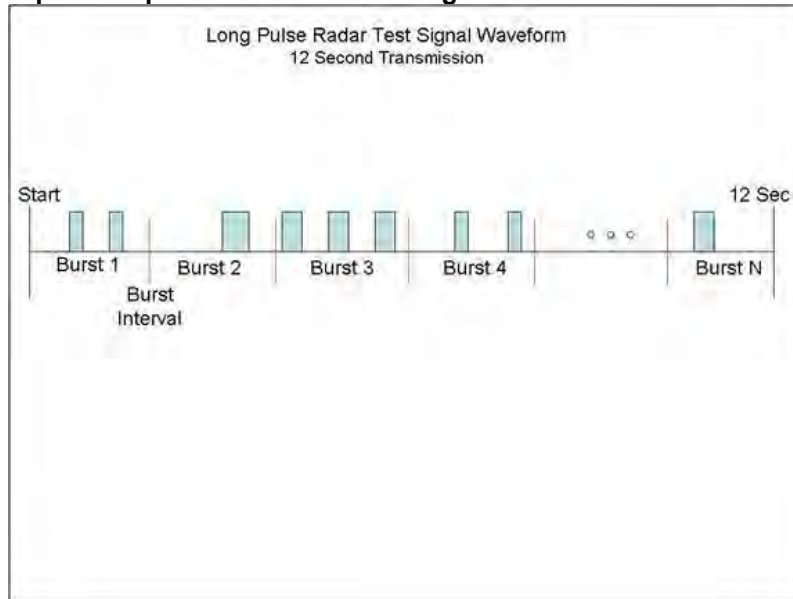
Each waveform is defined as follows:

1. The transmission period for the Long Pulse Radar test signal is 12 seconds.
2. There are a total of 8 to 20 Bursts in the 12 second period, with the number of Bursts being randomly chosen. This number is Burst Count.
3. Each Burst consists of 1 to 3 pulses, with the number of pulses being randomly chosen. Each Burst within the 12 second sequence may have a different number of pulses.
4. The pulse width is between 50 and 100 microseconds, with the pulse width being randomly chosen. Each pulse within a Burst will have the same pulse width. Pulses in different Bursts may have different pulse widths.
5. Each pulse has a linear frequency modulated chirp between 5 and 20 MHz, with the chirp width being randomly chosen. Each pulse within a transmission period will have the same chirp width. The chirp is centered on the pulse. For example, with a radar frequency of 5300 MHz and a 20 MHz chirped signal, the chirp starts at 5290 MHz and ends at 5310 MHz
6. If more than one pulse is present in a Burst, the time between the pulses will be between 1000 and 2000 microseconds, with the time being randomly chosen. If three pulses are present in a Burst, the time between the first and second pulses is chosen independently of the time between the second and third pulses.
7. The 12 second transmission period is divided into even intervals. The number of intervals is equal to Burst_Count. Each interval is of length $(12,000,000 / \text{Burst_Count})$ microseconds. Each interval contains one Burst. The start time for the Burst, relative to the beginning of the interval, is between 1 and $[(12,000,000 / \text{Burst_Count}) - (\text{Total Burst Length}) + (\text{One Random PRI Interval})]$ microseconds, with the start time being randomly chosen. The step interval for the start time is 1 microsecond. The start time for each Burst is chosen independently.

A representative example of a Long Pulse radar test waveform:

1. The total test signal length is 12 seconds.
2. 8 Bursts are randomly generated for the Burst_Count
3. Burst 1 has 2 randomly generated pulses.
4. The pulse width (for both pulses) is randomly selected to be 75 microseconds.
5. The PRI is randomly selected to be at 1213 microseconds.
6. Bursts 2 through 8 are generated using steps 3 – 5.
7. Each Burst is contained in even intervals of 1,500,000 microseconds. The starting location for Pulse 1, Burst 1 is randomly generated (1 to 1,500,000 minus the total Burst 1 length + 1 random PRI interval) at the 325,001 microsecond step. Bursts 2 through 8 randomly fall in successive 1,500,000 microsecond intervals (i.e. Burst 2 falls in the 1,500,001 – 3,000,000 microsecond range).

Graphical representation of the Long Pulse Radar Test Waveform.





9.1.5.3. Frequency Hopping Radar Test Waveform

Radar Type	Pulse Width (μsec)	PRI (μsec)	Pulses per Hop	Hopping Rate (kHz)	Hopping Sequence Length (msec)	Minimum Percentage of Successful Detection	Minimum Trials
6	1	333	9	.333	300	70%	30

For the Frequency Hopping Radar Type, the same Burst parameters are used for each waveform. The hopping sequence is different for each waveform and a 100-length segment is selected from the hopping sequence defined by the following algorithm:

The first frequency in a hopping sequence is selected randomly from the group of 475 integer frequencies from 5250 – 5724 MHz. Next, the frequency that was just chosen is removed from the group and a frequency is randomly selected from the remaining 474 frequencies in the group. This process continues until all 475 frequencies are chosen for the set. For selection of a random frequency, the frequencies remaining within the group are always treated as equally likely.

9.1.6. Radar Waveform Calibration

The following equipment setup was used to calibrate the Radar Waveform. A spectrum analyzer was used to establish the test signal level for each radar type. During this process, there were no transmissions by either the Master or Client Device. The spectrum analyzer was switched to the zero span (Time Domain) mode at the frequency of the Radar Waveform generator. Peak detection was utilized. The spectrum analyzer resolution bandwidth (RBW) and video bandwidth (VBW) were set to 1 MHz.

The signal generator amplitude was set so that the power level measured at the spectrum analyzer was equal to the DFS detection threshold +1dB (Ref Section 9.2).



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 28 of 177

9.1.7. Channel Availability Check

9.1.7.1. Initial CAC

This test verifies that the EUT does not emit pulse, control, or data signals on the test Channel until the power-up sequence has been completed and the U-NII device checks for Radar Waveforms for one minute on the test Channel. This test does not use any Radar Waveforms.

The EUT is instructed to power up at the appropriate center frequency. The spectrum analyzer is set on zero span with a 1 MHz resolution bandwidth and 260 second sweep time to monitor the RF output of the EUT during power up. The analyzer's sweep will be started the same time power is applied to the U-NII device.

The EUT should not transmit any pulse or data transmissions until at least 1 minute after the completion of the power-on cycle.

The first red vertical line shown on the following plot denotes the instant when the EUT starts its power-up sequence i.e. T0 (as defined within the FCC's KDB 905462 D02 Section 4.1). The power-up reference T0 is determined by the time it takes for the EUT to start "beaconing" i.e. initial beacon – 60 secs = end of power-up.

The Channel Availability Check Time commences at instant T0 and will end no sooner than T0 + 60 seconds. T0 + 60 is indicated on the plot by the second vertical line.

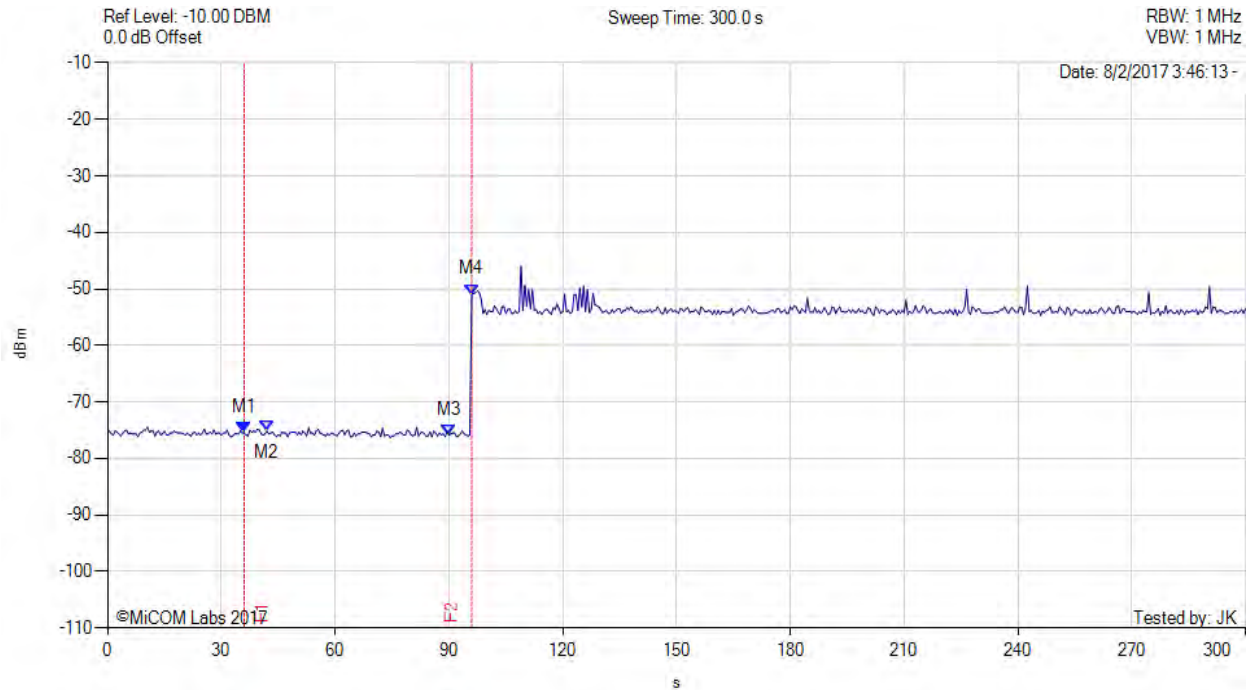


Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 29 of 177



INITIAL CAC

Variant: 802.11ac-80, Channel: 5530.00 MHz, Data Rate: 29 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 4.20 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 36.000 s : -75.500 dBm M2 : 42.000 s : -75.160 dBm M3 : 90.000 s : -75.830 dBm M4 : 96.000 s : -51.000 dBm	Monitored Frequency: 5499.00 MHz

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 30 of 177

9.1.7.2. Beginning CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold +1dB (Ref Section 9.2) occurs at the beginning of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at T0 (first red vertical marker line on the plot).

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

T0 + 60 is indicated on the plot by the second vertical line.

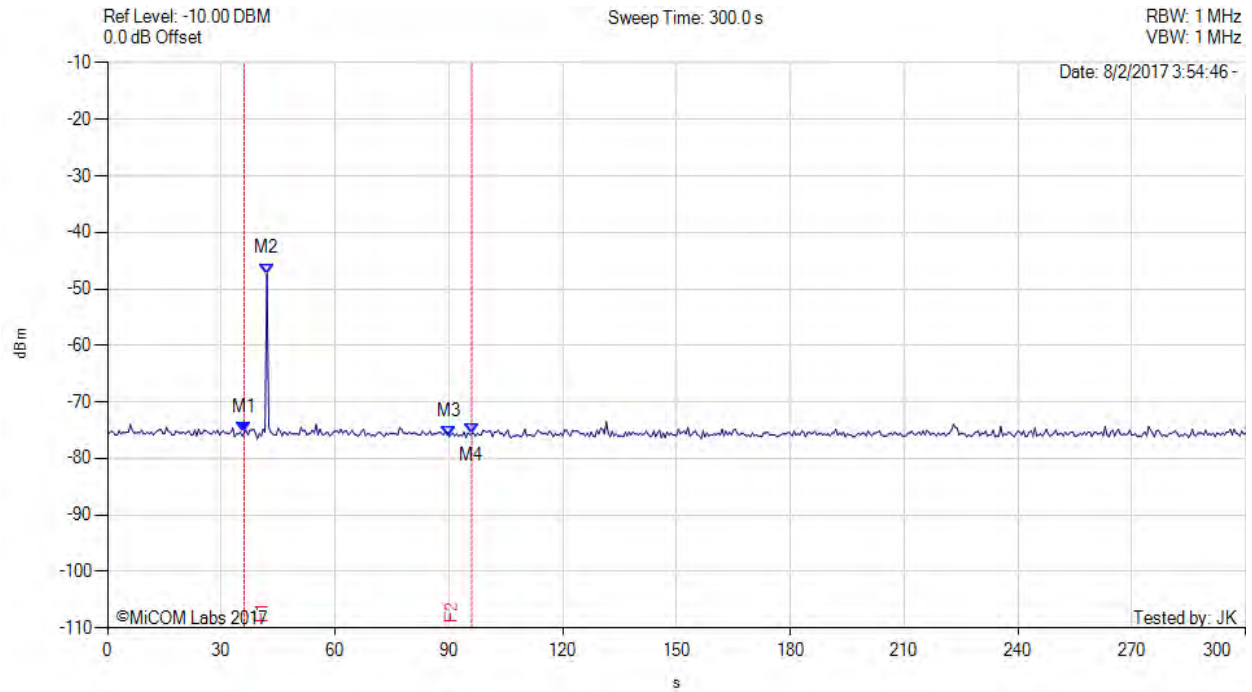


Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 31 of 177



BEGINNING CAC

Variant: 802.11ac-80, Channel: 5530.00 MHz, Data Rate: 29 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 4.20 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 36.000 s : -75.500 dBm M2 : 42.000 s : -47.330 dBm M3 : 90.000 s : -76.160 dBm M4 : 96.000 s : -75.660 dBm	Monitored Frequency: 5499.00 MHz

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 32 of 177

9.1.7.3. End CAC

The steps below define the procedure to verify successful radar detection on the selected Channel during a period equal to the Channel Availability Check Time and avoidance of operation on that Channel when a radar Burst with a level equal to the DFS Detection Threshold occurs at the end of the Channel Availability Check Time.

A single Burst of short pulse of radar Type 1 will commence within a 6 second window starting at $T_0 + 54$ seconds. The window will commence at marker 3 and end at the red time line $T_2 (T_0 + 60 \text{ secs})$

Visual indication on the EUT of successful detection of the radar Burst is recorded and reported. Observation of emissions at the appropriate center frequency will continue for 2.5 minutes after the radar burst has been generated.

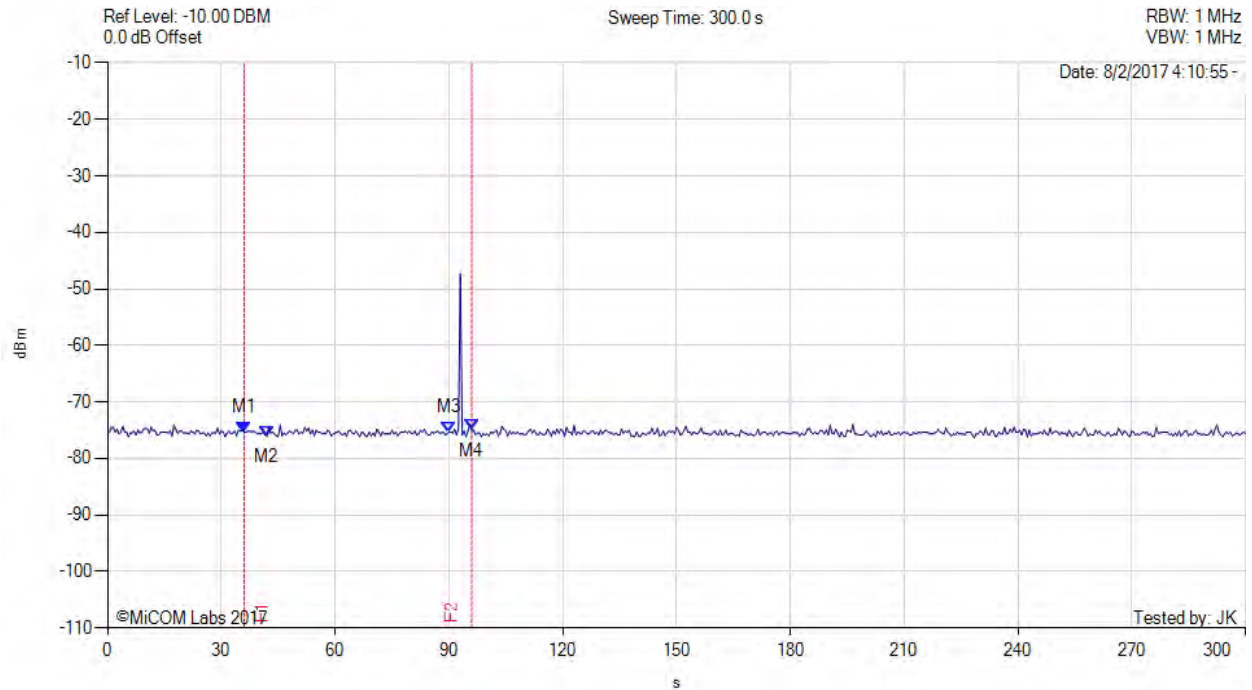


Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 33 of 177

END CAC



Variant: 802.11ac-80, Channel: 5530.00 MHz, Data Rate: 29 Mbit/s, Duty Cycle : 17.00%, Antenna Gain: 4.20 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 36.000 s : -75.330 dBm M2 : 42.000 s : -76.000 dBm M3 : 90.000 s : -75.330 dBm M4 : 96.000 s : -75.000 dBm	Monitored Frequency: 5499.00 MHz

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 34 of 177

9.1.8. Channel Close / Transmission Time

The steps below define the procedure to determine the above-mentioned parameters when a radar Burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The EUT will be associated with a support U-NII device in order to setup an appropriate transmission media in accordance with the FCC requirements.

The EUT was monitored on a frequency that contained control beacons.

Channel Closing Transmission Time and Channel Move Time - Measurement

The test system was set-up to capture all transmission data for access point events above a threshold level of -50 dBm. The test equipment time stamps all captured events.

A Type 0 waveform was introduced to the EUT, from which a 12 second transmission record was digitally captured. The start of the Type 0 radar waveform is indicated in the test result plot as "Start Waveform", the end of the waveform is indicated as "End waveform".

Channel Closing Transmission Time, and the Channel Move Time start immediately after the last radar pulse is transmitted.

The aggregate of all pulses seen after the end of the radar injection are measured as the "Channel Closing Transmission time".

The last EUT activity after the end of the radar pulse is identified and used to determine the "Channel Move Time"



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 35 of 177

Frequency 5570 MHz Channel 116 Monitored 5500 MHz

The PXI system measures and aggregates the pulses occurring after the end of the radar pulse to determine; -

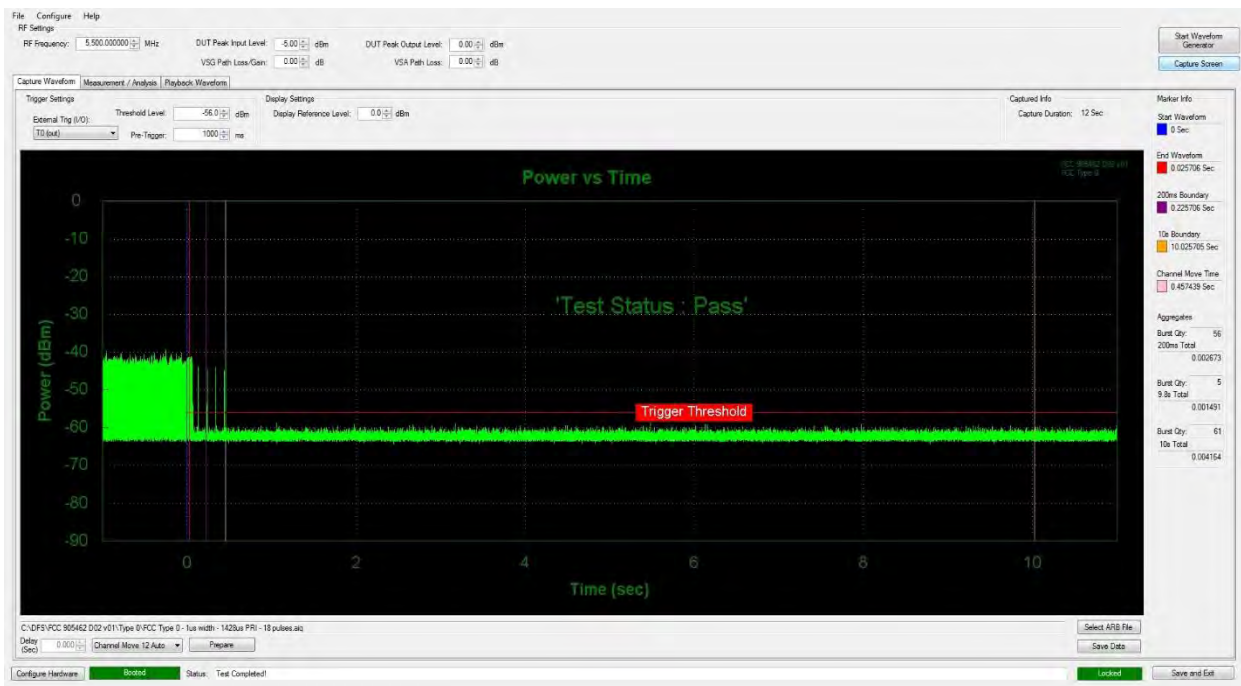
1) Channel Closing Transmission Time (limit is 260 millisecond)

2) Channel Move Time (limit is 10 seconds)

1) Channel Closing Transmission Time = **4.164 mSecs**

2) Channel Move Time = **0.457439 Secs**

**Channel Move Time, Channel Closing Transmission Time for Type Radar
Captured by the Test System - 0-12 Seconds**



This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 36 of 177

9.1.9. Non-Occupancy Period

The EUT is monitored for more than 30 minutes following the channel close/move time to verify no transmissions resume on this Channel. There should be no transmissions on the frequency of interest during the non-occupancy period.

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.

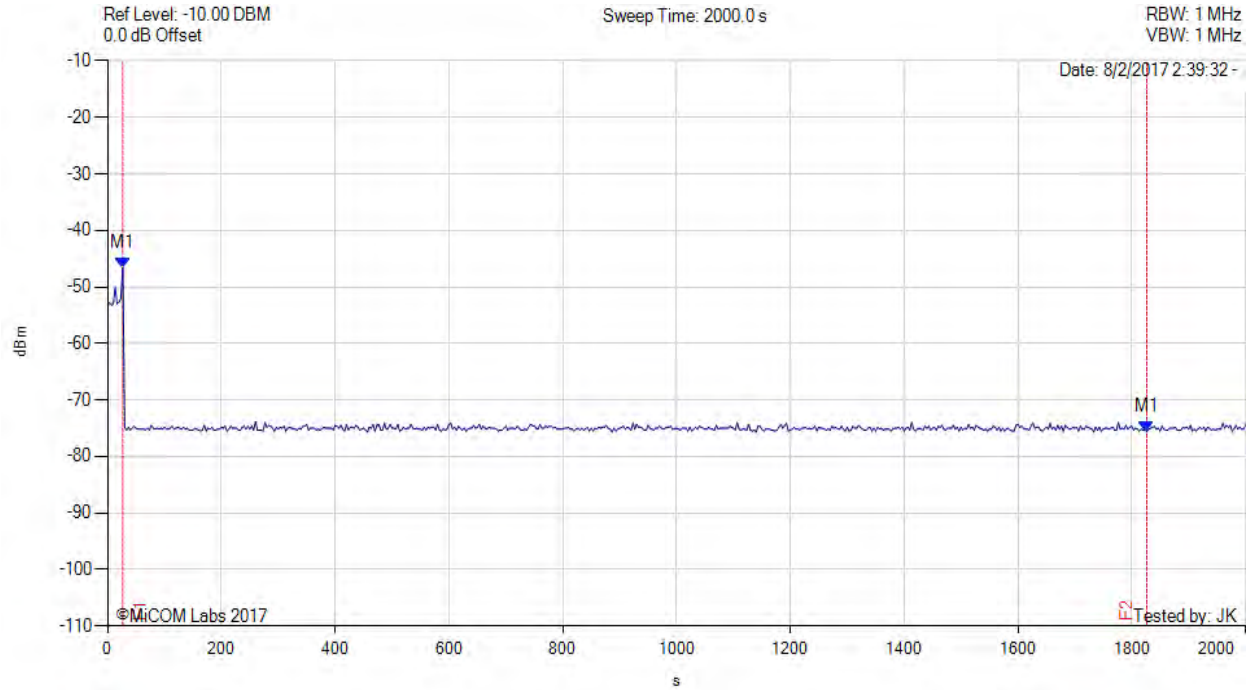


Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 37 of 177



NON-OCCUPANCY PERIOD

Variant: 802.11ac-80, Channel: 5530.00 MHz, Data Rate: 29, Duty Cycle : 17.00%, Antenna Gain: 4.20 dBi



Analyzer Setup	Marker:Time:Amplitude	Test Results
Detector = POS Sweep Count = View RF Atten (dB) = 0 Trace Mode = 0	M1 : 26.667 s : -46.660 dBm M1 : 1826.667 s : -75.660 dBm	Channel Frequency: 5499.00 MHz

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9.1.10. Probability of Detection

The steps below define the procedure to determine the minimum percentage of detection when a radar burst with a level equal to the DFS Detection Threshold is generated on the Operating Channel of the U-NII device.

The Radar Waveform generator sends the individual waveform for each of the radar Types 1-6. Statistical data will be gathered to determine the ability of the device to detect the radar test waveforms. The device can utilize a test mode to demonstrate when detection occurs to prevent the need to reset the device between trial runs. The percentage of successful detection is calculated by:

$$\text{Total \# of detections} \div \text{Total \# of Trials} \times 100 = \text{Probability of Detection}$$

The Minimum number of trails, minimum percentage of successful detection and the average minimum percentage of successful detection are found in the Radar Test Waveforms section.

The aggregate is the average of the percentage of successful detections of Short Pulse Radar Types 1-4. For example, the following table indicates how to compute the aggregate of percentage of successful detections;

Example - Calculation of Aggregate Percentage

Radar Type	Number of Trials	Number of Successful Detections	Minimum Percentage of Successful Detections
1	35	29	82.9%
2	30	18	60.0%
3	30	27	90.0%
4	30	44	88.0%
Aggregate (82.9% + 60.0% + 90.0% + 88.0%) / 4 = 80.2%			



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 39 of 177

802.11a - 5500 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	30	100.00%	Complies	View Data
Radar Type 3	30	30	100.00%	Complies	View Data
Radar Type 4	30	27	90.00%	Complies	View Data
Aggregate (100.00% + 100.00% + 100.00% + 90.00%) / 4 = 97.50%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

802.11ac-160 - 5570 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	29	96.67%	Complies	View Data
Radar Type 3	30	30	100.00%	Complies	View Data
Radar Type 4	30	27	90.00%	Complies	View Data
Aggregate (100.00% + 96.67% + 100.00% + 90.00%) / 4 = 96.67%				Complies	--
Radar Type 5	30	28	93.33%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 40 of 177

802.11ac-80 - 5530 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	29	96.67%	Complies	View Data
Radar Type 2	30	28	93.33%	Complies	View Data
Radar Type 3	30	27	90.00%	Complies	View Data
Radar Type 4	30	26	86.67%	Complies	View Data
Aggregate (96.67% + 93.33% + 90.00% + 86.67%) / 4 = 91.67%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

802.11n HT-40 - 5510 MHz

Statistical Performance Check					
Radar Type	Number of Trials	Number of Successful Detections	Percentage of Successful Detections	Result	Data Link
Radar Type 1	30	30	100.00%	Complies	View Data
Radar Type 2	30	25	83.33%	Complies	View Data
Radar Type 3	30	25	83.33%	Complies	View Data
Radar Type 4	30	27	90.00%	Complies	View Data
Aggregate (100.00% + 83.33% + 83.33% + 90.00%) / 4 = 89.17%				Complies	--
Radar Type 5	30	30	100.00%	Complies	View Data
Radar Type 6	30	30	100.00%	Complies	View Data

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 41 of 177

Equipment Configuration for Radar Type 1

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5506	1	1184	45	1	1	100.00	Detecting
5494	1	1734	31	1	1	100.00	Detecting
5493	1	2147	25	1	1	100.00	Detecting
5500	1	2261	24	1	1	100.00	Detecting
5502	1	2313	23	1	1	100.00	Detecting
5498	1	2411	22	1	1	100.00	Detecting
5492	1	2428	22	1	1	100.00	Detecting
5500	1	2588	21	1	1	100.00	Detecting
5497	1	2841	19	1	1	100.00	Detecting
5493	1	2922	19	1	1	100.00	Detecting
5504	1	3066	18	1	1	100.00	Detecting
5508	1	518	102	1	1	100.00	Detecting
5500	1	598	89	1	1	100.00	Detecting
5496	1	618	86	1	1	100.00	Detecting
5496	1	638	83	1	1	100.00	Detecting
5498	1	651	82	1	1	100.00	Detecting
5505	1	658	81	1	1	100.00	Detecting
5506	1	678	78	1	1	100.00	Detecting
5504	1	698	76	1	1	100.00	Detecting
5496	1	735	72	1	1	100.00	Detecting
5493	1	738	72	1	1	100.00	Detecting
5496	1	767	69	1	1	100.00	Detecting
5500	1	778	68	1	1	100.00	Detecting
5493	1	798	67	1	1	100.00	Detecting
5503	1	838	63	1	1	100.00	Detecting
5496	1	858	62	1	1	100.00	Detecting
5495	1	878	61	1	1	100.00	Detecting
5502	1	938	57	1	1	100.00	Detecting
5495	1	981	54	1	1	100.00	Detecting
5493	1	988	54	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 42 of 177

Equipment Configuration for Radar Type 2

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5498	1.9	177	23	1	1	100.00	Detecting
5496	1.9	211	29	1	1	100.00	Detecting
5494	1.9	222	26	1	1	100.00	Detecting
5501	2	155	24	1	1	100.00	Detecting
5506	2.2	162	26	1	1	100.00	Detecting
5501	2.3	223	27	1	1	100.00	Detecting
5496	2.4	180	28	1	1	100.00	Detecting
5504	2.4	197	29	1	1	100.00	Detecting
5502	2.5	208	25	1	1	100.00	Detecting
5505	2.6	192	27	1	1	100.00	Detecting
5494	2.8	174	28	1	1	100.00	Detecting
5496	2.9	167	27	1	1	100.00	Detecting
5495	2.9	170	23	1	1	100.00	Detecting
5499	3	158	23	1	1	100.00	Detecting
5496	3.4	152	24	1	1	100.00	Detecting
5496	3.5	162	28	1	1	100.00	Detecting
5504	3.5	186	26	1	1	100.00	Detecting
5502	3.6	157	29	1	1	100.00	Detecting
5505	3.8	177	27	1	1	100.00	Detecting
5492	3.9	201	28	1	1	100.00	Detecting
5503	4	189	29	1	1	100.00	Detecting
5508	4.2	162	25	1	1	100.00	Detecting
5495	4.3	194	23	1	1	100.00	Detecting
5500	4.3	197	29	1	1	100.00	Detecting
5495	4.3	201	26	1	1	100.00	Detecting
5502	4.4	168	27	1	1	100.00	Detecting
5502	4.4	207	25	1	1	100.00	Detecting
5492	4.5	225	24	1	1	100.00	Detecting
5506	4.6	186	29	1	1	100.00	Detecting
5497	4.7	220	29	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 43 of 177

Equipment Configuration for Radar Type 3

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5505	10	308	17	1	1	100.00	Detecting
5506	10	440	18	1	1	100.00	Detecting
5508	6	274	18	1	1	100.00	Detecting
5499	6.2	465	16	1	1	100.00	Detecting
5507	6.4	318	16	1	1	100.00	Detecting
5498	6.4	353	16	1	1	100.00	Detecting
5495	6.4	447	16	1	1	100.00	Detecting
5506	7	230	16	1	1	100.00	Detecting
5503	7.4	256	16	1	1	100.00	Detecting
5497	7.4	492	17	1	1	100.00	Detecting
5502	7.5	234	17	1	1	100.00	Detecting
5497	7.6	222	18	1	1	100.00	Detecting
5493	7.9	385	17	1	1	100.00	Detecting
5501	8.1	452	16	1	1	100.00	Detecting
5508	8.2	214	18	1	1	100.00	Detecting
5493	8.4	396	16	1	1	100.00	Detecting
5505	8.4	446	18	1	1	100.00	Detecting
5497	8.6	386	16	1	1	100.00	Detecting
5501	8.7	335	18	1	1	100.00	Detecting
5504	8.7	385	18	1	1	100.00	Detecting
5494	8.7	445	17	1	1	100.00	Detecting
5493	8.8	427	16	1	1	100.00	Detecting
5499	9	381	17	1	1	100.00	Detecting
5505	9.1	275	17	1	1	100.00	Detecting
5505	9.3	384	18	1	1	100.00	Detecting
5492	9.5	240	18	1	1	100.00	Detecting
5499	9.6	224	16	1	1	100.00	Detecting
5507	9.8	238	17	1	1	100.00	Detecting
5497	9.9	305	16	1	1	100.00	Detecting
5506	9.9	453	17	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 44 of 177

Equipment Configuration for Radar Type 4

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5507	11	463	15	1	1	100.00	Detecting
5501	12.3	309	15	1	1	100.00	Detecting
5492	12.4	273	14	1	1	100.00	Detecting
5498	12.5	299	14	1	1	100.00	Detecting
5496	12.6	318	16	1	1	100.00	Detecting
5500	13.1	343	13	1	1	100.00	Detecting
5493	13.3	427	14	1	1	100.00	Detecting
5498	13.5	235	15	1	1	100.00	Detecting
5503	13.5	275	12	1	1	100.00	Detecting
5503	13.7	415	16	1	1	100.00	Detecting
5507	13.8	463	12	1	0	0.00	Not Detecting
5502	14.1	206	16	1	1	100.00	Detecting
5503	14.3	290	13	1	1	100.00	Detecting
5492	14.4	334	16	1	1	100.00	Detecting
5502	14.5	291	12	1	0	0.00	Not Detecting
5495	15.1	307	16	1	1	100.00	Detecting
5500	15.7	314	12	1	1	100.00	Detecting
5506	15.9	304	12	1	1	100.00	Detecting
5503	17.2	222	16	1	1	100.00	Detecting
5493	17.8	427	14	1	1	100.00	Detecting
5500	17.9	428	14	1	1	100.00	Detecting
5507	18.1	388	13	1	1	100.00	Detecting
5493	18.4	323	13	1	0	0.00	Not Detecting
5494	18.5	327	14	1	1	100.00	Detecting
5493	18.5	496	16	1	1	100.00	Detecting
5499	18.7	308	12	1	1	100.00	Detecting
5492	19	266	15	1	1	100.00	Detecting
5497	19.6	470	14	1	1	100.00	Detecting
5497	19.7	294	15	1	1	100.00	Detecting
5504	19.9	228	14	1	1	100.00	Detecting
Aggregate:				30	27	90.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 45 of 177

Equipment Configuration for Radar Type 5

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1 5500	1	1	100	100
Type 5 #2 5504	1	1	100	100
Type 5 #3 5500	1	1	100	100
Type 5 #4 5499	1	1	100	100
Type 5 #5 5506	1	1	100	100
Type 5 #6 5499	1	1	100	100
Type 5 #7 5498	1	1	100	100
Type 5 #8 5500	1	1	100	100
Type 5 #9 5500	1	1	100	100
Type 5 #10 5496	1	1	100	100
Type 5 #11 5498	1	1	100	100
Type 5 #12 5500	1	1	100	100
Type 5 #13 5502	1	1	100	100
Type 5 #14 5500	1	1	100	100
Type 5 #15 5499	1	1	100	100
Type 5 #16 5501	1	1	100	100
Type 5 #17 5501	1	1	100	100
Type 5 #18 5500	1	1	100	100
Type 5 #19 5500	1	1	100	100
Type 5 #20 5500	1	1	100	100
Type 5 #21 5500	1	1	100	100
Type 5 #22 5500	1	1	100	100
Type 5 #23 5499	1	1	100	100
Type 5 #24 5496	1	1	100	100
Type 5 #25 5500	1	1	100	100
Type 5 #26 5504	1	1	100	100
Type 5 #27 5500	1	1	100	100
Type 5 #28 5500	1	1	100	100
Type 5 #29 5498	1	1	100	100
Type 5 #30 5500	1	1	100	100
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 46 of 177

Equipment Configuration for Radar Type 6

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100	Detecting
Type 6 #2	1	1	100	Detecting
Type 6 #3	1	1	100	Detecting
Type 6 #4	1	1	100	Detecting
Type 6 #5	1	1	100	Detecting
Type 6 #6	1	1	100	Detecting
Type 6 #7	1	1	100	Detecting
Type 6 #8	1	1	100	Detecting
Type 6 #9	1	1	100	Detecting
Type 6 #10	1	1	100	Detecting
Type 6 #11	1	1	100	Detecting
Type 6 #12	1	1	100	Detecting
Type 6 #13	1	1	100	Detecting
Type 6 #14	1	1	100	Detecting
Type 6 #15	1	1	100	Detecting
Type 6 #16	1	1	100	Detecting
Type 6 #17	1	1	100	Detecting
Type 6 #18	1	1	100	Detecting
Type 6 #19	1	1	100	Detecting
Type 6 #20	1	1	100	Detecting
Type 6 #21	1	1	100	Detecting
Type 6 #22	1	1	100	Detecting
Type 6 #23	1	1	100	Detecting
Type 6 #24	1	1	100	Detecting
Type 6 #25	1	1	100	Detecting
Type 6 #26	1	1	100	Detecting
Type 6 #27	1	1	100	Detecting
Type 6 #28	1	1	100	Detecting
Type 6 #29	1	1	100	Detecting
Type 6 #30	1	1	100	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 47 of 177

Equipment Configuration for Radar Type 1

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5593	1	678	78	1	1	100.00	Detecting
5500	1	3066	18	1	1	100.00	Detecting
5500	1	918	58	1	1	100.00	Detecting
5500	1	858	62	1	1	100.00	Detecting
5500	1	898	59	1	1	100.00	Detecting
5500	1	878	61	1	1	100.00	Detecting
5566	1	818	65	1	1	100.00	Detecting
5647	1	938	57	1	1	100.00	Detecting
5621	1	658	81	1	1	100.00	Detecting
5547	1	698	76	1	1	100.00	Detecting
5624	1	798	67	1	1	100.00	Detecting
5501	1	838	63	1	1	100.00	Detecting
5554	1	718	74	1	1	100.00	Detecting
5508	1	638	83	1	1	100.00	Detecting
5536	1	738	72	1	1	100.00	Detecting
5614	1	758	70	1	1	100.00	Detecting
5595	1	1071	50	1	1	100.00	Detecting
5600	1	2581	21	1	1	100.00	Detecting
5594	1	2819	19	1	1	100.00	Detecting
5610	1	672	79	1	1	100.00	Detecting
5638	1	1085	49	1	1	100.00	Detecting
5513	1	1942	28	1	1	100.00	Detecting
5496	1	2445	22	1	1	100.00	Detecting
5617	1	2953	18	1	1	100.00	Detecting
5550	1	1779	30	1	1	100.00	Detecting
5591	1	2023	27	1	1	100.00	Detecting
5559	1	1819	30	1	1	100.00	Detecting
5606	1	2084	26	1	1	100.00	Detecting
5528	1	2856	19	1	1	100.00	Detecting
5561	1	2162	25	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 48 of 177

Equipment Configuration for Radar Type 2

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5578	4	165	29	1	1	100.00	Detecting
5540	2	174	25	1	1	100.00	Detecting
5543	2	154	28	1	1	100.00	Detecting
5640	5	184	29	1	1	100.00	Detecting
5646	5	175	29	1	1	100.00	Detecting
5517	4	216	27	1	1	100.00	Detecting
5507	4	172	26	1	1	100.00	Detecting
5507	5	158	24	1	1	100.00	Detecting
5515	3	186	26	1	1	100.00	Detecting
5593	5	194	23	1	1	100.00	Detecting
5612	2	210	28	1	1	100.00	Detecting
5618	2	197	27	1	1	100.00	Detecting
5647	1	156	28	1	1	100.00	Detecting
5601	5	195	27	1	1	100.00	Detecting
5503	5	214	25	1	1	100.00	Detecting
5504	5	172	28	1	1	100.00	Detecting
5621	5	205	28	1	1	100.00	Detecting
5552	4	159	29	1	1	100.00	Detecting
5529	5	222	23	1	1	100.00	Detecting
5637	4	211	28	1	1	100.00	Detecting
5636	5	182	26	1	1	100.00	Detecting
5615	4	202	27	1	1	100.00	Detecting
5633	2	188	28	1	1	100.00	Detecting
5518	2	199	28	1	1	100.00	Detecting
5599	5	208	28	1	1	100.00	Detecting
5513	5	229	25	1	1	100.00	Detecting
5572	5	197	24	1	0	0.00	Not Detecting
5592	4	221	29	1	1	100.00	Detecting
5585	1	189	27	1	1	100.00	Detecting
5515	5	190	27	1	1	100.00	Detecting
Aggregate:				30	29	96.67	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 49 of 177

Equipment Configuration for Radar Type 3

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5577	6	319	18	1	1	100.00	Detecting
5556	6	402	16	1	1	100.00	Detecting
5597	8	489	18	1	1	100.00	Detecting
5509	8	457	18	1	1	100.00	Detecting
5629	6	267	18	1	1	100.00	Detecting
5559	7	433	16	1	1	100.00	Detecting
5516	9	233	18	1	1	100.00	Detecting
5609	7	371	17	1	1	100.00	Detecting
5614	9	429	17	1	1	100.00	Detecting
5598	6	277	18	1	1	100.00	Detecting
5598	9	338	17	1	1	100.00	Detecting
5565	10	378	17	1	1	100.00	Detecting
5499	10	485	16	1	1	100.00	Detecting
5631	9	403	18	1	1	100.00	Detecting
5615	9	405	16	1	1	100.00	Detecting
5575	6	390	18	1	1	100.00	Detecting
5517	7	297	17	1	1	100.00	Detecting
5621	7	454	17	1	1	100.00	Detecting
5499	8	443	18	1	1	100.00	Detecting
5597	8	283	18	1	1	100.00	Detecting
5523	10	273	18	1	1	100.00	Detecting
5639	10	472	17	1	1	100.00	Detecting
5636	7	248	17	1	1	100.00	Detecting
5580	8	361	18	1	1	100.00	Detecting
5614	6	206	17	1	1	100.00	Detecting
5518	10	381	18	1	1	100.00	Detecting
5558	8	414	16	1	1	100.00	Detecting
5613	9	446	18	1	1	100.00	Detecting
5556	8	297	17	1	1	100.00	Detecting
5583	6	354	18	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 50 of 177

Equipment Configuration for Radar Type 4

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5643	18	304	15	1	1	100.00	Detecting
5494	19	475	12	1	1	100.00	Detecting
5638	12	215	12	1	1	100.00	Detecting
5596	11	396	16	1	1	100.00	Detecting
5496	12	445	12	1	1	100.00	Detecting
5543	17	403	16	1	1	100.00	Detecting
5553	12	485	12	1	0	0.00	Not Detecting
5529	18	494	16	1	1	100.00	Detecting
5498	16	381	14	1	1	100.00	Detecting
5610	12	300	15	1	1	100.00	Detecting
5621	11	315	13	1	1	100.00	Detecting
5635	12	468	13	1	1	100.00	Detecting
5520	19	260	16	1	1	100.00	Detecting
5622	17	313	12	1	1	100.00	Detecting
5536	17	212	12	1	0	0.00	Not Detecting
5494	14	449	12	1	1	100.00	Detecting
5575	16	235	14	1	1	100.00	Detecting
5514	15	388	14	1	1	100.00	Detecting
5631	15	500	13	1	0	0.00	Not Detecting
5549	19	279	13	1	1	100.00	Detecting
5631	17	215	15	1	1	100.00	Detecting
5560	15	500	13	1	1	100.00	Detecting
5647	16	474	16	1	1	100.00	Detecting
5496	18	452	14	1	1	100.00	Detecting
5576	20	345	14	1	1	100.00	Detecting
5529	11	232	16	1	1	100.00	Detecting
5566	19	270	15	1	1	100.00	Detecting
5570	14	373	13	1	1	100.00	Detecting
5528	13	354	15	1	1	100.00	Detecting
5568	19	433	16	1	1	100.00	Detecting
Aggregate:				30	27	90.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 51 of 177

Equipment Configuration for Radar Type 5

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1 5570	1	1	100.00	Detecting
Type 5 #2 5498	1	1	100.00	Detecting
Type 5 #3 5500	1	0	0.00	Not Detecting
Type 5 #4 5500	1	1	100.00	Detecting
Type 5 #5 5640	1	1	100.00	Detecting
Type 5 #6 5646	1	1	100.00	Detecting
Type 5 #7 5645	1	1	100.00	Detecting
Type 5 #8 5497	1	1	100.00	Detecting
Type 5 #9 5570	1	1	100.00	Detecting
Type 5 #10 5570	1	0	0.00	Not Detecting
Type 5 #11 5495	1	1	100.00	Detecting
Type 5 #12 5500	1	1	100.00	Detecting
Type 5 #13 5500	1	1	100.00	Detecting
Type 5 #14 5570	1	1	100.00	Detecting
Type 5 #15 5500	1	1	100.00	Detecting
Type 5 #16 5570	1	1	100.00	Detecting
Type 5 #17 5570	1	1	100.00	Detecting
Type 5 #18 5642	1	1	100.00	Detecting
Type 5 #19 5496	1	1	100.00	Detecting
Type 5 #20 5644	1	1	100.00	Detecting
Type 5 #21 5495	1	1	100.00	Detecting
Type 5 #22 5645	1	1	100.00	Detecting
Type 5 #23 5570	1	1	100.00	Detecting
Type 5 #24 5641	1	1	100.00	Detecting
Type 5 #25 5641	1	1	100.00	Detecting
Type 5 #26 5640	1	1	100.00	Detecting
Type 5 #27 5644	1	1	100.00	Detecting
Type 5 #28 5570	1	1	100.00	Detecting
Type 5 #29 5570	1	1	100.00	Detecting
Type 5 #30 5570	1	1	100.00	Detecting
Aggregate:	30	28	93.33	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 52 of 177

Equipment Configuration for Radar Type 6

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100	Detecting
Type 6 #2	1	1	100	Detecting
Type 6 #3	1	1	100	Detecting
Type 6 #4	1	1	100	Detecting
Type 6 #5	1	1	100	Detecting
Type 6 #6	1	1	100	Detecting
Type 6 #7	1	1	100	Detecting
Type 6 #8	1	1	100	Detecting
Type 6 #9	1	1	100	Detecting
Type 6 #10	1	1	100	Detecting
Type 6 #11	1	1	100	Detecting
Type 6 #12	1	1	100	Detecting
Type 6 #13	1	1	100	Detecting
Type 6 #14	1	1	100	Detecting
Type 6 #15	1	1	100	Detecting
Type 6 #16	1	1	100	Detecting
Type 6 #17	1	1	100	Detecting
Type 6 #18	1	1	100	Detecting
Type 6 #19	1	1	100	Detecting
Type 6 #20	1	1	100	Detecting
Type 6 #21	1	1	100	Detecting
Type 6 #22	1	1	100	Detecting
Type 6 #23	1	1	100	Detecting
Type 6 #24	1	1	100	Detecting
Type 6 #25	1	1	100	Detecting
Type 6 #26	1	1	100	Detecting
Type 6 #27	1	1	100	Detecting
Type 6 #28	1	1	100	Detecting
Type 6 #29	1	1	100	Detecting
Type 6 #30	1	1	100	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 53 of 177

Equipment Configuration for Radar Type 1

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5512	1	1184	45	1	1	100.00	Detecting
5522	1	1734	31	1	1	100.00	Detecting
5548	1	2147	25	1	1	100.00	Detecting
5499	1	2261	24	1	0	0.00	Not Detecting
5527	1	2313	23	1	1	100.00	Detecting
5558	1	2411	22	1	1	100.00	Detecting
5502	1	2428	22	1	1	100.00	Detecting
5498	1	2588	21	1	1	100.00	Detecting
5549	1	2841	19	1	1	100.00	Detecting
5555	1	2922	19	1	1	100.00	Detecting
5511	1	3066	18	1	1	100.00	Detecting
5514	1	518	102	1	1	100.00	Detecting
5510	1	598	89	1	1	100.00	Detecting
5504	1	618	86	1	1	100.00	Detecting
5524	1	638	83	1	1	100.00	Detecting
5546	1	651	82	1	1	100.00	Detecting
5556	1	658	81	1	1	100.00	Detecting
5504	1	678	78	1	1	100.00	Detecting
5564	1	698	76	1	1	100.00	Detecting
5525	1	735	72	1	1	100.00	Detecting
5544	1	738	72	1	1	100.00	Detecting
5524	1	767	69	1	1	100.00	Detecting
5497	1	778	68	1	1	100.00	Detecting
5564	1	798	67	1	1	100.00	Detecting
5554	1	838	63	1	1	100.00	Detecting
5538	1	858	62	1	1	100.00	Detecting
5503	1	878	61	1	1	100.00	Detecting
5543	1	938	57	1	1	100.00	Detecting
5530	1	981	54	1	1	100.00	Detecting
5535	1	988	54	1	1	100.00	Detecting
Aggregate:				30	29	96.67	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 54 of 177

Equipment Configuration for Radar Type 2

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5519	1.9	177	23	1	1	100.00	Detecting
5516	1.9	211	29	1	1	100.00	Detecting
5521	1.9	222	26	1	1	100.00	Detecting
5504	2	155	24	1	1	100.00	Detecting
5564	2.2	162	26	1	1	100.00	Detecting
5564	2.3	223	27	1	1	100.00	Detecting
5550	2.4	180	28	1	1	100.00	Detecting
5535	2.4	197	29	1	1	100.00	Detecting
5548	2.5	208	25	1	1	100.00	Detecting
5533	2.6	192	27	1	1	100.00	Detecting
5520	2.8	174	28	1	1	100.00	Detecting
5508	2.9	167	27	1	1	100.00	Detecting
5521	2.9	170	23	1	1	100.00	Detecting
5555	3	158	23	1	1	100.00	Detecting
5526	3.4	152	24	1	1	100.00	Detecting
5562	3.5	162	28	1	1	100.00	Detecting
5550	3.5	186	26	1	1	100.00	Detecting
5527	3.6	157	29	1	1	100.00	Detecting
5534	3.8	177	27	1	1	100.00	Detecting
5541	3.9	201	28	1	1	100.00	Detecting
5532	4	189	29	1	1	100.00	Detecting
5542	4.2	162	25	1	1	100.00	Detecting
5561	4.3	194	23	1	0	0.00	Not Detecting
5533	4.3	197	29	1	1	100.00	Detecting
5560	4.3	201	26	1	0	0.00	Not Detecting
5556	4.4	168	27	1	1	100.00	Detecting
5517	4.4	207	25	1	1	100.00	Detecting
5553	4.5	225	24	1	1	100.00	Detecting
5513	4.6	186	29	1	1	100.00	Detecting
5557	4.7	220	29	1	1	100.00	Detecting
Aggregate:				30	28	93.33	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 55 of 177

Equipment Configuration for Radar Type 3

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5547	10	308	17	1	1	100.00	Detecting
5528	10	440	18	1	1	100.00	Detecting
5536	6	274	18	1	1	100.00	Detecting
5506	6.2	465	16	1	1	100.00	Detecting
5528	6.4	318	16	1	1	100.00	Detecting
5563	6.4	353	16	1	0	0.00	Not Detecting
5562	6.4	447	16	1	0	0.00	Not Detecting
5497	7	230	16	1	1	100.00	Detecting
5509	7.4	256	16	1	1	100.00	Detecting
5528	7.4	492	17	1	1	100.00	Detecting
5565	7.5	234	17	1	1	100.00	Detecting
5513	7.6	222	18	1	1	100.00	Detecting
5525	7.9	385	17	1	1	100.00	Detecting
5522	8.1	452	16	1	1	100.00	Detecting
5496	8.2	214	18	1	1	100.00	Detecting
5528	8.4	396	16	1	1	100.00	Detecting
5494	8.4	446	18	1	1	100.00	Detecting
5510	8.6	386	16	1	1	100.00	Detecting
5529	8.7	335	18	1	1	100.00	Detecting
5560	8.7	385	18	1	0	0.00	Not Detecting
5557	8.7	445	17	1	1	100.00	Detecting
5544	8.8	427	16	1	1	100.00	Detecting
5500	9	381	17	1	1	100.00	Detecting
5558	9.1	275	17	1	1	100.00	Detecting
5494	9.3	384	18	1	1	100.00	Detecting
5545	9.5	240	18	1	1	100.00	Detecting
5523	9.6	224	16	1	1	100.00	Detecting
5557	9.8	238	17	1	1	100.00	Detecting
5513	9.9	305	16	1	1	100.00	Detecting
5499	9.9	453	17	1	1	100.00	Detecting
Aggregate:				30	27	90.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 56 of 177

Equipment Configuration for Radar Type 4

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5495	11	463	15	1	1	100.00	Detecting
5513	12.3	309	15	1	1	100.00	Detecting
5512	12.4	273	14	1	1	100.00	Detecting
5494	12.5	299	14	1	1	100.00	Detecting
5532	12.6	318	16	1	1	100.00	Detecting
5496	13.1	343	13	1	1	100.00	Detecting
5502	13.3	427	14	1	1	100.00	Detecting
5566	13.5	235	15	1	1	100.00	Detecting
5507	13.5	275	12	1	1	100.00	Detecting
5498	13.7	415	16	1	1	100.00	Detecting
5506	13.8	463	12	1	1	100.00	Detecting
5504	14.1	206	16	1	0	0.00	Not Detecting
5492	14.3	290	13	1	1	100.00	Detecting
5551	14.4	334	16	1	1	100.00	Detecting
5519	14.5	291	12	1	0	0.00	Not Detecting
5542	15.1	307	16	1	1	100.00	Detecting
5504	15.7	314	12	1	1	100.00	Detecting
5542	15.9	304	12	1	1	100.00	Detecting
5542	17.2	222	16	1	1	100.00	Detecting
5562	17.8	427	14	1	1	100.00	Detecting
5497	17.9	428	14	1	1	100.00	Detecting
5507	18.1	388	13	1	1	100.00	Detecting
5551	18.4	323	13	1	0	0.00	Not Detecting
5562	18.5	327	14	1	1	100.00	Detecting
5523	18.5	496	16	1	1	100.00	Detecting
5518	18.7	308	12	1	0	0.00	Not Detecting
5564	19	266	15	1	1	100.00	Detecting
5545	19.6	470	14	1	1	100.00	Detecting
5542	19.7	294	15	1	1	100.00	Detecting
5556	19.9	228	14	1	1	100.00	Detecting
Aggregate:				30	26	86.67	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 57 of 177

Equipment Configuration for Radar Type 5

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1 5564	1	1	100.00	Detecting
Type 5 #2 5562	1	1	100.00	Detecting
Type 5 #3 5530	1	1	100.00	Detecting
Type 5 #4 5563	1	1	100.00	Detecting
Type 5 #5 5530	1	1	100.00	Detecting
Type 5 #6 5499	1	1	100.00	Detecting
Type 5 #7 5530	1	1	100.00	Detecting
Type 5 #8 5530	1	1	100.00	Detecting
Type 5 #9 5561	1	1	100.00	Detecting
Type 5 #10 5562	1	1	100.00	Detecting
Type 5 #11 5496	1	1	100.00	Detecting
Type 5 #12 5530	1	1	100.00	Detecting
Type 5 #13 5530	1	1	100.00	Detecting
Type 5 #14 5562	1	1	100.00	Detecting
Type 5 #15 5564	1	1	100.00	Detecting
Type 5 #16 5530	1	1	100.00	Detecting
Type 5 #17 5560	1	1	100.00	Detecting
Type 5 #18 5530	1	1	100.00	Detecting
Type 5 #19 5563	1	1	100.00	Detecting
Type 5 #20 5566	1	1	100.00	Detecting
Type 5 #21 5499	1	1	100.00	Detecting
Type 5 #22 5495	1	1	100.00	Detecting
Type 5 #23 5496	1	1	100.00	Detecting
Type 5 #24 5498	1	1	100.00	Detecting
Type 5 #25 5497	1	1	100.00	Detecting
Type 5 #26 5495	1	1	100.00	Detecting
Type 5 #27 5497	1	1	100.00	Detecting
Type 5 #28 5496	1	1	100.00	Detecting
Type 5 #29 5530	1	1	100.00	Detecting
Type 5 #30 5530	1	1	100.00	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 58 of 177

Equipment Configuration for Radar Type 6

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100	Detecting
Type 6 #2	1	1	100	Detecting
Type 6 #3	1	1	100	Detecting
Type 6 #4	1	1	100	Detecting
Type 6 #5	1	1	100	Detecting
Type 6 #6	1	1	100	Detecting
Type 6 #7	1	1	100	Detecting
Type 6 #8	1	1	100	Detecting
Type 6 #9	1	1	100	Detecting
Type 6 #10	1	1	100	Detecting
Type 6 #11	1	1	100	Detecting
Type 6 #12	1	1	100	Detecting
Type 6 #13	1	1	100	Detecting
Type 6 #14	1	1	100	Detecting
Type 6 #15	1	1	100	Detecting
Type 6 #16	1	1	100	Detecting
Type 6 #17	1	1	100	Detecting
Type 6 #18	1	1	100	Detecting
Type 6 #19	1	1	100	Detecting
Type 6 #20	1	1	100	Detecting
Type 6 #21	1	1	100	Detecting
Type 6 #22	1	1	100	Detecting
Type 6 #23	1	1	100	Detecting
Type 6 #24	1	1	100	Detecting
Type 6 #25	1	1	100	Detecting
Type 6 #26	1	1	100	Detecting
Type 6 #27	1	1	100	Detecting
Type 6 #28	1	1	100	Detecting
Type 6 #29	1	1	100	Detecting
Type 6 #30	1	1	100	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 59 of 177

Equipment Configuration for Radar Type 1

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5509	1	1184	45	1	1	100.00	Detecting
5493	1	1734	31	1	1	100.00	Detecting
5500	1	2147	25	1	1	100.00	Detecting
5523	1	2261	24	1	1	100.00	Detecting
5519	1	2313	23	1	1	100.00	Detecting
5526	1	2411	22	1	1	100.00	Detecting
5509	1	2428	22	1	1	100.00	Detecting
5492	1	2588	21	1	1	100.00	Detecting
5503	1	2841	19	1	1	100.00	Detecting
5500	1	2922	19	1	1	100.00	Detecting
5514	1	3066	18	1	1	100.00	Detecting
5518	1	518	102	1	1	100.00	Detecting
5512	1	598	89	1	1	100.00	Detecting
5501	1	618	86	1	1	100.00	Detecting
5520	1	638	83	1	1	100.00	Detecting
5492	1	651	82	1	1	100.00	Detecting
5524	1	658	81	1	1	100.00	Detecting
5494	1	678	78	1	1	100.00	Detecting
5523	1	698	76	1	1	100.00	Detecting
5500	1	735	72	1	1	100.00	Detecting
5528	1	738	72	1	1	100.00	Detecting
5526	1	767	69	1	1	100.00	Detecting
5513	1	778	68	1	1	100.00	Detecting
5501	1	798	67	1	1	100.00	Detecting
5503	1	838	63	1	1	100.00	Detecting
5498	1	858	62	1	1	100.00	Detecting
5512	1	878	61	1	1	100.00	Detecting
5507	1	938	57	1	1	100.00	Detecting
5495	1	981	54	1	1	100.00	Detecting
5522	1	988	54	1	1	100.00	Detecting
Aggregate:				30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 60 of 177

Equipment Configuration for Radar Type 2

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5513	1.9	177	23	1	1	100.00	Detecting
5516	1.9	211	29	1	1	100.00	Detecting
5514	1.9	222	26	1	1	100.00	Detecting
5498	2	155	24	1	1	100.00	Detecting
5525	2.2	162	26	1	1	100.00	Detecting
5503	2.3	223	27	1	1	100.00	Detecting
5501	2.4	180	28	1	1	100.00	Detecting
5526	2.4	197	29	1	1	100.00	Detecting
5522	2.5	208	25	1	0	0.00	Not Detecting
5503	2.6	192	27	1	1	100.00	Detecting
5525	2.8	174	28	1	1	100.00	Detecting
5521	2.9	167	27	1	0	0.00	Not Detecting
5513	2.9	170	23	1	1	100.00	Detecting
5494	3	158	23	1	1	100.00	Detecting
5499	3.4	152	24	1	1	100.00	Detecting
5494	3.5	162	28	1	1	100.00	Detecting
5495	3.5	186	26	1	1	100.00	Detecting
5498	3.6	157	29	1	1	100.00	Detecting
5492	3.8	177	27	1	1	100.00	Detecting
5495	3.9	201	28	1	1	100.00	Detecting
5520	4	189	29	1	0	0.00	Not Detecting
5494	4.2	162	25	1	1	100.00	Detecting
5493	4.3	194	23	1	1	100.00	Detecting
5528	4.3	197	29	1	0	0.00	Not Detecting
5503	4.3	201	26	1	1	100.00	Detecting
5511	4.4	168	27	1	1	100.00	Detecting
5508	4.4	207	25	1	1	100.00	Detecting
5527	4.5	225	24	1	0	0.00	Not Detecting
5512	4.6	186	29	1	1	100.00	Detecting
5512	4.7	220	29	1	1	100.00	Detecting
Aggregate:				30	25	83.33	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 61 of 177

Equipment Configuration for Radar Type 3

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5506	10	308	17	1	1	100.00	Detecting
5493	10	440	18	1	1	100.00	Detecting
5526	6	274	18	1	1	100.00	Detecting
5510	6.2	465	16	1	0	0.00	Not Detecting
5516	6.4	318	16	1	1	100.00	Detecting
5526	6.4	353	16	1	1	100.00	Detecting
5495	6.4	447	16	1	1	100.00	Detecting
5505	7	230	16	1	1	100.00	Detecting
5504	7.4	256	16	1	1	100.00	Detecting
5508	7.4	492	17	1	1	100.00	Detecting
5520	7.5	234	17	1	0	0.00	Not Detecting
5527	7.6	222	18	1	1	100.00	Detecting
5500	7.9	385	17	1	1	100.00	Detecting
5511	8.1	452	16	1	1	100.00	Detecting
5504	8.2	214	18	1	1	100.00	Detecting
5498	8.4	396	16	1	1	100.00	Detecting
5505	8.4	446	18	1	1	100.00	Detecting
5511	8.6	386	16	1	1	100.00	Detecting
5494	8.7	335	18	1	1	100.00	Detecting
5501	8.7	385	18	1	1	100.00	Detecting
5495	8.7	445	17	1	1	100.00	Detecting
5505	8.8	427	16	1	1	100.00	Detecting
5506	9	381	17	1	1	100.00	Detecting
5528	9.1	275	17	1	0	0.00	Not Detecting
5493	9.3	384	18	1	1	100.00	Detecting
5510	9.5	240	18	1	0	0.00	Not Detecting
5515	9.6	224	16	1	1	100.00	Detecting
5515	9.8	238	17	1	1	100.00	Detecting
5524	9.9	305	16	1	0	0.00	Not Detecting
5505	9.9	453	17	1	1	100.00	Detecting
Aggregate:				30	25	83.33	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 62 of 177

Equipment Configuration for Radar Type 4

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency (MHz)	Pulse Width (us)	PRI (us)	# Pulses	Injections	Detections	Detection Rate	Result
5522	11	463	15	1	0	0.00	Not Detecting
5515	12.3	309	15	1	1	100.00	Detecting
5500	12.4	273	14	1	1	100.00	Detecting
5515	12.5	299	14	1	1	100.00	Detecting
5496	12.6	318	16	1	1	100.00	Detecting
5528	13.1	343	13	1	1	100.00	Detecting
5519	13.3	427	14	1	1	100.00	Detecting
5499	13.5	235	15	1	1	100.00	Detecting
5526	13.5	275	12	1	1	100.00	Detecting
5507	13.7	415	16	1	1	100.00	Detecting
5494	13.8	463	12	1	1	100.00	Detecting
5521	14.1	206	16	1	0	0.00	Not Detecting
5526	14.3	290	13	1	1	100.00	Detecting
5499	14.4	334	16	1	1	100.00	Detecting
5526	14.5	291	12	1	1	100.00	Detecting
5515	15.1	307	16	1	1	100.00	Detecting
5500	15.7	314	12	1	1	100.00	Detecting
5528	15.9	304	12	1	1	100.00	Detecting
5511	17.2	222	16	1	1	100.00	Detecting
5500	17.8	427	14	1	1	100.00	Detecting
5523	17.9	428	14	1	1	100.00	Detecting
5528	18.1	388	13	1	1	100.00	Detecting
5524	18.4	323	13	1	1	100.00	Detecting
5500	18.5	327	14	1	1	100.00	Detecting
5525	18.5	496	16	1	1	100.00	Detecting
5497	18.7	308	12	1	0	0.00	Not Detecting
5523	19	266	15	1	1	100.00	Detecting
5524	19.6	470	14	1	1	100.00	Detecting
5521	19.7	294	15	1	1	100.00	Detecting
5494	19.9	228	14	1	1	100.00	Detecting
Aggregate:				30	27	90.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 63 of 177

Equipment Configuration for Radar Type 5

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Injections	Detections	Detection Rate	Result
Type 5 #1 5521	1	1	100.00	Detecting
Type 5 #2 5524	1	1	100.00	Detecting
Type 5 #3 5510	1	1	100.00	Detecting
Type 5 #4 5499	1	1	100.00	Detecting
Type 5 #5 5524	1	1	100.00	Detecting
Type 5 #6 5510	1	1	100.00	Detecting
Type 5 #7 5524	1	1	100.00	Detecting
Type 5 #8 5496	1	1	100.00	Detecting
Type 5 #9 5510	1	1	100.00	Detecting
Type 5 #10 5525	1	1	100.00	Detecting
Type 5 #11 5525	1	1	100.00	Detecting
Type 5 #12 5510	1	1	100.00	Detecting
Type 5 #13 5510	1	1	100.00	Detecting
Type 5 #14 5510	1	1	100.00	Detecting
Type 5 #15 5510	1	1	100.00	Detecting
Type 5 #16 5495	1	1	100.00	Detecting
Type 5 #17 5499	1	1	100.00	Detecting
Type 5 #18 5510	1	1	100.00	Detecting
Type 5 #19 5524	1	1	100.00	Detecting
Type 5 #20 5525	1	1	100.00	Detecting
Type 5 #21 5526	1	1	100.00	Detecting
Type 5 #22 5498	1	1	100.00	Detecting
Type 5 #23 5499	1	1	100.00	Detecting
Type 5 #24 5495	1	1	100.00	Detecting
Type 5 #25 5520	1	1	100.00	Detecting
Type 5 #26 5498	1	1	100.00	Detecting
Type 5 #27 5496	1	1	100.00	Detecting
Type 5 #28 5524	1	1	100.00	Detecting
Type 5 #29 5510	1	1	100.00	Detecting
Type 5 #30 5521	1	1	100.00	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 64 of 177

Equipment Configuration for Radar Type 6

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Burst Segment	Detections	Injection #	Detection Rate	Pass/Fail
Type 6 #1	1	1	100	Detecting
Type 6 #2	1	1	100	Detecting
Type 6 #3	1	1	100	Detecting
Type 6 #4	1	1	100	Detecting
Type 6 #5	1	1	100	Detecting
Type 6 #6	1	1	100	Detecting
Type 6 #7	1	1	100	Detecting
Type 6 #8	1	1	100	Detecting
Type 6 #9	1	1	100	Detecting
Type 6 #10	1	1	100	Detecting
Type 6 #11	1	1	100	Detecting
Type 6 #12	1	1	100	Detecting
Type 6 #13	1	1	100	Detecting
Type 6 #14	1	1	100	Detecting
Type 6 #15	1	1	100	Detecting
Type 6 #16	1	1	100	Detecting
Type 6 #17	1	1	100	Detecting
Type 6 #18	1	1	100	Detecting
Type 6 #19	1	1	100	Detecting
Type 6 #20	1	1	100	Detecting
Type 6 #21	1	1	100	Detecting
Type 6 #22	1	1	100	Detecting
Type 6 #23	1	1	100	Detecting
Type 6 #24	1	1	100	Detecting
Type 6 #25	1	1	100	Detecting
Type 6 #26	1	1	100	Detecting
Type 6 #27	1	1	100	Detecting
Type 6 #28	1	1	100	Detecting
Type 6 #29	1	1	100	Detecting
Type 6 #30	1	1	100	Detecting
Aggregate:	30	30	100.00	Pass

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 65 of 177

9.1.11. Detection Bandwidth

To determine the equipment Detection Bandwidth for each applicable operational mode a single burst of the short pulse radar Type 0 was produced at the appropriate power level. The EUT was set up as a standalone device (no associated Client or Master, as appropriate) and no traffic. Frame based systems will be set to a talk/listen ratio reflecting the worst case (maximum) that is user configurable during this test.

To determine the actual receiver bandwidth a single radar burst is generated for a minimum of 10 trials and the response of the EUT noted. The EUT must detect at least 9 trials in order to meet the criteria.

Starting from the actual channel center frequency the radar frequency is increased in 5 MHz steps, injecting a Type 0 ten times, until the detection rate falls below 90%. At this time the span between this decrease in detection rate and the last 5 MHz step is checked with a 1 MHz step size. The highest frequency at which detection is greater than or equal to 90% is denoted as FH.

The radar frequency is decreased in 5 MHz steps, repeating the above test sequence, until the detection rate falls below 90%. The lowest frequency at which detection is greater than or equal to 90% is denoted as FL.

The U-NII Detection Bandwidth is calculated as follows:

U-NII Detection Bandwidth = FH – FL

The U-NII Detection Bandwidth must meet the U-NII Detection Bandwidth criterion specified. Otherwise, the UUT does not comply with DFS requirements. This is essential to ensure that the UUT is capable of detecting Radar Waveforms across the same frequency spectrum that contains the significant energy from the system. In the case that the U-NII Detection Bandwidth is greater than or equal to the 99% power bandwidth for the measured FH and FL, the test can be truncated and the U-NII Detection Bandwidth can be reported as the measured FH and FL.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 66 of 177

Equipment Configuration for Detection Bandwidth

Variant:	802.11a	Duty Cycle (%):	17.00
Data Rate:	6 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5500.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Result
5515 MHz	2	0	Not Detected
5511 MHz	2	0	Not Detected
5510 MHz	10	10	Detected
5505 MHz	10	10	Detected
5500 MHz	10	10	Detected
5495 MHz	10	10	Detected
5490 MHz	10	10	Detected
5489 MHz	2	0	Not Detected
5485 MHz	2	0	Not Detected
	FL: 5490 MHz	FH: 5510 MHz	FH – FL = 20 MHz

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 67 of 177

Equipment Configuration for Detection Bandwidth

Variant:	802.11ac-160	Duty Cycle (%):	17.00
Data Rate:	260 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5570.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Result
5655 MHz	2	0	Not Detected
5651 MHz	4	2	Not Detected
5650 MHz	10	10	Detected
5645 MHz	10	10	Detected
5640 MHz	10	10	Detected
5635 MHz	10	10	Detected
5630 MHz	10	10	Detected
5625 MHz	10	10	Detected
5620 MHz	10	10	Detected
5615 MHz	10	10	Detected
5610 MHz	10	10	Detected
5605 MHz	10	10	Detected
5600 MHz	10	10	Detected
5595 MHz	10	10	Detected
5590 MHz	10	10	Detected
5585 MHz	10	10	Detected
5580 MHz	10	10	Detected
5575 MHz	10	10	Detected
5570 MHz	10	10	Detected
5565 MHz	10	10	Detected
5560 MHz	10	10	Detected
5555 MHz	10	10	Detected
5550 MHz	10	10	Detected
5545 MHz	10	10	Detected
5540 MHz	10	10	Detected
5535 MHz	10	10	Detected
5530 MHz	10	10	Detected
5525 MHz	10	10	Detected
5520 MHz	10	10	Detected
5515 MHz	10	10	Detected
5510 MHz	10	10	Detected
5505 MHz	10	10	Detected
5500 MHz	10	10	Detected

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 68 of 177

5495 MHz	10	10	Detected
5490 MHz	10	10	Detected
5489 MHz	2	0	Not Detected
5485 MHz	2	0	Not Detected
	FL: 5490 MHz	FH: 5650 MHz	FH – FL = 160 MHz

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 69 of 177

Equipment Configuration for Detection Bandwidth

Variant:	802.11ac-80	Duty Cycle (%):	17.00
Data Rate:	29 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5530.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Result
5575 MHz	2	0	Not Detected
5571 MHz	2	0	Not Detected
5570 MHz	10	10	Detected
5565 MHz	10	10	Detected
5560 MHz	10	10	Detected
5555 MHz	10	10	Detected
5550 MHz	10	10	Detected
5545 MHz	10	10	Detected
5540 MHz	10	10	Detected
5535 MHz	10	10	Detected
5530 MHz	10	10	Detected
5525 MHz	10	10	Detected
5520 MHz	10	10	Detected
5515 MHz	10	10	Detected
5510 MHz	10	10	Detected
5505 MHz	10	10	Detected
5500 MHz	10	10	Detected
5495 MHz	10	10	Detected
5490 MHz	10	10	Detected
5489 MHz	2	0	Not Detected
5485 MHz	2	0	Not Detected
	FL: 5490 MHz	FH: 5570 MHz	FH – FL = 80 MHz

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 70 of 177

Equipment Configuration for Detection Bandwidth

Variant:	802.11n HT-40	Duty Cycle (%):	17.00
Data Rate:	18 Mbit/s	Antenna Gain (dBi):	4.20
Modulation:	OFDM	Beam Forming Gain (Y):	Not Applicable
Channel Frequency:	5510.00 MHz	Tested By:	JK
Engineering Test Notes:			

Test Measurement Results

Frequency	Injections	Detections	Result
5535 MHz	2	0	Not Detected
5531 MHz	2	0	Not Detected
5530 MHz	10	10	Detected
5525 MHz	10	10	Detected
5520 MHz	10	10	Detected
5515 MHz	10	10	Detected
5510 MHz	10	10	Detected
5505 MHz	10	10	Detected
5500 MHz	10	10	Detected
5495 MHz	10	10	Detected
5490 MHz	10	10	Detected
5489 MHz	2	0	Not Detected
5485 MHz	3	1	Not Detected
	FL: 5490 MHz	FH: 5530 MHz	FH – FL = 40 MHz

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 71 of 177

A. APPENDIX – RADAR SIGNATURES

This test report may be reproduced in full only. The document may only be updated by MiCOM Labs personnel. All changes will be noted in the Document History section of the report.



Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 72 of 177

Type 5 #1 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	378909	100	1265	1353	475315	857142
2	3	20	190803	83	1256	1319	663515	857142
3	3	20	439393	50	951	1818	414830	857142
4	1	20	811770	71	0	0	45301	857142
5	1	20	778804	93	0	0	78245	857142
6	1	20	328836	84	0	0	528222	857142
7	1	20	806042	66	0	0	51034	857142
8	2	20	569818	97	1787	0	285343	857142
9	3	20	221105	62	1839	1819	632193	857142
10	3	20	221451	85	1429	1791	632216	857142
11	1	20	454527	98	0	0	402517	857142
12	1	20	131354	89	0	0	725699	857142
13	2	20	510933	71	1374	0	344693	857142
14	1	20	650557	53	0	0	206532	857142

Type 5 #2 5504 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	135731	74	1774	1068	611205	750000
2	3	10	159887	52	1548	1206	587203	750000
3	1	10	93195	58	0	0	656747	750000
4	3	10	113648	69	1341	1264	633540	750000
5	2	10	102398	87	1397	0	646031	750000
6	3	10	699030	65	1122	1586	48067	750000
7	2	10	347075	83	1192	0	401567	750000
8	3	10	229276	62	1931	1394	517213	750000
9	3	10	353183	66	1884	1036	393699	750000
10	2	10	225301	84	1265	0	523266	750000
11	3	10	33519	94	1633	1564	713002	750000
12	1	10	309879	87	0	0	440034	750000
13	2	10	714424	64	1445	0	34003	750000
14	3	10	254275	68	1175	1590	492756	750000
15	3	10	140177	65	1726	1055	606847	750000
16	2	10	627541	92	1409	0	120866	750000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 73 of 177

Type 5 #3 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	18099	97	0	0	781804	800000
2	3	19	643993	57	1675	1193	152968	800000
3	3	19	117482	64	1593	1376	679357	800000
4	2	19	551520	50	1519	0	246861	800000
5	3	19	427937	50	1367	1886	368660	800000
6	3	19	612379	68	1282	1845	184290	800000
7	3	19	496694	83	1363	1743	299951	800000
8	2	19	709480	52	1038	0	89378	800000
9	2	19	597200	77	1387	0	201259	800000
10	2	19	214883	60	1338	0	583659	800000
11	3	19	638577	54	1873	1551	157837	800000
12	2	19	365973	67	1272	0	432621	800000
13	3	19	557955	76	1917	1788	238112	800000
14	3	19	693547	70	1459	1695	103089	800000
15	1	19	157359	58	0	0	642583	800000

Type 5 #4 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	16	105053	93	0	0	1394854	1500000
2	2	16	990341	75	1507	0	508002	1500000
3	2	16	1040271	61	1772	0	457835	1500000
4	2	16	42118	88	1336	0	1456370	1500000
5	2	16	612034	74	1734	0	886084	1500000
6	3	16	1175517	87	1044	1125	322053	1500000
7	3	16	767310	87	1447	1149	729833	1500000
8	2	16	846941	69	950	0	651971	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 74 of 177

Type 5 #5 5506 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	529050	59	0	0	393967	923076
2	3	5	691382	92	1027	1609	228782	923076
3	3	5	272615	91	1134	956	648098	923076
4	1	5	613054	89	0	0	309933	923076
5	2	5	199564	94	1392	0	721932	923076
6	1	5	107620	73	0	0	815383	923076
7	1	5	750334	98	0	0	172644	923076
8	1	5	767158	84	0	0	155834	923076
9	1	5	854203	96	0	0	68777	923076
10	1	5	824657	54	0	0	98365	923076
11	3	5	186889	97	1368	1241	733287	923076
12	3	5	380202	63	978	1263	540444	923076
13	1	5	347905	68	0	0	575103	923076

Type 5 #6 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	1000172	83	0	0	199745	1200000
2	1	17	504982	77	0	0	694941	1200000
3	2	17	885027	94	1761	0	313024	1200000
4	1	17	710515	90	0	0	489395	1200000
5	2	17	932674	68	1513	0	265677	1200000
6	3	17	424877	63	1850	956	772128	1200000
7	1	17	449368	87	0	0	750545	1200000
8	2	17	246570	89	1337	0	951915	1200000
9	1	17	561484	89	0	0	638427	1200000
10	1	17	978104	94	0	0	221802	1200000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 75 of 177

Type 5 #7 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	595032	88	0	0	327956	923076
2	2	13	533342	97	1834	0	387706	923076
3	1	13	78635	91	0	0	844350	923076
4	1	13	191272	76	0	0	731728	923076
5	3	13	173097	96	1231	1878	746582	923076
6	2	13	897892	78	1572	0	23456	923076
7	3	13	316025	77	1432	1377	604011	923076
8	3	13	26415	63	1506	1176	893790	923076
9	1	13	797944	80	0	0	125052	923076
10	2	13	801731	84	1603	0	119574	923076
11	1	13	379749	92	0	0	543235	923076
12	1	13	531388	53	0	0	391635	923076
13	1	13	255517	54	0	0	667505	923076

Type 5 #8 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	888239	52	1259	1019	309327	1200000
2	2	10	582207	63	1575	0	616092	1200000
3	3	10	909235	64	1723	1260	287590	1200000
4	3	10	837594	78	1026	1621	359525	1200000
5	3	10	813580	54	1212	1507	383539	1200000
6	2	10	23306	74	1678	0	1174868	1200000
7	2	10	729362	57	1237	0	469287	1200000
8	1	10	1092795	67	0	0	107138	1200000
9	1	10	33032	83	0	0	1166885	1200000
10	2	10	239518	70	1340	0	959002	1200000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 76 of 177

Type 5 #9 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	9	316323	54	0	0	606699	923076
2	2	9	721140	60	1416	0	200400	923076
3	2	9	126916	86	1127	0	794861	923076
4	1	9	719009	54	0	0	204013	923076
5	2	9	461017	63	1556	0	460377	923076
6	3	9	844893	75	1501	1034	75423	923076
7	1	9	264879	71	0	0	658126	923076
8	3	9	903301	72	1322	1730	16507	923076
9	1	9	517562	84	0	0	405430	923076
10	1	9	413855	59	0	0	509162	923076
11	2	9	435770	88	1672	0	485458	923076
12	3	9	426307	97	1598	1489	493391	923076
13	3	9	573427	73	1752	1485	346193	923076

Type 5 #10 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	402578	94	1606	0	795628	1200000
2	3	10	679029	92	1293	1508	517894	1200000
3	1	10	544417	74	0	0	655509	1200000
4	2	10	478792	59	1595	0	719495	1200000
5	3	10	416289	65	1712	1678	780126	1200000
6	3	10	238735	98	1344	1751	957876	1200000
7	3	10	819433	93	1089	1004	378195	1200000
8	2	10	670784	79	1597	0	527461	1200000
9	1	10	123109	76	0	0	1076815	1200000
10	3	10	1082244	69	1378	1404	114767	1200000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 77 of 177

Type 5 #11 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	688889	59	0	0	511052	1200000
2	3	13	1128703	100	1782	1182	68033	1200000
3	3	13	324178	68	1557	1817	872244	1200000
4	2	13	577206	75	1003	0	621641	1200000
5	1	13	310833	87	0	0	889080	1200000
6	1	13	685863	62	0	0	514075	1200000
7	3	13	782688	100	1195	1613	414204	1200000
8	2	13	520015	84	1643	0	678174	1200000
9	3	13	179779	51	1566	1524	1016978	1200000
10	2	13	325022	74	1043	0	873787	1200000

Type 5 #12 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	20	268743	92	1834	0	329239	600000
2	2	20	415649	66	1677	0	182542	600000
3	1	20	225330	80	0	0	374590	600000
4	1	20	213885	70	0	0	386045	600000
5	2	20	156867	51	1445	0	441586	600000
6	2	20	65126	95	1365	0	533319	600000
7	2	20	252974	89	1365	0	345483	600000
8	1	20	582328	92	0	0	17580	600000
9	3	20	412618	54	1154	1823	184243	600000
10	1	20	400837	87	0	0	199076	600000
11	1	20	304346	53	0	0	295601	600000
12	2	20	28871	76	1084	0	569893	600000
13	2	20	5399	65	1266	0	593205	600000
14	1	20	367861	63	0	0	232076	600000
15	3	20	261120	58	1486	1545	335675	600000
16	1	20	491021	64	0	0	108915	600000
17	3	20	268844	91	1628	988	328267	600000
18	1	20	156039	51	0	0	443910	600000
19	2	20	468518	97	1798	0	129490	600000
20	3	20	1082	84	1664	1117	595885	600000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 78 of 177

Type 5 #13 5502 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	15	489358	75	1564	1700	257153	750000
2	2	15	107735	84	1264	0	640833	750000
3	2	15	433095	63	1360	0	315419	750000
4	3	15	534245	94	1081	1679	212713	750000
5	1	15	749543	97	0	0	360	750000
6	3	15	134430	85	1471	1446	612398	750000
7	3	15	328572	64	1568	1785	417883	750000
8	3	15	80770	80	1737	1916	665337	750000
9	3	15	70696	88	1452	1395	676193	750000
10	3	15	577	94	1733	1753	745655	750000
11	2	15	669629	98	1677	0	78498	750000
12	3	15	454781	96	1722	1868	291341	750000
13	3	15	152895	57	1674	1465	593795	750000
14	1	15	539725	81	0	0	210194	750000
15	1	15	271663	57	0	0	478280	750000
16	1	15	623151	60	0	0	126789	750000

Type 5 #14 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	675779	100	987	1181	71753	750000
2	3	10	214105	95	1682	1817	532111	750000
3	1	10	498255	91	0	0	251654	750000
4	2	10	495615	85	1118	0	253097	750000
5	1	10	210780	60	0	0	539160	750000
6	1	10	309310	90	0	0	440600	750000
7	3	10	176713	78	1800	1075	570178	750000
8	2	10	618481	77	1433	0	129932	750000
9	3	10	323316	65	1778	978	423733	750000
10	3	10	388487	66	1632	1771	357912	750000
11	1	10	313882	81	0	0	436037	750000
12	3	10	278417	77	1902	1024	468426	750000
13	2	10	306238	51	1626	0	442034	750000
14	1	10	97258	79	0	0	652663	750000
15	1	10	352896	59	0	0	397045	750000
16	2	10	634558	94	1753	0	113501	750000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 79 of 177

Type 5 #15 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	36007	66	1771	0	762090	800000
2	3	16	785812	62	1756	1775	10471	800000
3	1	16	288104	77	0	0	511819	800000
4	3	16	494701	70	1297	953	302839	800000
5	3	16	611755	79	1442	1258	185308	800000
6	1	16	334116	82	0	0	465802	800000
7	3	16	617225	98	1520	952	180009	800000
8	1	16	127200	58	0	0	672742	800000
9	3	16	520352	89	1053	964	277364	800000
10	3	16	381946	55	1421	1680	414788	800000
11	3	16	251515	97	1655	1049	545490	800000
12	3	16	334022	58	1450	1216	463138	800000
13	1	16	86129	65	0	0	713806	800000
14	1	16	371295	52	0	0	428653	800000
15	2	16	705640	94	1875	0	92297	800000

Type 5 #16 5501 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	91673	84	962	0	830273	923076
2	1	17	123148	84	0	0	799844	923076
3	2	17	813538	94	1534	0	107816	923076
4	2	17	453991	79	1399	0	467528	923076
5	1	17	513289	93	0	0	409694	923076
6	3	17	791340	90	1186	1180	129100	923076
7	3	17	779688	64	1804	1657	139735	923076
8	1	17	377373	60	0	0	545643	923076
9	1	17	157061	87	0	0	765928	923076
10	2	17	292217	62	1351	0	629384	923076
11	1	17	144491	51	0	0	778534	923076
12	2	17	118869	81	1636	0	802409	923076
13	1	17	731121	62	0	0	191893	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 80 of 177

Type 5 #17 5501 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	397535	58	1031	0	524394	923076
2	3	17	63417	51	1327	967	857212	923076
3	1	17	535476	77	0	0	387523	923076
4	3	17	243769	73	1017	1886	676185	923076
5	3	17	141252	58	1246	1192	779212	923076
6	1	17	739492	95	0	0	183489	923076
7	3	17	335465	71	1630	1926	583842	923076
8	1	17	260390	79	0	0	662607	923076
9	2	17	174297	83	1004	0	747609	923076
10	1	17	146360	89	0	0	776627	923076
11	3	17	494218	73	1761	1075	425803	923076
12	1	17	166948	54	0	0	756074	923076
13	3	17	235594	96	1325	1121	684748	923076

Type 5 #18 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	14	382416	54	0	0	249108	631578
2	1	14	427363	60	0	0	204155	631578
3	3	14	103571	58	987	1057	525789	631578
4	2	14	217521	100	1073	0	412784	631578
5	1	14	103284	79	0	0	528215	631578
6	3	14	237475	64	1335	1689	390887	631578
7	1	14	525216	61	0	0	106301	631578
8	1	14	349788	94	0	0	281696	631578
9	2	14	98557	73	1848	0	531027	631578
10	2	14	422604	68	974	0	207864	631578
11	1	14	510155	69	0	0	121354	631578
12	1	14	184376	94	0	0	447108	631578
13	1	14	207233	97	0	0	424248	631578
14	3	14	586759	91	1208	1579	41759	631578
15	3	14	276407	60	1227	1641	352123	631578
16	1	14	244493	86	0	0	386999	631578
17	2	14	148337	86	1268	0	481801	631578
18	3	14	620756	69	1398	1149	8068	631578
19	3	14	600142	95	1749	1655	27747	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 81 of 177

Type 5 #19 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	937447	72	1786	0	260623	1200000
2	2	18	873479	91	1781	0	324558	1200000
3	3	18	671390	74	1466	1700	525222	1200000
4	3	18	314361	65	1179	1027	883238	1200000
5	2	18	1134226	73	1378	0	64250	1200000
6	1	18	531796	66	0	0	668138	1200000
7	3	18	356736	74	1123	1590	840329	1200000
8	2	18	488122	97	1445	0	710239	1200000
9	3	18	534609	83	1914	1510	661718	1200000
10	3	18	852069	66	1468	1549	344716	1200000

Type 5 #20 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	35150	50	0	0	1298133	1333333
2	1	15	663453	74	0	0	669806	1333333
3	1	15	1315650	64	0	0	17619	1333333
4	3	15	491845	67	1196	1234	838857	1333333
5	3	15	988932	85	1356	1690	341100	1333333
6	3	15	822181	93	1118	915	508840	1333333
7	3	15	872324	67	1758	1883	457167	1333333
8	2	15	1141088	77	1795	0	190296	1333333
9	3	15	1228720	86	1900	923	101532	1333333

Type 5 #21 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	8	13109	53	1111	1787	1317167	1333333
2	2	8	255162	91	1804	0	1076185	1333333
3	2	8	638622	100	1389	0	693122	1333333
4	2	8	523234	69	1775	0	808186	1333333
5	2	8	1202067	80	1681	0	129425	1333333
6	3	8	1097072	89	1318	1669	233007	1333333
7	3	8	990809	70	1879	1693	338742	1333333
8	2	8	564120	88	1055	0	767982	1333333
9	3	8	558863	67	1816	1316	771137	1333333

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 82 of 177

Type 5 #22 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	383789	80	999	1631	704250	1090909
2	2	12	179467	54	1884	0	909450	1090909
3	3	12	585740	54	1082	1313	502612	1090909
4	2	12	687560	53	1664	0	401579	1090909
5	3	12	911565	73	1176	957	176992	1090909
6	2	12	387310	81	1381	0	702056	1090909
7	2	12	931853	71	958	0	157956	1090909
8	3	12	608012	52	1617	1289	479835	1090909
9	2	12	684980	86	1512	0	404245	1090909
10	3	12	573575	80	1234	1800	514060	1090909
11	2	12	502682	86	1528	0	586527	1090909

Type 5 #23 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	17	701745	84	1834	0	296253	1000000
2	1	17	979186	81	0	0	20733	1000000
3	2	17	48077	84	933	0	950822	1000000
4	1	17	855269	64	0	0	144667	1000000
5	3	17	26110	59	1149	1372	971192	1000000
6	3	17	445476	57	1889	998	551466	1000000
7	3	17	984380	62	1668	1812	11954	1000000
8	2	17	437912	82	1310	0	560614	1000000
9	1	17	914822	83	0	0	85095	1000000
10	2	17	69947	65	1414	0	928509	1000000
11	2	17	888244	74	1192	0	110416	1000000
12	2	17	554729	62	1125	0	444022	1000000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 83 of 177

Type 5 #24 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	8	455465	68	1582	1374	208041	666666
2	1	8	485226	58	0	0	181382	666666
3	3	8	370889	99	1658	1146	292676	666666
4	3	8	309415	55	1797	1590	353699	666666
5	3	8	557054	53	1332	1904	106217	666666
6	2	8	225314	87	1368	0	439810	666666
7	2	8	661842	89	1028	0	3618	666666
8	2	8	278516	85	1572	0	386408	666666
9	2	8	339012	85	1404	0	326080	666666
10	2	8	556197	93	1549	0	108734	666666
11	3	8	298503	59	1309	1407	365270	666666
12	1	8	473967	87	0	0	192612	666666
13	1	8	414869	96	0	0	251701	666666
14	3	8	423552	100	1342	1693	239779	666666
15	2	8	428391	93	954	0	237135	666666
16	2	8	129955	84	1363	0	535180	666666
17	2	8	422321	64	1554	0	242663	666666
18	2	8	362295	78	1574	0	302641	666666

Type 5 #25 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	420362	78	1019	1345	500116	923076
2	3	20	616357	84	1149	1326	303992	923076
3	1	20	191078	59	0	0	731939	923076
4	1	20	715814	86	0	0	207176	923076
5	1	20	91420	64	0	0	831592	923076
6	1	20	911276	88	0	0	11712	923076
7	2	20	228139	71	1719	0	693076	923076
8	1	20	38567	85	0	0	884424	923076
9	3	20	851219	61	1710	1159	68805	923076
10	3	20	714102	60	1103	1378	206313	923076
11	1	20	518633	70	0	0	404373	923076
12	3	20	48165	62	1243	1785	871697	923076
13	3	20	264801	92	1128	1006	655865	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 84 of 177

Type 5 #26 5504 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	123648	89	1484	0	624690	750000
2	1	9	3714	75	0	0	746211	750000
3	3	9	440487	68	1829	1370	306110	750000
4	1	9	10722	60	0	0	739218	750000
5	1	9	726000	61	0	0	23939	750000
6	1	9	673431	100	0	0	76469	750000
7	2	9	618591	54	1946	0	129355	750000
8	3	9	151204	79	1303	1873	595383	750000
9	3	9	233946	60	1331	1705	512838	750000
10	1	9	460616	50	0	0	289334	750000
11	1	9	686395	83	0	0	63522	750000
12	1	9	707738	54	0	0	42208	750000
13	3	9	711301	74	1897	1233	35347	750000
14	1	9	398233	57	0	0	351710	750000
15	2	9	169125	66	1142	0	579601	750000
16	1	9	725390	66	0	0	24544	750000

Type 5 #27 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	8	188286	83	1885	1161	475085	666666
2	2	8	494600	71	1013	0	170911	666666
3	2	8	317436	59	1510	0	347602	666666
4	2	8	199203	50	1235	0	466128	666666
5	2	8	423320	68	1329	0	241881	666666
6	2	8	396376	94	1602	0	268500	666666
7	1	8	153157	55	0	0	513454	666666
8	1	8	483651	89	0	0	182926	666666
9	1	8	759	74	0	0	665833	666666
10	3	8	424404	90	1032	922	240038	666666
11	3	8	356334	70	1845	1613	306664	666666
12	1	8	380019	64	0	0	286583	666666
13	2	8	301478	97	1881	0	363113	666666
14	2	8	7518	73	1564	0	657438	666666
15	2	8	580592	85	1205	0	84699	666666
16	3	8	246790	81	1434	922	417277	666666
17	2	8	197452	67	1622	0	467458	666666
18	1	8	11269	68	0	0	655329	666666

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 85 of 177

Type 5 #28 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	19	1174597	95	1022	1005	156424	1333333
2	3	19	645054	77	1241	1473	685334	1333333
3	1	19	552455	61	0	0	780817	1333333
4	1	19	1219587	52	0	0	113694	1333333
5	2	19	125387	89	1109	0	1206659	1333333
6	2	19	260958	68	1088	0	1071151	1333333
7	1	19	1175670	52	0	0	157611	1333333
8	2	19	1028565	91	1081	0	303505	1333333
9	3	19	1093762	97	1048	1589	236643	1333333

Type 5 #29 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	15	417144	50	1833	0	1080923	1500000
2	1	15	962758	78	0	0	537164	1500000
3	1	15	34626	100	0	0	1465274	1500000
4	2	15	259095	76	1315	0	1239438	1500000
5	1	15	178849	75	0	0	1321076	1500000
6	3	15	1435139	62	1780	1207	61688	1500000
7	3	15	96975	71	1138	1305	1400369	1500000
8	1	15	411083	68	0	0	1088849	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 86 of 177

Type 5 #30 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	514521	74	1166	1356	114313	631578
2	1	20	255179	57	0	0	376342	631578
3	2	20	198635	84	1395	0	431380	631578
4	1	20	243831	61	0	0	387686	631578
5	2	20	70253	72	1523	0	559658	631578
6	1	20	303511	74	0	0	327993	631578
7	3	20	160590	65	1689	1051	468053	631578
8	2	20	164410	50	1830	0	465238	631578
9	2	20	349741	71	952	0	280743	631578
10	2	20	38439	88	1643	0	591320	631578
11	3	20	301825	100	1170	1777	326506	631578
12	3	20	23975	95	925	1852	604541	631578
13	2	20	479734	59	1188	0	150538	631578
14	2	20	515891	86	1211	0	114304	631578
15	2	20	469145	52	1933	0	160396	631578
16	1	20	297439	52	0	0	334087	631578
17	3	20	69710	52	1006	1248	559458	631578
18	2	20	78019	62	1604	0	551831	631578
19	3	20	314570	93	1298	1729	313702	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 87 of 177

Type 6 #1 [Back to Summary]

#01-5286	#02-5395	#03-5589	#04-5340	#05-5692	#06-5565	#07-5612	#08-5288	#09-5558	#10-5721
#11-5398	#12-5673	#13-5599	#14-5593	#15-5655	#16-5616	#17-5511	#18-5303	#19-5719	#20-5331
#21-5313	#22-5557	#23-5315	#24-5381	#25-5400	#26-5697	#27-5440	#28-5332	#29-5667	#30-5482
#31-5600	#32-5518	#33-5327	#34-5366	#35-5700	#36-5598	#37-5687	#38-5383	#39-5678	#40-5432
#41-5561	#42-5714	#43-5306	#44-5415	#45-5268	#46-5698	#47-5378	#48-5330	#49-5396	#50-5346
#51-5441	#52-5424	#53-5453	#54-5457	#55-5664	#56-5720	#57-5375	#58-5530	#59-5325	#60-5370
#61-5604	#62-5596	#63-5483	#64-5617	#65-5307	#66-5653	#67-5350	#68-5536	#69-5495	#70-5323
#71-5723	#72-5258	#73-5300	#74-5710	#75-5467	#76-5679	#77-5587	#78-5336	#79-5504	#80-5494
#81-5666	#82-5496	#83-5517	#84-5479	#85-5443	#86-5682	#87-5281	#88-5618	#89-5661	#90-5451
#91-5543	#92-5510	#93-5320	#94-5401	#95-5629	#96-5455	#97-5322	#98-5407	#99-5291	#100-5633

Type 6 #2 [Back to Summary]

#01-5576	#02-5483	#03-5714	#04-5590	#05-5526	#06-5352	#07-5541	#08-5371	#09-5514	#10-5424
#11-5659	#12-5392	#13-5479	#14-5463	#15-5430	#16-5490	#17-5322	#18-5573	#19-5416	#20-5417
#21-5386	#22-5608	#23-5436	#24-5317	#25-5509	#26-5423	#27-5565	#28-5291	#29-5445	#30-5488
#31-5641	#32-5399	#33-5384	#34-5492	#35-5320	#36-5649	#37-5441	#38-5694	#39-5683	#40-5531
#41-5701	#42-5333	#43-5578	#44-5400	#45-5574	#46-5645	#47-5689	#48-5724	#49-5558	#50-5512
#51-5598	#52-5496	#53-5692	#54-5297	#55-5647	#56-5331	#57-5353	#58-5646	#59-5329	#60-5319
#61-5421	#62-5476	#63-5283	#64-5296	#65-5722	#66-5252	#67-5699	#68-5448	#69-5428	#70-5327
#71-5459	#72-5708	#73-5655	#74-5273	#75-5581	#76-5700	#77-5292	#78-5628	#79-5462	#80-5337
#81-5570	#82-5546	#83-5520	#84-5718	#85-5604	#86-5461	#87-5599	#88-5637	#89-5540	#90-5691
#91-5634	#92-5537	#93-5318	#94-5615	#95-5562	#96-5664	#97-5315	#98-5305	#99-5588	#100-5433

Type 6 #3 [Back to Summary]

#01-5426	#02-5546	#03-5683	#04-5402	#05-5262	#06-5352	#07-5429	#08-5455	#09-5548	#10-5590
#11-5584	#12-5320	#13-5553	#14-5678	#15-5290	#16-5296	#17-5361	#18-5448	#19-5579	#20-5413
#21-5616	#22-5560	#23-5571	#24-5500	#25-5630	#26-5564	#27-5467	#28-5454	#29-5662	#30-5601
#31-5587	#32-5261	#33-5442	#34-5643	#35-5618	#36-5719	#37-5640	#38-5538	#39-5709	#40-5531
#41-5357	#42-5670	#43-5494	#44-5275	#45-5702	#46-5593	#47-5376	#48-5274	#49-5259	#50-5400
#51-5258	#52-5282	#53-5542	#54-5591	#55-5700	#56-5433	#57-5496	#58-5423	#59-5610	#60-5699
#61-5518	#62-5672	#63-5252	#64-5573	#65-5602	#66-5635	#67-5309	#68-5381	#69-5547	#70-5463
#71-5298	#72-5305	#73-5671	#74-5315	#75-5545	#76-5522	#77-5286	#78-5717	#79-5341	#80-5430
#81-5652	#82-5710	#83-5436	#84-5253	#85-5410	#86-5351	#87-5277	#88-5268	#89-5456	#90-5291
#91-5536	#92-5646	#93-5382	#94-5401	#95-5272	#96-5379	#97-5716	#98-5660	#99-5316	#100-5603

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 88 of 177

Type 6 #4 [Back to Summary]									
#01-5318	#02-5662	#03-5684	#04-5702	#05-5595	#06-5525	#07-5404	#08-5636	#09-5459	#10-5431
#11-5519	#12-5590	#13-5686	#14-5541	#15-5570	#16-5442	#17-5534	#18-5282	#19-5278	#20-5649
#21-5505	#22-5652	#23-5377	#24-5647	#25-5493	#26-5523	#27-5393	#28-5295	#29-5306	#30-5274
#31-5452	#32-5299	#33-5641	#34-5499	#35-5293	#36-5433	#37-5480	#38-5476	#39-5589	#40-5545
#41-5557	#42-5354	#43-5376	#44-5588	#45-5536	#46-5585	#47-5456	#48-5284	#49-5674	#50-5678
#51-5538	#52-5260	#53-5305	#54-5325	#55-5281	#56-5605	#57-5492	#58-5414	#59-5374	#60-5494
#61-5316	#62-5540	#63-5291	#64-5526	#65-5259	#66-5303	#67-5530	#68-5673	#69-5547	#70-5250
#71-5308	#72-5708	#73-5633	#74-5317	#75-5584	#76-5497	#77-5655	#78-5715	#79-5503	#80-5346
#81-5353	#82-5489	#83-5460	#84-5378	#85-5405	#86-5445	#87-5302	#88-5392	#89-5705	#90-5606
#91-5521	#92-5720	#93-5257	#94-5514	#95-5323	#96-5479	#97-5510	#98-5573	#99-5437	#100-5721

Type 6 #5 [Back to Summary]									
#01-5342	#02-5373	#03-5538	#04-5633	#05-5641	#06-5444	#07-5504	#08-5666	#09-5527	#10-5315
#11-5605	#12-5623	#13-5334	#14-5430	#15-5302	#16-5530	#17-5566	#18-5368	#19-5512	#20-5712
#21-5343	#22-5627	#23-5577	#24-5707	#25-5581	#26-5485	#27-5717	#28-5497	#29-5488	#30-5301
#31-5628	#32-5381	#33-5313	#34-5321	#35-5419	#36-5394	#37-5475	#38-5511	#39-5351	#40-5525
#41-5598	#42-5612	#43-5425	#44-5329	#45-5521	#46-5309	#47-5595	#48-5438	#49-5459	#50-5354
#51-5280	#52-5636	#53-5306	#54-5659	#55-5587	#56-5269	#57-5546	#58-5672	#59-5428	#60-5412
#61-5474	#62-5559	#63-5262	#64-5261	#65-5632	#66-5304	#67-5305	#68-5267	#69-5529	#70-5436
#71-5469	#72-5264	#73-5635	#74-5324	#75-5406	#76-5341	#77-5637	#78-5700	#79-5431	#80-5439
#81-5647	#82-5683	#83-5291	#84-5508	#85-5337	#86-5541	#87-5648	#88-5332	#89-5411	#90-5578
#91-5420	#92-5387	#93-5503	#94-5409	#95-5590	#96-5317	#97-5613	#98-5254	#99-5540	#100-5421

Type 6 #6 [Back to Summary]									
#01-5654	#02-5642	#03-5535	#04-5621	#05-5395	#06-5585	#07-5430	#08-5652	#09-5633	#10-5697
#11-5724	#12-5294	#13-5551	#14-5601	#15-5696	#16-5478	#17-5544	#18-5487	#19-5382	#20-5659
#21-5368	#22-5583	#23-5299	#24-5602	#25-5381	#26-5639	#27-5541	#28-5685	#29-5569	#30-5336
#31-5423	#32-5615	#33-5268	#34-5718	#35-5290	#36-5481	#37-5612	#38-5667	#39-5681	#40-5467
#41-5405	#42-5502	#43-5605	#44-5420	#45-5343	#46-5531	#47-5713	#48-5410	#49-5564	#50-5319
#51-5491	#52-5407	#53-5486	#54-5536	#55-5308	#56-5263	#57-5670	#58-5613	#59-5692	#60-5313
#61-5610	#62-5550	#63-5403	#64-5679	#65-5558	#66-5560	#67-5465	#68-5591	#69-5504	#70-5590
#71-5702	#72-5604	#73-5509	#74-5575	#75-5306	#76-5553	#77-5525	#78-5255	#79-5267	#80-5656
#81-5458	#82-5506	#83-5431	#84-5706	#85-5720	#86-5593	#87-5653	#88-5260	#89-5579	#90-5438
#91-5439	#92-5594	#93-5665	#94-5577	#95-5274	#96-5402	#97-5698	#98-5441	#99-5493	#100-5707

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 89 of 177

Type 6 #7 [Back to Summary]									
#01-5671	#02-5331	#03-5607	#04-5484	#05-5413	#06-5614	#07-5310	#08-5416	#09-5308	#10-5593
#11-5618	#12-5670	#13-5422	#14-5376	#15-5579	#16-5470	#17-5722	#18-5674	#19-5520	#20-5316
#21-5400	#22-5707	#23-5259	#24-5568	#25-5723	#26-5281	#27-5580	#28-5550	#29-5696	#30-5689
#31-5523	#32-5485	#33-5625	#34-5362	#35-5358	#36-5490	#37-5371	#38-5518	#39-5271	#40-5381
#41-5700	#42-5720	#43-5404	#44-5623	#45-5548	#46-5450	#47-5492	#48-5414	#49-5433	#50-5641
#51-5348	#52-5597	#53-5640	#54-5582	#55-5635	#56-5561	#57-5276	#58-5292	#59-5647	#60-5705
#61-5616	#62-5678	#63-5357	#64-5613	#65-5434	#66-5399	#67-5516	#68-5295	#69-5269	#70-5581
#71-5283	#72-5573	#73-5569	#74-5383	#75-5576	#76-5380	#77-5305	#78-5532	#79-5505	#80-5690
#81-5527	#82-5442	#83-5325	#84-5514	#85-5354	#86-5333	#87-5303	#88-5264	#89-5256	#90-5595
#91-5342	#92-5337	#93-5596	#94-5501	#95-5491	#96-5564	#97-5317	#98-5570	#99-5448	#100-5309

Type 6 #8 [Back to Summary]									
#01-5431	#02-5695	#03-5709	#04-5365	#05-5449	#06-5266	#07-5651	#08-5401	#09-5591	#10-5420
#11-5358	#12-5610	#13-5634	#14-5585	#15-5639	#16-5497	#17-5704	#18-5559	#19-5313	#20-5376
#21-5706	#22-5287	#23-5693	#24-5250	#25-5517	#26-5589	#27-5260	#28-5439	#29-5285	#30-5375
#31-5479	#32-5315	#33-5548	#34-5252	#35-5384	#36-5349	#37-5663	#38-5539	#39-5489	#40-5330
#41-5444	#42-5476	#43-5641	#44-5674	#45-5379	#46-5257	#47-5586	#48-5719	#49-5584	#50-5482
#51-5507	#52-5322	#53-5327	#54-5394	#55-5708	#56-5572	#57-5255	#58-5462	#59-5665	#60-5295
#61-5604	#62-5544	#63-5336	#64-5582	#65-5505	#66-5398	#67-5291	#68-5269	#69-5512	#70-5535
#71-5302	#72-5301	#73-5387	#74-5724	#75-5577	#76-5317	#77-5618	#78-5697	#79-5718	#80-5470
#81-5583	#82-5381	#83-5340	#84-5679	#85-5483	#86-5593	#87-5328	#88-5595	#89-5319	#90-5645
#91-5403	#92-5571	#93-5542	#94-5463	#95-5683	#96-5276	#97-5540	#98-5657	#99-5435	#100-5253

Type 6 #9 [Back to Summary]									
#01-5256	#02-5609	#03-5324	#04-5598	#05-5401	#06-5631	#07-5551	#08-5590	#09-5724	#10-5373
#11-5282	#12-5675	#13-5315	#14-5427	#15-5434	#16-5431	#17-5706	#18-5552	#19-5661	#20-5571
#21-5496	#22-5444	#23-5499	#24-5405	#25-5264	#26-5691	#27-5655	#28-5432	#29-5433	#30-5629
#31-5477	#32-5709	#33-5253	#34-5662	#35-5413	#36-5257	#37-5305	#38-5403	#39-5682	#40-5538
#41-5591	#42-5397	#43-5617	#44-5573	#45-5356	#46-5583	#47-5493	#48-5607	#49-5317	#50-5409
#51-5363	#52-5604	#53-5348	#54-5721	#55-5585	#56-5660	#57-5250	#58-5666	#59-5574	#60-5296
#61-5364	#62-5563	#63-5443	#64-5430	#65-5312	#66-5712	#67-5543	#68-5544	#69-5605	#70-5418
#71-5539	#72-5632	#73-5371	#74-5367	#75-5548	#76-5390	#77-5664	#78-5482	#79-5272	#80-5608
#81-5596	#82-5447	#83-5520	#84-5370	#85-5265	#86-5689	#87-5545	#88-5304	#89-5380	#90-5650
#91-5521	#92-5505	#93-5382	#94-5436	#95-5716	#96-5698	#97-5441	#98-5714	#99-5467	#100-5361

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 90 of 177

Type 6 #10 [Back to Summary]									
#01-5584	#02-5252	#03-5342	#04-5273	#05-5481	#06-5495	#07-5572	#08-5306	#09-5473	#10-5515
#11-5272	#12-5397	#13-5485	#14-5264	#15-5523	#16-5667	#17-5336	#18-5700	#19-5316	#20-5712
#21-5623	#22-5594	#23-5408	#24-5349	#25-5684	#26-5422	#27-5325	#28-5297	#29-5400	#30-5372
#31-5458	#32-5274	#33-5655	#34-5258	#35-5544	#36-5263	#37-5596	#38-5521	#39-5526	#40-5533
#41-5593	#42-5298	#43-5715	#44-5359	#45-5640	#46-5676	#47-5702	#48-5275	#49-5281	#50-5354
#51-5429	#52-5479	#53-5463	#54-5569	#55-5717	#56-5314	#57-5309	#58-5420	#59-5525	#60-5631
#61-5350	#62-5307	#63-5723	#64-5466	#65-5476	#66-5445	#67-5510	#68-5320	#69-5540	#70-5423
#71-5508	#72-5428	#73-5279	#74-5545	#75-5418	#76-5714	#77-5293	#78-5470	#79-5348	#80-5271
#81-5369	#82-5268	#83-5444	#84-5425	#85-5520	#86-5554	#87-5419	#88-5603	#89-5457	#90-5467
#91-5363	#92-5687	#93-5672	#94-5657	#95-5361	#96-5424	#97-5449	#98-5506	#99-5490	#100-5685

Type 6 #11 [Back to Summary]									
#01-5539	#02-5565	#03-5646	#04-5301	#05-5433	#06-5419	#07-5400	#08-5253	#09-5270	#10-5563
#11-5322	#12-5503	#13-5512	#14-5332	#15-5588	#16-5403	#17-5290	#18-5680	#19-5616	#20-5340
#21-5442	#22-5681	#23-5395	#24-5420	#25-5316	#26-5598	#27-5485	#28-5602	#29-5594	#30-5271
#31-5566	#32-5506	#33-5408	#34-5454	#35-5603	#36-5648	#37-5374	#38-5336	#39-5385	#40-5268
#41-5600	#42-5436	#43-5629	#44-5291	#45-5480	#46-5425	#47-5590	#48-5319	#49-5683	#50-5383
#51-5494	#52-5615	#53-5399	#54-5493	#55-5456	#56-5608	#57-5501	#58-5605	#59-5367	#60-5545
#61-5640	#62-5375	#63-5401	#64-5541	#65-5721	#66-5353	#67-5709	#68-5479	#69-5641	#70-5593
#71-5567	#72-5621	#73-5302	#74-5665	#75-5258	#76-5415	#77-5644	#78-5461	#79-5502	#80-5675
#81-5356	#82-5722	#83-5720	#84-5397	#85-5694	#86-5564	#87-5352	#88-5474	#89-5285	#90-5337
#91-5535	#92-5483	#93-5321	#94-5711	#95-5335	#96-5453	#97-5466	#98-5625	#99-5384	#100-5327

Type 6 #12 [Back to Summary]									
#01-5651	#02-5560	#03-5556	#04-5397	#05-5665	#06-5475	#07-5537	#08-5455	#09-5289	#10-5529
#11-5614	#12-5437	#13-5605	#14-5714	#15-5332	#16-5623	#17-5641	#18-5694	#19-5342	#20-5585
#21-5690	#22-5543	#23-5431	#24-5544	#25-5271	#26-5329	#27-5441	#28-5719	#29-5602	#30-5540
#31-5279	#32-5412	#33-5413	#34-5250	#35-5553	#36-5468	#37-5277	#38-5268	#39-5345	#40-5297
#41-5255	#42-5593	#43-5609	#44-5356	#45-5346	#46-5370	#47-5319	#48-5251	#49-5358	#50-5558
#51-5699	#52-5591	#53-5578	#54-5483	#55-5656	#56-5516	#57-5395	#58-5264	#59-5670	#60-5713
#61-5448	#62-5443	#63-5550	#64-5331	#65-5568	#66-5404	#67-5341	#68-5324	#69-5490	#70-5642
#71-5563	#72-5660	#73-5639	#74-5708	#75-5320	#76-5649	#77-5600	#78-5322	#79-5645	#80-5405
#81-5547	#82-5396	#83-5485	#84-5457	#85-5254	#86-5399	#87-5610	#88-5266	#89-5257	#90-5410
#91-5637	#92-5520	#93-5476	#94-5571	#95-5267	#96-5484	#97-5458	#98-5673	#99-5291	#100-5644

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 91 of 177

Type 6 #13 [Back to Summary]									
#01-5720	#02-5601	#03-5412	#04-5668	#05-5271	#06-5536	#07-5641	#08-5665	#09-5292	#10-5256
#11-5252	#12-5660	#13-5497	#14-5592	#15-5378	#16-5609	#17-5319	#18-5341	#19-5281	#20-5520
#21-5555	#22-5499	#23-5437	#24-5423	#25-5278	#26-5468	#27-5627	#28-5646	#29-5703	#30-5598
#31-5355	#32-5400	#33-5541	#34-5295	#35-5310	#36-5323	#37-5350	#38-5317	#39-5367	#40-5631
#41-5518	#42-5353	#43-5704	#44-5450	#45-5383	#46-5414	#47-5642	#48-5495	#49-5339	#50-5470
#51-5599	#52-5699	#53-5637	#54-5572	#55-5508	#56-5422	#57-5287	#58-5371	#59-5277	#60-5379
#61-5554	#62-5346	#63-5300	#64-5493	#65-5563	#66-5259	#67-5687	#68-5683	#69-5419	#70-5488
#71-5382	#72-5345	#73-5644	#74-5652	#75-5444	#76-5299	#77-5268	#78-5494	#79-5481	#80-5586
#81-5681	#82-5585	#83-5311	#84-5320	#85-5260	#86-5397	#87-5530	#88-5540	#89-5653	#90-5279
#91-5721	#92-5604	#93-5388	#94-5523	#95-5606	#96-5544	#97-5404	#98-5684	#99-5325	#100-5575

Type 6 #14 [Back to Summary]									
#01-5338	#02-5503	#03-5305	#04-5709	#05-5378	#06-5458	#07-5404	#08-5518	#09-5614	#10-5416
#11-5422	#12-5694	#13-5285	#14-5704	#15-5483	#16-5493	#17-5586	#18-5407	#19-5392	#20-5491
#21-5459	#22-5385	#23-5466	#24-5505	#25-5379	#26-5563	#27-5370	#28-5311	#29-5675	#30-5326
#31-5431	#32-5722	#33-5509	#34-5461	#35-5707	#36-5482	#37-5265	#38-5413	#39-5402	#40-5332
#41-5498	#42-5486	#43-5356	#44-5437	#45-5690	#46-5554	#47-5571	#48-5674	#49-5448	#50-5301
#51-5542	#52-5541	#53-5558	#54-5366	#55-5677	#56-5286	#57-5524	#58-5580	#59-5539	#60-5337
#61-5342	#62-5568	#63-5538	#64-5710	#65-5425	#66-5434	#67-5548	#68-5251	#69-5477	#70-5423
#71-5255	#72-5310	#73-5718	#74-5697	#75-5279	#76-5278	#77-5549	#78-5716	#79-5421	#80-5588
#81-5623	#82-5508	#83-5430	#84-5676	#85-5345	#86-5445	#87-5557	#88-5587	#89-5719	#90-5405
#91-5643	#92-5543	#93-5452	#94-5515	#95-5369	#96-5272	#97-5446	#98-5481	#99-5565	#100-5393

Type 6 #15 [Back to Summary]									
#01-5648	#02-5257	#03-5709	#04-5280	#05-5547	#06-5641	#07-5479	#08-5669	#09-5279	#10-5525
#11-5720	#12-5483	#13-5453	#14-5692	#15-5531	#16-5261	#17-5591	#18-5392	#19-5315	#20-5562
#21-5304	#22-5460	#23-5551	#24-5274	#25-5430	#26-5694	#27-5468	#28-5391	#29-5324	#30-5389
#31-5442	#32-5673	#33-5360	#34-5676	#35-5355	#36-5437	#37-5481	#38-5526	#39-5289	#40-5327
#41-5651	#42-5698	#43-5514	#44-5519	#45-5611	#46-5544	#47-5640	#48-5537	#49-5502	#50-5573
#51-5415	#52-5253	#53-5339	#54-5431	#55-5684	#56-5575	#57-5578	#58-5422	#59-5338	#60-5594
#61-5614	#62-5333	#63-5296	#64-5372	#65-5501	#66-5587	#67-5343	#68-5504	#69-5314	#70-5353
#71-5713	#72-5636	#73-5330	#74-5671	#75-5624	#76-5480	#77-5400	#78-5484	#79-5475	#80-5511
#81-5593	#82-5508	#83-5357	#84-5642	#85-5255	#86-5521	#87-5435	#88-5630	#89-5354	#90-5567
#91-5472	#92-5488	#93-5292	#94-5283	#95-5438	#96-5470	#97-5427	#98-5342	#99-5258	#100-5491

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 92 of 177

Type 6 #16 [Back to Summary]									
#01-5531	#02-5454	#03-5281	#04-5428	#05-5662	#06-5587	#07-5332	#08-5252	#09-5465	#10-5513
#11-5265	#12-5638	#13-5669	#14-5338	#15-5708	#16-5362	#17-5642	#18-5323	#19-5701	#20-5297
#21-5307	#22-5257	#23-5305	#24-5357	#25-5653	#26-5478	#27-5423	#28-5372	#29-5330	#30-5579
#31-5401	#32-5448	#33-5316	#34-5645	#35-5692	#36-5699	#37-5271	#38-5621	#39-5352	#40-5684
#41-5473	#42-5379	#43-5427	#44-5458	#45-5299	#46-5325	#47-5552	#48-5344	#49-5268	#50-5282
#51-5444	#52-5474	#53-5447	#54-5700	#55-5321	#56-5550	#57-5659	#58-5578	#59-5554	#60-5342
#61-5432	#62-5724	#63-5309	#64-5518	#65-5614	#66-5641	#67-5442	#68-5635	#69-5365	#70-5348
#71-5680	#72-5400	#73-5679	#74-5557	#75-5703	#76-5660	#77-5347	#78-5544	#79-5710	#80-5721
#81-5546	#82-5682	#83-5594	#84-5670	#85-5392	#86-5290	#87-5417	#88-5317	#89-5259	#90-5501
#91-5319	#92-5634	#93-5569	#94-5383	#95-5608	#96-5704	#97-5327	#98-5293	#99-5519	#100-5393

Type 6 #17 [Back to Summary]									
#01-5343	#02-5614	#03-5465	#04-5400	#05-5456	#06-5522	#07-5446	#08-5253	#09-5487	#10-5561
#11-5640	#12-5296	#13-5497	#14-5699	#15-5698	#16-5308	#17-5512	#18-5333	#19-5669	#20-5520
#21-5633	#22-5276	#23-5599	#24-5295	#25-5464	#26-5627	#27-5256	#28-5326	#29-5469	#30-5638
#31-5429	#32-5443	#33-5526	#34-5567	#35-5502	#36-5550	#37-5267	#38-5585	#39-5462	#40-5305
#41-5470	#42-5557	#43-5323	#44-5654	#45-5336	#46-5360	#47-5667	#48-5255	#49-5586	#50-5539
#51-5685	#52-5574	#53-5604	#54-5309	#55-5435	#56-5588	#57-5590	#58-5354	#59-5717	#60-5620
#61-5439	#62-5651	#63-5268	#64-5647	#65-5460	#66-5578	#67-5695	#68-5381	#69-5483	#70-5495
#71-5472	#72-5457	#73-5587	#74-5325	#75-5678	#76-5670	#77-5683	#78-5353	#79-5684	#80-5251
#81-5655	#82-5677	#83-5579	#84-5564	#85-5467	#86-5382	#87-5637	#88-5592	#89-5544	#90-5390
#91-5535	#92-5534	#93-5293	#94-5463	#95-5367	#96-5388	#97-5447	#98-5359	#99-5635	#100-5644

Type 6 #18 [Back to Summary]									
#01-5396	#02-5613	#03-5660	#04-5438	#05-5437	#06-5337	#07-5695	#08-5606	#09-5263	#10-5478
#11-5724	#12-5533	#13-5523	#14-5583	#15-5604	#16-5615	#17-5600	#18-5293	#19-5511	#20-5527
#21-5477	#22-5449	#23-5688	#24-5398	#25-5442	#26-5360	#27-5611	#28-5464	#29-5462	#30-5425
#31-5270	#32-5273	#33-5252	#34-5290	#35-5490	#36-5703	#37-5631	#38-5401	#39-5357	#40-5451
#41-5430	#42-5562	#43-5470	#44-5637	#45-5536	#46-5250	#47-5555	#48-5435	#49-5476	#50-5513
#51-5403	#52-5572	#53-5358	#54-5417	#55-5672	#56-5650	#57-5721	#58-5326	#59-5480	#60-5394
#61-5457	#62-5701	#63-5530	#64-5483	#65-5342	#66-5626	#67-5708	#68-5448	#69-5661	#70-5310
#71-5347	#72-5640	#73-5704	#74-5301	#75-5587	#76-5441	#77-5426	#78-5710	#79-5591	#80-5619
#81-5597	#82-5543	#83-5303	#84-5370	#85-5405	#86-5280	#87-5674	#88-5632	#89-5429	#90-5560
#91-5445	#92-5321	#93-5681	#94-5492	#95-5314	#96-5467	#97-5260	#98-5502	#99-5693	#100-5599

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 93 of 177

Type 6 #19 [Back to Summary]									
#01-5649	#02-5529	#03-5520	#04-5274	#05-5598	#06-5408	#07-5650	#08-5591	#09-5525	#10-5636
#11-5610	#12-5524	#13-5572	#14-5588	#15-5293	#16-5630	#17-5310	#18-5397	#19-5472	#20-5321
#21-5596	#22-5276	#23-5721	#24-5458	#25-5334	#26-5468	#27-5373	#28-5639	#29-5608	#30-5345
#31-5575	#32-5429	#33-5445	#34-5600	#35-5485	#36-5700	#37-5325	#38-5259	#39-5706	#40-5562
#41-5285	#42-5534	#43-5436	#44-5542	#45-5359	#46-5628	#47-5270	#48-5451	#49-5280	#50-5621
#51-5252	#52-5622	#53-5533	#54-5311	#55-5665	#56-5674	#57-5328	#58-5467	#59-5277	#60-5514
#61-5393	#62-5418	#63-5395	#64-5335	#65-5463	#66-5340	#67-5283	#68-5716	#69-5437	#70-5272
#71-5517	#72-5540	#73-5564	#74-5551	#75-5536	#76-5269	#77-5315	#78-5678	#79-5426	#80-5547
#81-5316	#82-5424	#83-5284	#84-5376	#85-5319	#86-5399	#87-5506	#88-5647	#89-5592	#90-5690
#91-5577	#92-5417	#93-5365	#94-5530	#95-5693	#96-5631	#97-5346	#98-5289	#99-5398	#100-5384

Type 6 #20 [Back to Summary]									
#01-5350	#02-5501	#03-5655	#04-5422	#05-5257	#06-5449	#07-5720	#08-5692	#09-5570	#10-5351
#11-5695	#12-5300	#13-5669	#14-5393	#15-5437	#16-5663	#17-5566	#18-5649	#19-5574	#20-5329
#21-5698	#22-5369	#23-5322	#24-5477	#25-5498	#26-5398	#27-5457	#28-5641	#29-5384	#30-5611
#31-5717	#32-5694	#33-5376	#34-5414	#35-5701	#36-5448	#37-5597	#38-5723	#39-5640	#40-5476
#41-5446	#42-5315	#43-5572	#44-5343	#45-5280	#46-5314	#47-5415	#48-5473	#49-5534	#50-5271
#51-5527	#52-5535	#53-5505	#54-5675	#55-5484	#56-5653	#57-5380	#58-5560	#59-5413	#60-5677
#61-5424	#62-5310	#63-5590	#64-5407	#65-5627	#66-5301	#67-5575	#68-5472	#69-5648	#70-5256
#71-5630	#72-5304	#73-5427	#74-5577	#75-5530	#76-5445	#77-5387	#78-5432	#79-5673	#80-5573
#81-5604	#82-5600	#83-5718	#84-5497	#85-5274	#86-5489	#87-5711	#88-5346	#89-5610	#90-5626
#91-5619	#92-5283	#93-5507	#94-5286	#95-5684	#96-5582	#97-5305	#98-5599	#99-5517	#100-5307

Type 6 #21 [Back to Summary]									
#01-5326	#02-5575	#03-5364	#04-5275	#05-5494	#06-5476	#07-5461	#08-5619	#09-5714	#10-5414
#11-5379	#12-5276	#13-5336	#14-5426	#15-5375	#16-5288	#17-5355	#18-5261	#19-5376	#20-5271
#21-5645	#22-5378	#23-5522	#24-5409	#25-5690	#26-5473	#27-5340	#28-5518	#29-5717	#30-5506
#31-5368	#32-5647	#33-5481	#34-5432	#35-5635	#36-5496	#37-5495	#38-5600	#39-5374	#40-5472
#41-5546	#42-5612	#43-5458	#44-5568	#45-5632	#46-5395	#47-5598	#48-5405	#49-5655	#50-5573
#51-5713	#52-5588	#53-5448	#54-5387	#55-5673	#56-5302	#57-5680	#58-5310	#59-5385	#60-5668
#61-5626	#62-5295	#63-5457	#64-5519	#65-5628	#66-5516	#67-5604	#68-5479	#69-5611	#70-5629
#71-5449	#72-5282	#73-5644	#74-5679	#75-5501	#76-5545	#77-5660	#78-5394	#79-5505	#80-5710
#81-5687	#82-5443	#83-5539	#84-5540	#85-5352	#86-5603	#87-5711	#88-5250	#89-5523	#90-5425
#91-5694	#92-5614	#93-5300	#94-5304	#95-5483	#96-5701	#97-5544	#98-5296	#99-5354	#100-5278

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 94 of 177

Type 6 #22 [Back to Summary]									
#01-5348	#02-5429	#03-5489	#04-5396	#05-5450	#06-5330	#07-5482	#08-5665	#09-5515	#10-5258
#11-5534	#12-5583	#13-5553	#14-5410	#15-5704	#16-5664	#17-5508	#18-5543	#19-5571	#20-5296
#21-5643	#22-5406	#23-5326	#24-5670	#25-5631	#26-5295	#27-5537	#28-5339	#29-5284	#30-5528
#31-5629	#32-5663	#33-5658	#34-5345	#35-5359	#36-5300	#37-5681	#38-5610	#39-5522	#40-5478
#41-5310	#42-5417	#43-5315	#44-5360	#45-5615	#46-5325	#47-5544	#48-5442	#49-5251	#50-5308
#51-5667	#52-5353	#53-5404	#54-5517	#55-5393	#56-5630	#57-5711	#58-5596	#59-5619	#60-5594
#61-5613	#62-5551	#63-5657	#64-5298	#65-5542	#66-5398	#67-5633	#68-5604	#69-5520	#70-5709
#71-5647	#72-5263	#73-5464	#74-5335	#75-5628	#76-5462	#77-5606	#78-5548	#79-5403	#80-5256
#81-5481	#82-5441	#83-5456	#84-5255	#85-5334	#86-5271	#87-5313	#88-5444	#89-5416	#90-5549
#91-5656	#92-5616	#93-5318	#94-5401	#95-5490	#96-5501	#97-5519	#98-5694	#99-5419	#100-5595

Type 6 #23 [Back to Summary]									
#01-5379	#02-5416	#03-5625	#04-5449	#05-5383	#06-5286	#07-5320	#08-5637	#09-5587	#10-5381
#11-5359	#12-5451	#13-5293	#14-5458	#15-5428	#16-5376	#17-5569	#18-5410	#19-5328	#20-5543
#21-5347	#22-5532	#23-5444	#24-5559	#25-5311	#26-5366	#27-5297	#28-5608	#29-5536	#30-5542
#31-5472	#32-5384	#33-5680	#34-5712	#35-5371	#36-5589	#37-5310	#38-5406	#39-5345	#40-5593
#41-5524	#42-5506	#43-5592	#44-5358	#45-5282	#46-5323	#47-5392	#48-5599	#49-5503	#50-5616
#51-5601	#52-5498	#53-5572	#54-5430	#55-5614	#56-5322	#57-5644	#58-5273	#59-5278	#60-5300
#61-5564	#62-5612	#63-5414	#64-5633	#65-5502	#66-5440	#67-5254	#68-5705	#69-5349	#70-5646
#71-5448	#72-5434	#73-5664	#74-5258	#75-5663	#76-5692	#77-5677	#78-5333	#79-5698	#80-5465
#81-5662	#82-5288	#83-5581	#84-5611	#85-5357	#86-5354	#87-5665	#88-5699	#89-5713	#90-5486
#91-5321	#92-5609	#93-5685	#94-5619	#95-5504	#96-5607	#97-5388	#98-5618	#99-5403	#100-5694

Type 6 #24 [Back to Summary]									
#01-5402	#02-5313	#03-5633	#04-5600	#05-5492	#06-5647	#07-5369	#08-5560	#09-5299	#10-5537
#11-5363	#12-5525	#13-5280	#14-5253	#15-5272	#16-5394	#17-5336	#18-5314	#19-5256	#20-5360
#21-5410	#22-5376	#23-5550	#24-5371	#25-5297	#26-5294	#27-5513	#28-5478	#29-5554	#30-5341
#31-5327	#32-5293	#33-5610	#34-5612	#35-5257	#36-5548	#37-5449	#38-5423	#39-5301	#40-5594
#41-5651	#42-5271	#43-5321	#44-5428	#45-5588	#46-5424	#47-5427	#48-5359	#49-5521	#50-5324
#51-5292	#52-5534	#53-5276	#54-5487	#55-5511	#56-5552	#57-5448	#58-5383	#59-5616	#60-5683
#61-5459	#62-5320	#63-5640	#64-5393	#65-5721	#66-5669	#67-5582	#68-5615	#69-5680	#70-5491
#71-5484	#72-5354	#73-5479	#74-5668	#75-5430	#76-5339	#77-5300	#78-5444	#79-5545	#80-5406
#81-5567	#82-5706	#83-5310	#84-5663	#85-5650	#86-5700	#87-5642	#88-5702	#89-5644	#90-5586
#91-5358	#92-5495	#93-5445	#94-5703	#95-5414	#96-5433	#97-5656	#98-5526	#99-5646	#100-5258

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 95 of 177

Type 6 #25 [Back to Summary]									
#01-5568	#02-5665	#03-5267	#04-5294	#05-5565	#06-5536	#07-5388	#08-5456	#09-5638	#10-5322
#11-5315	#12-5264	#13-5256	#14-5656	#15-5640	#16-5287	#17-5513	#18-5564	#19-5291	#20-5617
#21-5559	#22-5367	#23-5710	#24-5636	#25-5279	#26-5606	#27-5545	#28-5474	#29-5277	#30-5309
#31-5302	#32-5345	#33-5682	#34-5598	#35-5387	#36-5357	#37-5650	#38-5380	#39-5444	#40-5422
#41-5379	#42-5413	#43-5408	#44-5257	#45-5517	#46-5619	#47-5262	#48-5460	#49-5605	#50-5366
#51-5258	#52-5548	#53-5282	#54-5382	#55-5492	#56-5507	#57-5506	#58-5635	#59-5414	#60-5281
#61-5288	#62-5680	#63-5335	#64-5671	#65-5376	#66-5365	#67-5486	#68-5669	#69-5580	#70-5473
#71-5482	#72-5596	#73-5599	#74-5579	#75-5541	#76-5428	#77-5661	#78-5337	#79-5411	#80-5465
#81-5575	#82-5393	#83-5469	#84-5280	#85-5390	#86-5341	#87-5457	#88-5478	#89-5497	#90-5310
#91-5455	#92-5610	#93-5254	#94-5490	#95-5604	#96-5426	#97-5634	#98-5259	#99-5632	#100-5608

Type 6 #26 [Back to Summary]									
#01-5559	#02-5252	#03-5471	#04-5501	#05-5399	#06-5548	#07-5510	#08-5282	#09-5673	#10-5481
#11-5606	#12-5697	#13-5266	#14-5335	#15-5528	#16-5489	#17-5265	#18-5254	#19-5348	#20-5538
#21-5442	#22-5374	#23-5393	#24-5537	#25-5663	#26-5306	#27-5444	#28-5532	#29-5473	#30-5555
#31-5610	#32-5664	#33-5485	#34-5586	#35-5445	#36-5388	#37-5594	#38-5681	#39-5329	#40-5674
#41-5525	#42-5527	#43-5506	#44-5378	#45-5373	#46-5517	#47-5587	#48-5325	#49-5662	#50-5619
#51-5255	#52-5344	#53-5415	#54-5434	#55-5583	#56-5659	#57-5563	#58-5342	#59-5354	#60-5702
#61-5534	#62-5368	#63-5596	#64-5666	#65-5462	#66-5405	#67-5614	#68-5390	#69-5309	#70-5649
#71-5262	#72-5640	#73-5592	#74-5264	#75-5413	#76-5396	#77-5636	#78-5456	#79-5536	#80-5660
#81-5604	#82-5376	#83-5420	#84-5260	#85-5529	#86-5367	#87-5711	#88-5569	#89-5547	#90-5718
#91-5507	#92-5431	#93-5305	#94-5432	#95-5642	#96-5292	#97-5560	#98-5330	#99-5332	#100-5500

Type 6 #27 [Back to Summary]									
#01-5567	#02-5568	#03-5495	#04-5417	#05-5623	#06-5442	#07-5496	#08-5722	#09-5432	#10-5717
#11-5539	#12-5321	#13-5709	#14-5604	#15-5585	#16-5684	#17-5666	#18-5663	#19-5554	#20-5439
#21-5647	#22-5454	#23-5482	#24-5707	#25-5340	#26-5261	#27-5718	#28-5521	#29-5493	#30-5349
#31-5523	#32-5713	#33-5308	#34-5645	#35-5418	#36-5685	#37-5414	#38-5675	#39-5337	#40-5376
#41-5301	#42-5720	#43-5680	#44-5514	#45-5616	#46-5708	#47-5448	#48-5288	#49-5324	#50-5332
#51-5619	#52-5392	#53-5558	#54-5617	#55-5578	#56-5362	#57-5336	#58-5513	#59-5326	#60-5611
#61-5449	#62-5699	#63-5479	#64-5333	#65-5443	#66-5551	#67-5262	#68-5313	#69-5435	#70-5624
#71-5520	#72-5715	#73-5576	#74-5427	#75-5387	#76-5651	#77-5498	#78-5693	#79-5356	#80-5538
#81-5679	#82-5446	#83-5411	#84-5381	#85-5404	#86-5416	#87-5317	#88-5305	#89-5599	#90-5625
#91-5450	#92-5652	#93-5327	#94-5491	#95-5597	#96-5315	#97-5696	#98-5384	#99-5425	#100-5536

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 96 of 177

Type 6 #28 [Back to Summary]									
#01-5628	#02-5540	#03-5381	#04-5479	#05-5651	#06-5589	#07-5368	#08-5422	#09-5694	#10-5322
#11-5494	#12-5502	#13-5317	#14-5603	#15-5311	#16-5396	#17-5571	#18-5721	#19-5380	#20-5274
#21-5620	#22-5366	#23-5375	#24-5500	#25-5310	#26-5410	#27-5625	#28-5621	#29-5275	#30-5385
#31-5404	#32-5351	#33-5271	#34-5599	#35-5551	#36-5565	#37-5273	#38-5661	#39-5390	#40-5440
#41-5481	#42-5453	#43-5629	#44-5377	#45-5407	#46-5549	#47-5423	#48-5719	#49-5259	#50-5643
#51-5374	#52-5387	#53-5447	#54-5400	#55-5641	#56-5512	#57-5415	#58-5605	#59-5419	#60-5491
#61-5689	#62-5471	#63-5559	#64-5392	#65-5443	#66-5302	#67-5470	#68-5373	#69-5634	#70-5581
#71-5664	#72-5517	#73-5416	#74-5462	#75-5722	#76-5342	#77-5486	#78-5712	#79-5630	#80-5611
#81-5357	#82-5260	#83-5267	#84-5595	#85-5683	#86-5288	#87-5492	#88-5624	#89-5476	#90-5307
#91-5319	#92-5459	#93-5265	#94-5705	#95-5667	#96-5514	#97-5519	#98-5465	#99-5530	#100-5508

Type 6 #29 [Back to Summary]									
#01-5607	#02-5474	#03-5299	#04-5418	#05-5513	#06-5657	#07-5504	#08-5308	#09-5584	#10-5288
#11-5548	#12-5625	#13-5488	#14-5611	#15-5484	#16-5263	#17-5320	#18-5705	#19-5392	#20-5682
#21-5438	#22-5507	#23-5359	#24-5327	#25-5256	#26-5687	#27-5347	#28-5562	#29-5520	#30-5461
#31-5370	#32-5712	#33-5458	#34-5713	#35-5707	#36-5604	#37-5559	#38-5417	#39-5401	#40-5268
#41-5496	#42-5558	#43-5501	#44-5431	#45-5470	#46-5654	#47-5443	#48-5539	#49-5322	#50-5573
#51-5350	#52-5365	#53-5632	#54-5630	#55-5435	#56-5489	#57-5497	#58-5346	#59-5486	#60-5450
#61-5278	#62-5414	#63-5367	#64-5623	#65-5276	#66-5274	#67-5338	#68-5557	#69-5270	#70-5356
#71-5341	#72-5621	#73-5679	#74-5550	#75-5711	#76-5511	#77-5283	#78-5629	#79-5273	#80-5447
#81-5613	#82-5300	#83-5612	#84-5342	#85-5331	#86-5326	#87-5319	#88-5597	#89-5321	#90-5639
#91-5542	#92-5467	#93-5394	#94-5383	#95-5533	#96-5444	#97-5355	#98-5261	#99-5719	#100-5260

Type 6 #30 [Back to Summary]									
#01-5675	#02-5610	#03-5503	#04-5711	#05-5312	#06-5581	#07-5427	#08-5555	#09-5526	#10-5316
#11-5261	#12-5658	#13-5668	#14-5657	#15-5487	#16-5689	#17-5674	#18-5441	#19-5523	#20-5403
#21-5535	#22-5417	#23-5317	#24-5378	#25-5524	#26-5560	#27-5682	#28-5602	#29-5251	#30-5617
#31-5318	#32-5320	#33-5376	#34-5533	#35-5541	#36-5611	#37-5258	#38-5307	#39-5365	#40-5636
#41-5593	#42-5522	#43-5510	#44-5686	#45-5343	#46-5506	#47-5296	#48-5350	#49-5527	#50-5476
#51-5390	#52-5443	#53-5325	#54-5643	#55-5659	#56-5591	#57-5597	#58-5649	#59-5315	#60-5368
#61-5590	#62-5373	#63-5671	#64-5328	#65-5665	#66-5383	#67-5407	#68-5492	#69-5667	#70-5630
#71-5531	#72-5416	#73-5430	#74-5303	#75-5681	#76-5625	#77-5340	#78-5567	#79-5463	#80-5710
#81-5466	#82-5692	#83-5324	#84-5724	#85-5498	#86-5288	#87-5645	#88-5339	#89-5458	#90-5382
#91-5305	#92-5693	#93-5410	#94-5393	#95-5448	#96-5342	#97-5419	#98-5362	#99-5493	#100-5537

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 97 of 177

Type 5 #1 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	16	989809	77	1296	1453	507211	1500000
2	3	16	313584	95	1065	1414	1183652	1500000
3	3	16	1467665	97	1190	1980	28874	1500000
4	2	16	1358825	50	1530	0	139545	1500000
5	1	16	1338124	90	0	0	161786	1500000
6	1	16	253182	78	0	0	1246740	1500000
7	3	16	355489	57	1091	1458	1141791	1500000
8	3	16	1386759	82	1708	1017	110270	1500000

Type 5 #2 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	14	476550	75	0	0	229257	705882
2	3	14	119579	50	1207	1798	583148	705882
3	2	14	235982	70	1770	0	467990	705882
4	3	14	336655	62	1080	1054	366907	705882
5	3	14	697484	87	1924	1335	4878	705882
6	3	14	85573	55	1291	1449	617404	705882
7	1	14	239278	99	0	0	466505	705882
8	2	14	466876	52	1136	0	237766	705882
9	3	14	106873	53	1028	1247	596575	705882
10	1	14	422384	55	0	0	283443	705882
11	3	14	688553	53	1087	1330	14753	705882
12	2	14	492954	51	1027	0	211799	705882
13	2	14	312872	86	1901	0	390937	705882
14	3	14	645497	64	1488	1750	56955	705882
15	3	14	61444	91	1867	1675	640623	705882
16	3	14	600112	92	1781	1000	102713	705882
17	3	14	254863	52	1238	1633	447992	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 98 of 177

Type 5 #3 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	20	371079	67	1128	0	377659	750000
2	1	20	465657	97	0	0	284246	750000
3	2	20	347681	53	1299	0	400914	750000
4	1	20	203271	54	0	0	546675	750000
5	1	20	317119	72	0	0	432809	750000
6	3	20	744803	55	1225	1205	2602	750000
7	1	20	607257	80	0	0	142663	750000
8	1	20	246757	93	0	0	503150	750000
9	3	20	292022	55	1267	1590	454956	750000
10	1	20	564180	64	0	0	185756	750000
11	3	20	557512	58	1199	1280	189835	750000
12	3	20	8840	61	1265	1079	738633	750000
13	3	20	19662	64	1981	1931	726234	750000
14	2	20	74094	62	1192	0	674590	750000
15	3	20	436267	66	1136	1003	311396	750000
16	1	20	293843	56	0	0	456101	750000

Type 5 #4 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	189325	64	1889	1880	473380	666666
2	3	18	615215	88	1369	1979	47839	666666
3	3	18	365415	64	1745	1475	297839	666666
4	1	18	514665	72	0	0	151929	666666
5	3	18	595597	66	1645	1958	67268	666666
6	2	18	89683	63	1049	0	575808	666666
7	2	18	208669	67	1268	0	456595	666666
8	3	18	16820	91	1909	1560	646104	666666
9	3	18	609166	83	1402	1846	54003	666666
10	3	18	611136	85	1028	1357	52890	666666
11	2	18	217100	78	1234	0	448176	666666
12	3	18	526321	56	1097	1929	137151	666666
13	1	18	75479	97	0	0	591090	666666
14	1	18	353858	86	0	0	312722	666666
15	2	18	658601	50	1715	0	6250	666666
16	2	18	236304	55	1059	0	429193	666666
17	2	18	280578	93	1778	0	384124	666666
18	3	18	634530	90	1079	1196	29591	666666

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 99 of 177

Type 5 #5 5640 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	18	877066	96	0	0	213747	1090909
2	3	18	996015	99	1772	1827	90998	1090909
3	3	18	976668	61	1245	1077	111736	1090909
4	2	18	15078	87	1568	0	1074089	1090909
5	2	18	181252	76	1742	0	907763	1090909
6	2	18	363673	89	1577	0	725481	1090909
7	2	18	224206	53	1123	0	865474	1090909
8	3	18	1034503	95	1683	1393	53045	1090909
9	1	18	612209	75	0	0	478625	1090909
10	3	18	1009584	56	1277	1057	78823	1090909
11	2	18	428933	69	1852	0	659986	1090909

Type 5 #6 5646 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	186122	75	0	0	736879	923076
2	1	5	5355	56	0	0	917665	923076
3	1	5	161513	76	0	0	761487	923076
4	3	5	698865	53	1225	1009	221818	923076
5	1	5	480355	70	0	0	442651	923076
6	3	5	731205	70	1089	1683	188889	923076
7	3	5	72929	54	1416	1177	847392	923076
8	3	5	654761	90	1925	1713	264407	923076
9	2	5	797782	63	1860	0	123308	923076
10	2	5	354088	80	1788	0	567040	923076
11	3	5	674060	87	1172	1034	246549	923076
12	2	5	785473	58	1111	0	136376	923076
13	3	5	206104	59	1117	1111	714567	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 100 of 177

Type 5 #7 5645 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	879929	81	1946	0	451296	1333333
2	2	6	644262	77	1736	0	687181	1333333
3	2	6	5373	71	1290	0	1326528	1333333
4	3	6	800182	78	1969	1280	529668	1333333
5	3	6	475470	93	1598	1077	854909	1333333
6	3	6	397594	56	1880	1424	932267	1333333
7	3	6	94028	68	1551	1088	1236462	1333333
8	3	6	627559	82	1376	1392	702760	1333333
9	3	6	194143	92	1422	1881	1135611	1333333

Type 5 #8 5497 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	480697	67	1143	1919	373182	857142
2	2	12	111299	60	1059	0	744664	857142
3	2	12	238658	66	1453	0	616899	857142
4	3	12	422381	64	1118	1224	432227	857142
5	1	12	802732	65	0	0	54345	857142
6	1	12	25019	92	0	0	832031	857142
7	3	12	633683	99	1160	1918	220084	857142
8	1	12	59672	57	0	0	797413	857142
9	3	12	181928	59	1308	1044	672685	857142
10	1	12	744793	71	0	0	112278	857142
11	2	12	793823	94	1217	0	61914	857142
12	1	12	4204	61	0	0	852877	857142
13	1	12	409640	73	0	0	447429	857142
14	1	12	390519	81	0	0	466542	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 101 of 177

Type 5 #9 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	247152	52	1453	0	1084624	1333333
2	1	16	1115199	84	0	0	218050	1333333
3	3	16	993303	67	1866	1532	336431	1333333
4	3	16	195577	100	1523	1519	1134414	1333333
5	2	16	370354	80	1992	0	960827	1333333
6	2	16	1020401	73	1758	0	311028	1333333
7	2	16	224550	87	1751	0	1106858	1333333
8	3	16	404212	79	1082	1140	926662	1333333
9	2	16	663963	90	1435	0	667755	1333333

Type 5 #10 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	7	407318	91	1600	0	513976	923076
2	2	7	191943	82	1908	0	729061	923076
3	3	7	719072	57	1908	1954	199971	923076
4	2	7	407014	79	1032	0	514872	923076
5	2	7	754622	58	1844	0	166494	923076
6	2	7	44282	54	1780	0	876906	923076
7	1	7	761077	64	0	0	161935	923076
8	3	7	874559	57	1570	1727	45049	923076
9	1	7	332480	74	0	0	590522	923076
10	1	7	444800	94	0	0	478182	923076
11	3	7	642872	57	1844	1552	276637	923076
12	1	7	578418	83	0	0	344575	923076
13	2	7	827802	96	1543	0	93539	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 102 of 177

Type 5 #11 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	7	929067	82	0	0	161760	1090909
2	2	7	235836	73	1266	0	853661	1090909
3	2	7	667338	99	1936	0	421437	1090909
4	1	7	677496	81	0	0	413332	1090909
5	1	7	292221	97	0	0	798591	1090909
6	2	7	444034	98	1104	0	645575	1090909
7	1	7	642434	80	0	0	448395	1090909
8	2	7	94169	80	1351	0	995229	1090909
9	1	7	605301	100	0	0	485508	1090909
10	2	7	712663	65	1437	0	376679	1090909
11	3	7	1040403	92	1931	1064	47235	1090909

Type 5 #12 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	161082	50	0	0	696010	857142
2	1	20	369235	61	0	0	487846	857142
3	3	20	835536	80	1335	1723	18308	857142
4	2	20	424807	60	1726	0	430489	857142
5	2	20	357549	92	1123	0	498286	857142
6	2	20	711165	74	1983	0	143846	857142
7	2	20	283319	90	1248	0	572395	857142
8	3	20	182107	58	1247	1708	671906	857142
9	3	20	93127	50	1376	1064	761425	857142
10	2	20	364718	54	1859	0	490457	857142
11	3	20	620165	93	1161	1111	234426	857142
12	1	20	203177	78	0	0	653887	857142
13	3	20	743062	80	1459	1802	110579	857142
14	1	20	827649	56	0	0	29437	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 103 of 177

Type 5 #13 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	18	894602	61	1065	1529	102621	1000000
2	2	18	390791	54	1011	0	608090	1000000
3	3	18	157312	61	1740	1445	839320	1000000
4	3	18	261999	99	1998	1407	734299	1000000
5	1	18	963169	62	0	0	36769	1000000
6	2	18	574709	89	1407	0	423706	1000000
7	3	18	20881	64	1364	1499	976064	1000000
8	3	18	894622	67	1553	1513	102111	1000000
9	3	18	45839	59	1791	1385	950808	1000000
10	3	18	829370	64	1306	1342	167790	1000000
11	3	18	843001	90	1289	1306	154134	1000000
12	1	18	816766	80	0	0	183154	1000000

Type 5 #14 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	267104	62	0	0	332834	600000
2	3	15	471865	73	1366	1569	124981	600000
3	2	15	237455	90	1734	0	360631	600000
4	1	15	321112	74	0	0	278814	600000
5	2	15	244321	73	1732	0	353801	600000
6	3	15	183718	60	1844	1663	412595	600000
7	3	15	17091	50	1867	1391	579501	600000
8	3	15	138302	95	1522	1361	458530	600000
9	1	15	33180	76	0	0	566744	600000
10	2	15	234413	52	1838	0	363645	600000
11	1	15	114556	92	0	0	485352	600000
12	2	15	412839	94	1227	0	185746	600000
13	2	15	557541	85	1688	0	40601	600000
14	2	15	220567	97	1342	0	377897	600000
15	2	15	562142	79	1350	0	36350	600000
16	1	15	30060	75	0	0	569865	600000
17	2	15	199685	82	1788	0	398363	600000
18	3	15	190718	90	1167	1455	406390	600000
19	1	15	501364	72	0	0	98564	600000
20	3	15	473422	95	1543	1472	123278	600000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 104 of 177

Type 5 #15 5500 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	771027	86	1670	1474	82713	857142
2	1	20	46387	59	0	0	810696	857142
3	3	20	340815	94	1355	1839	512851	857142
4	2	20	130543	57	1504	0	724981	857142
5	2	20	590949	76	1435	0	264606	857142
6	1	20	447324	63	0	0	409755	857142
7	2	20	90762	78	1355	0	764869	857142
8	1	20	208990	75	0	0	648077	857142
9	2	20	668370	57	1266	0	187392	857142
10	3	20	335907	50	1187	1634	518264	857142
11	2	20	684305	54	1730	0	170999	857142
12	2	20	229515	59	1235	0	626274	857142
13	3	20	242890	87	1919	1559	610513	857142
14	2	20	771742	99	1733	0	83469	857142

Type 5 #16 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	41428	87	0	0	1458485	1500000
2	2	19	1281981	70	1814	0	216065	1500000
3	1	19	874660	92	0	0	625248	1500000
4	3	19	822082	95	1262	1551	674820	1500000
5	2	19	922101	67	1525	0	576240	1500000
6	2	19	736622	60	1901	0	761357	1500000
7	1	19	311035	59	0	0	1188906	1500000
8	3	19	1147015	53	1456	1699	349671	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 105 of 177

Type 5 #17 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	96878	71	1391	0	607471	705882
2	2	10	449159	97	1923	0	254606	705882
3	2	10	377551	91	1607	0	326542	705882
4	1	10	265055	75	0	0	440752	705882
5	3	10	458778	56	1181	1886	243869	705882
6	2	10	54729	78	1148	0	649849	705882
7	2	10	109378	65	1821	0	594553	705882
8	1	10	201949	91	0	0	503842	705882
9	3	10	264390	62	1268	1104	438934	705882
10	1	10	614204	93	0	0	91585	705882
11	2	10	21826	99	1529	0	682329	705882
12	1	10	510216	64	0	0	195602	705882
13	2	10	503578	85	1074	0	201060	705882
14	2	10	575063	57	1243	0	129462	705882
15	3	10	367469	74	1465	1618	335108	705882
16	2	10	207915	93	1076	0	496705	705882
17	2	10	516322	80	1788	0	187612	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 106 of 177

Type 5 #18 5642 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	517774	76	1102	1511	146051	666666
2	2	14	87940	78	1644	0	576926	666666
3	1	14	264336	51	0	0	402279	666666
4	1	14	104069	68	0	0	562529	666666
5	2	14	284466	68	1202	0	380862	666666
6	3	14	237093	55	1287	1506	426615	666666
7	1	14	155884	81	0	0	510701	666666
8	3	14	495128	98	1363	1107	168774	666666
9	3	14	88575	65	1432	1884	574580	666666
10	2	14	499200	89	1885	0	165403	666666
11	2	14	449198	73	1185	0	216137	666666
12	1	14	327029	84	0	0	339553	666666
13	2	14	175471	98	1574	0	489425	666666
14	2	14	294282	53	1803	0	370475	666666
15	2	14	426101	62	1908	0	238533	666666
16	1	14	176484	89	0	0	490093	666666
17	3	14	403374	77	1510	1621	259930	666666
18	2	14	144183	58	1013	0	521354	666666

Type 5 #19 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	9	930685	87	0	0	569228	1500000
2	2	9	663450	53	1755	0	834689	1500000
3	1	9	74275	75	0	0	1425650	1500000
4	2	9	616459	58	1904	0	881521	1500000
5	3	9	1020064	98	1981	1334	476327	1500000
6	2	9	1356524	67	1053	0	142289	1500000
7	3	9	944311	99	1680	1882	551830	1500000
8	1	9	912288	81	0	0	587631	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 107 of 177

Type 5 #20 5644 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	8	562402	100	0	0	637498	1200000
2	3	8	95950	65	1722	1276	1100857	1200000
3	1	8	556290	84	0	0	643626	1200000
4	3	8	797568	66	1012	1963	399259	1200000
5	1	8	1070612	91	0	0	129297	1200000
6	3	8	1116544	92	1278	1217	80685	1200000
7	1	8	143520	56	0	0	1056424	1200000
8	2	8	1143668	83	1225	0	54941	1200000
9	2	8	962396	52	1687	0	235813	1200000
10	3	8	349550	98	1914	1163	847079	1200000

Type 5 #21 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	475392	61	0	0	381689	857142
2	3	6	790200	51	1504	1473	63812	857142
3	1	6	761887	76	0	0	95179	857142
4	1	6	7939	54	0	0	849149	857142
5	1	6	5235	81	0	0	851826	857142
6	3	6	401391	50	1959	1927	451715	857142
7	2	6	550221	58	1330	0	305475	857142
8	1	6	664	64	0	0	856414	857142
9	1	6	473000	98	0	0	384044	857142
10	1	6	635186	94	0	0	221862	857142
11	2	6	172450	81	1275	0	683255	857142
12	1	6	775831	91	0	0	81220	857142
13	3	6	61816	64	1269	1219	792646	857142
14	3	6	103781	51	1962	1762	749484	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 108 of 177

Type 5 #22 5645 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	129507	52	1604	0	500363	631578
2	1	6	329565	53	0	0	301960	631578
3	1	6	196456	92	0	0	435030	631578
4	3	6	7862	76	1084	1739	620665	631578
5	1	6	557883	89	0	0	73606	631578
6	2	6	180487	76	1252	0	449687	631578
7	2	6	345247	78	1356	0	284819	631578
8	1	6	212935	97	0	0	418546	631578
9	3	6	47228	73	1153	1192	581786	631578
10	3	6	50322	54	1994	1651	577449	631578
11	1	6	370049	57	0	0	261472	631578
12	3	6	342113	65	1960	1174	286136	631578
13	3	6	599731	50	1791	1648	28258	631578
14	1	6	573041	75	0	0	58462	631578
15	3	6	612718	88	1896	1900	14800	631578
16	3	6	379325	68	1117	1557	249375	631578
17	1	6	268026	60	0	0	363492	631578
18	2	6	616208	54	1830	0	13432	631578
19	2	6	93308	68	1301	0	536833	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 109 of 177

Type 5 #23 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	192688	73	1014	0	472818	666666
2	1	19	496754	100	0	0	169812	666666
3	2	19	13489	80	1056	0	651961	666666
4	2	19	357362	91	1585	0	307537	666666
5	2	19	619540	53	1664	0	45356	666666
6	1	19	260171	69	0	0	406426	666666
7	3	19	423859	79	1521	1246	239803	666666
8	1	19	585878	57	0	0	80731	666666
9	1	19	246783	59	0	0	419824	666666
10	1	19	354486	66	0	0	312114	666666
11	3	19	159680	64	1159	1342	504293	666666
12	2	19	36960	66	1853	0	627721	666666
13	1	19	433182	58	0	0	233426	666666
14	2	19	235318	50	1171	0	430077	666666
15	3	19	470311	89	1998	1200	192890	666666
16	3	19	49089	68	1038	1697	614638	666666
17	2	19	153057	82	1421	0	512024	666666
18	2	19	659335	88	1281	0	5874	666666

Type 5 #24 5641 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	1219045	77	1847	0	112287	1333333
2	2	16	377394	51	1779	0	954058	1333333
3	3	16	369780	86	1109	1465	960721	1333333
4	1	16	710034	63	0	0	623236	1333333
5	2	16	858327	74	1334	0	473524	1333333
6	2	16	1318005	84	1685	0	13475	1333333
7	3	16	1094619	55	1520	1996	235033	1333333
8	1	16	949352	67	0	0	383914	1333333
9	2	16	360526	93	1236	0	971385	1333333

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 110 of 177

Type 5 #25 5641 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	166645	97	1113	0	755124	923076
2	3	16	630486	60	1466	1712	289232	923076
3	2	16	788172	50	1196	0	133608	923076
4	1	16	370008	55	0	0	553013	923076
5	1	16	250104	91	0	0	672881	923076
6	1	16	281040	84	0	0	641952	923076
7	1	16	797403	100	0	0	125573	923076
8	1	16	814401	52	0	0	108623	923076
9	3	16	669215	98	1815	1498	250254	923076
10	2	16	773549	58	1026	0	148385	923076
11	1	16	413880	78	0	0	509118	923076
12	2	16	752551	87	1044	0	169307	923076
13	2	16	591381	92	1566	0	329945	923076

Type 5 #26 5640 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	18	418702	99	0	0	287081	705882
2	3	18	252774	62	1300	1575	450047	705882
3	1	18	576319	71	0	0	129492	705882
4	3	18	169970	60	1747	1694	532291	705882
5	1	18	385108	59	0	0	320715	705882
6	2	18	605221	57	1385	0	99162	705882
7	3	18	62164	68	1913	1440	640161	705882
8	3	18	162033	60	1966	1555	540148	705882
9	1	18	445390	63	0	0	260429	705882
10	3	18	104267	80	1751	1663	597961	705882
11	2	18	639000	58	1484	0	65282	705882
12	2	18	610840	64	1045	0	93869	705882
13	3	18	696298	86	1047	1988	6291	705882
14	1	18	7286	87	0	0	698509	705882
15	3	18	653826	57	1350	1011	49524	705882
16	1	18	389361	96	0	0	316425	705882
17	2	18	500139	83	1430	0	204147	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 111 of 177

Type 5 #27 5644 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	539093	96	1844	1333	657442	1200000
2	1	10	1101547	64	0	0	98389	1200000
3	2	10	441047	51	1697	0	757154	1200000
4	2	10	1173819	91	1473	0	24526	1200000
5	2	10	275487	69	1406	0	922969	1200000
6	2	10	636209	64	1467	0	562196	1200000
7	1	10	756941	77	0	0	442982	1200000
8	1	10	20210	93	0	0	1179697	1200000
9	3	10	865658	75	1707	1881	330529	1200000
10	3	10	220767	81	1953	1012	976025	1200000

Type 5 #28 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	20	1083561	76	1682	0	114605	1200000
2	1	20	993717	88	0	0	206195	1200000
3	3	20	608038	51	1480	1066	589263	1200000
4	1	20	297547	90	0	0	902363	1200000
5	1	20	821190	75	0	0	378735	1200000
6	1	20	330639	81	0	0	869280	1200000
7	1	20	663219	54	0	0	536727	1200000
8	3	20	734482	67	1673	1568	462076	1200000
9	3	20	875658	94	1340	1954	320766	1200000
10	3	20	845974	99	1131	1887	350711	1200000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 112 of 177

Type 5 #29 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	415486	86	1831	0	439653	857142
2	2	19	187721	95	1500	0	667731	857142
3	1	19	338141	62	0	0	518939	857142
4	3	19	776488	58	1616	1890	76974	857142
5	1	19	723903	81	0	0	133158	857142
6	1	19	498341	74	0	0	358727	857142
7	2	19	239608	57	1489	0	615931	857142
8	2	19	87981	60	1856	0	767185	857142
9	2	19	836203	67	1452	0	19353	857142
10	2	19	421888	75	1729	0	433375	857142
11	3	19	511173	77	1338	1229	343171	857142
12	2	19	262781	92	1623	0	592554	857142
13	3	19	624883	50	1307	1953	228849	857142
14	2	19	766274	98	1737	0	88935	857142

Type 5 #30 5570 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	12	425589	82	1578	1335	428394	857142
2	1	12	688044	82	0	0	169016	857142
3	1	12	677501	92	0	0	179549	857142
4	2	12	369084	61	1528	0	486408	857142
5	1	12	181435	57	0	0	675650	857142
6	3	12	42748	98	1769	1252	811079	857142
7	3	12	641865	92	1769	1447	211785	857142
8	1	12	713593	52	0	0	143497	857142
9	2	12	825213	50	1671	0	30158	857142
10	2	12	692765	86	1277	0	162928	857142
11	2	12	137787	55	1718	0	717527	857142
12	1	12	683697	68	0	0	173377	857142
13	2	12	502176	86	1245	0	353549	857142
14	1	12	333290	99	0	0	523753	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 113 of 177

Type 6 #1 [Back to Summary]

#01-5286	#02-5395	#03-5589	#04-5340	#05-5692	#06-5565	#07-5612	#08-5288	#09-5558	#10-5721
#11-5398	#12-5673	#13-5599	#14-5593	#15-5655	#16-5616	#17-5511	#18-5303	#19-5719	#20-5331
#21-5313	#22-5557	#23-5315	#24-5381	#25-5400	#26-5697	#27-5440	#28-5332	#29-5667	#30-5482
#31-5600	#32-5518	#33-5327	#34-5366	#35-5700	#36-5598	#37-5687	#38-5383	#39-5678	#40-5432
#41-5561	#42-5714	#43-5306	#44-5415	#45-5268	#46-5698	#47-5378	#48-5330	#49-5396	#50-5346
#51-5441	#52-5424	#53-5453	#54-5457	#55-5664	#56-5720	#57-5375	#58-5530	#59-5325	#60-5370
#61-5604	#62-5596	#63-5483	#64-5617	#65-5307	#66-5653	#67-5350	#68-5536	#69-5495	#70-5323
#71-5723	#72-5258	#73-5300	#74-5710	#75-5467	#76-5679	#77-5587	#78-5336	#79-5504	#80-5494
#81-5666	#82-5496	#83-5517	#84-5479	#85-5443	#86-5682	#87-5281	#88-5618	#89-5661	#90-5451
#91-5543	#92-5510	#93-5320	#94-5401	#95-5629	#96-5455	#97-5322	#98-5407	#99-5291	#100-5633

Type 6 #2 [Back to Summary]

#01-5576	#02-5483	#03-5714	#04-5590	#05-5526	#06-5352	#07-5541	#08-5371	#09-5514	#10-5424
#11-5659	#12-5392	#13-5479	#14-5463	#15-5430	#16-5490	#17-5322	#18-5573	#19-5416	#20-5417
#21-5386	#22-5608	#23-5436	#24-5317	#25-5509	#26-5423	#27-5565	#28-5291	#29-5445	#30-5488
#31-5641	#32-5399	#33-5384	#34-5492	#35-5320	#36-5649	#37-5441	#38-5694	#39-5683	#40-5531
#41-5701	#42-5333	#43-5578	#44-5400	#45-5574	#46-5645	#47-5689	#48-5724	#49-5558	#50-5512
#51-5598	#52-5496	#53-5692	#54-5297	#55-5647	#56-5331	#57-5353	#58-5646	#59-5329	#60-5319
#61-5421	#62-5476	#63-5283	#64-5296	#65-5722	#66-5252	#67-5699	#68-5448	#69-5428	#70-5327
#71-5459	#72-5708	#73-5655	#74-5273	#75-5581	#76-5700	#77-5292	#78-5628	#79-5462	#80-5337
#81-5570	#82-5546	#83-5520	#84-5718	#85-5604	#86-5461	#87-5599	#88-5637	#89-5540	#90-5691
#91-5634	#92-5537	#93-5318	#94-5615	#95-5562	#96-5664	#97-5315	#98-5305	#99-5588	#100-5433

Type 6 #3 [Back to Summary]

#01-5426	#02-5546	#03-5683	#04-5402	#05-5262	#06-5352	#07-5429	#08-5455	#09-5548	#10-5590
#11-5584	#12-5320	#13-5553	#14-5678	#15-5290	#16-5296	#17-5361	#18-5448	#19-5579	#20-5413
#21-5616	#22-5560	#23-5571	#24-5500	#25-5630	#26-5564	#27-5467	#28-5454	#29-5662	#30-5601
#31-5587	#32-5261	#33-5442	#34-5643	#35-5618	#36-5719	#37-5640	#38-5538	#39-5709	#40-5531
#41-5357	#42-5670	#43-5494	#44-5275	#45-5702	#46-5593	#47-5376	#48-5274	#49-5259	#50-5400
#51-5258	#52-5282	#53-5542	#54-5591	#55-5700	#56-5433	#57-5496	#58-5423	#59-5610	#60-5699
#61-5518	#62-5672	#63-5252	#64-5573	#65-5602	#66-5635	#67-5309	#68-5381	#69-5547	#70-5463
#71-5298	#72-5305	#73-5671	#74-5315	#75-5545	#76-5522	#77-5286	#78-5717	#79-5341	#80-5430
#81-5652	#82-5710	#83-5436	#84-5253	#85-5410	#86-5351	#87-5277	#88-5268	#89-5456	#90-5291
#91-5536	#92-5646	#93-5382	#94-5401	#95-5272	#96-5379	#97-5716	#98-5660	#99-5316	#100-5603

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 114 of 177

Type 6 #4 [Back to Summary]									
#01-5318	#02-5662	#03-5684	#04-5702	#05-5595	#06-5525	#07-5404	#08-5636	#09-5459	#10-5431
#11-5519	#12-5590	#13-5686	#14-5541	#15-5570	#16-5442	#17-5534	#18-5282	#19-5278	#20-5649
#21-5505	#22-5652	#23-5377	#24-5647	#25-5493	#26-5523	#27-5393	#28-5295	#29-5306	#30-5274
#31-5452	#32-5299	#33-5641	#34-5499	#35-5293	#36-5433	#37-5480	#38-5476	#39-5589	#40-5545
#41-5557	#42-5354	#43-5376	#44-5588	#45-5536	#46-5585	#47-5456	#48-5284	#49-5674	#50-5678
#51-5538	#52-5260	#53-5305	#54-5325	#55-5281	#56-5605	#57-5492	#58-5414	#59-5374	#60-5494
#61-5316	#62-5540	#63-5291	#64-5526	#65-5259	#66-5303	#67-5530	#68-5673	#69-5547	#70-5250
#71-5308	#72-5708	#73-5633	#74-5317	#75-5584	#76-5497	#77-5655	#78-5715	#79-5503	#80-5346
#81-5353	#82-5489	#83-5460	#84-5378	#85-5405	#86-5445	#87-5302	#88-5392	#89-5705	#90-5606
#91-5521	#92-5720	#93-5257	#94-5514	#95-5323	#96-5479	#97-5510	#98-5573	#99-5437	#100-5721

Type 6 #5 [Back to Summary]									
#01-5342	#02-5373	#03-5538	#04-5633	#05-5641	#06-5444	#07-5504	#08-5666	#09-5527	#10-5315
#11-5605	#12-5623	#13-5334	#14-5430	#15-5302	#16-5530	#17-5566	#18-5368	#19-5512	#20-5712
#21-5343	#22-5627	#23-5577	#24-5707	#25-5581	#26-5485	#27-5717	#28-5497	#29-5488	#30-5301
#31-5628	#32-5381	#33-5313	#34-5321	#35-5419	#36-5394	#37-5475	#38-5511	#39-5351	#40-5525
#41-5598	#42-5612	#43-5425	#44-5329	#45-5521	#46-5309	#47-5595	#48-5438	#49-5459	#50-5354
#51-5280	#52-5636	#53-5306	#54-5659	#55-5587	#56-5269	#57-5546	#58-5672	#59-5428	#60-5412
#61-5474	#62-5559	#63-5262	#64-5261	#65-5632	#66-5304	#67-5305	#68-5267	#69-5529	#70-5436
#71-5469	#72-5264	#73-5635	#74-5324	#75-5406	#76-5341	#77-5637	#78-5700	#79-5431	#80-5439
#81-5647	#82-5683	#83-5291	#84-5508	#85-5337	#86-5541	#87-5648	#88-5332	#89-5411	#90-5578
#91-5420	#92-5387	#93-5503	#94-5409	#95-5590	#96-5317	#97-5613	#98-5254	#99-5540	#100-5421

Type 6 #6 [Back to Summary]									
#01-5654	#02-5642	#03-5535	#04-5621	#05-5395	#06-5585	#07-5430	#08-5652	#09-5633	#10-5697
#11-5724	#12-5294	#13-5551	#14-5601	#15-5696	#16-5478	#17-5544	#18-5487	#19-5382	#20-5659
#21-5368	#22-5583	#23-5299	#24-5602	#25-5381	#26-5639	#27-5541	#28-5685	#29-5569	#30-5336
#31-5423	#32-5615	#33-5268	#34-5718	#35-5290	#36-5481	#37-5612	#38-5667	#39-5681	#40-5467
#41-5405	#42-5502	#43-5605	#44-5420	#45-5343	#46-5531	#47-5713	#48-5410	#49-5564	#50-5319
#51-5491	#52-5407	#53-5486	#54-5536	#55-5308	#56-5263	#57-5670	#58-5613	#59-5692	#60-5313
#61-5610	#62-5550	#63-5403	#64-5679	#65-5558	#66-5560	#67-5465	#68-5591	#69-5504	#70-5590
#71-5702	#72-5604	#73-5509	#74-5575	#75-5306	#76-5553	#77-5525	#78-5255	#79-5267	#80-5656
#81-5458	#82-5506	#83-5431	#84-5706	#85-5720	#86-5593	#87-5653	#88-5260	#89-5579	#90-5438
#91-5439	#92-5594	#93-5665	#94-5577	#95-5274	#96-5402	#97-5698	#98-5441	#99-5493	#100-5707

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 115 of 177

Type 6 #7 [Back to Summary]									
#01-5671	#02-5331	#03-5607	#04-5484	#05-5413	#06-5614	#07-5310	#08-5416	#09-5308	#10-5593
#11-5618	#12-5670	#13-5422	#14-5376	#15-5579	#16-5470	#17-5722	#18-5674	#19-5520	#20-5316
#21-5400	#22-5707	#23-5259	#24-5568	#25-5723	#26-5281	#27-5580	#28-5550	#29-5696	#30-5689
#31-5523	#32-5485	#33-5625	#34-5362	#35-5358	#36-5490	#37-5371	#38-5518	#39-5271	#40-5381
#41-5700	#42-5720	#43-5404	#44-5623	#45-5548	#46-5450	#47-5492	#48-5414	#49-5433	#50-5641
#51-5348	#52-5597	#53-5640	#54-5582	#55-5635	#56-5561	#57-5276	#58-5292	#59-5647	#60-5705
#61-5616	#62-5678	#63-5357	#64-5613	#65-5434	#66-5399	#67-5516	#68-5295	#69-5269	#70-5581
#71-5283	#72-5573	#73-5569	#74-5383	#75-5576	#76-5380	#77-5305	#78-5532	#79-5505	#80-5690
#81-5527	#82-5442	#83-5325	#84-5514	#85-5354	#86-5333	#87-5303	#88-5264	#89-5256	#90-5595
#91-5342	#92-5337	#93-5596	#94-5501	#95-5491	#96-5564	#97-5317	#98-5570	#99-5448	#100-5309

Type 6 #8 [Back to Summary]									
#01-5431	#02-5695	#03-5709	#04-5365	#05-5449	#06-5266	#07-5651	#08-5401	#09-5591	#10-5420
#11-5358	#12-5610	#13-5634	#14-5585	#15-5639	#16-5497	#17-5704	#18-5559	#19-5313	#20-5376
#21-5706	#22-5287	#23-5693	#24-5250	#25-5517	#26-5589	#27-5260	#28-5439	#29-5285	#30-5375
#31-5479	#32-5315	#33-5548	#34-5252	#35-5384	#36-5349	#37-5663	#38-5539	#39-5489	#40-5330
#41-5444	#42-5476	#43-5641	#44-5674	#45-5379	#46-5257	#47-5586	#48-5719	#49-5584	#50-5482
#51-5507	#52-5322	#53-5327	#54-5394	#55-5708	#56-5572	#57-5255	#58-5462	#59-5665	#60-5295
#61-5604	#62-5544	#63-5336	#64-5582	#65-5505	#66-5398	#67-5291	#68-5269	#69-5512	#70-5535
#71-5302	#72-5301	#73-5387	#74-5724	#75-5577	#76-5317	#77-5618	#78-5697	#79-5718	#80-5470
#81-5583	#82-5381	#83-5340	#84-5679	#85-5483	#86-5593	#87-5328	#88-5595	#89-5319	#90-5645
#91-5403	#92-5571	#93-5542	#94-5463	#95-5683	#96-5276	#97-5540	#98-5657	#99-5435	#100-5253

Type 6 #9 [Back to Summary]									
#01-5256	#02-5609	#03-5324	#04-5598	#05-5401	#06-5631	#07-5551	#08-5590	#09-5724	#10-5373
#11-5282	#12-5675	#13-5315	#14-5427	#15-5434	#16-5431	#17-5706	#18-5552	#19-5661	#20-5571
#21-5496	#22-5444	#23-5499	#24-5405	#25-5264	#26-5691	#27-5655	#28-5432	#29-5433	#30-5629
#31-5477	#32-5709	#33-5253	#34-5662	#35-5413	#36-5257	#37-5305	#38-5403	#39-5682	#40-5538
#41-5591	#42-5397	#43-5617	#44-5573	#45-5356	#46-5583	#47-5493	#48-5607	#49-5317	#50-5409
#51-5363	#52-5604	#53-5348	#54-5721	#55-5585	#56-5660	#57-5250	#58-5666	#59-5574	#60-5296
#61-5364	#62-5563	#63-5443	#64-5430	#65-5312	#66-5712	#67-5543	#68-5544	#69-5605	#70-5418
#71-5539	#72-5632	#73-5371	#74-5367	#75-5548	#76-5390	#77-5664	#78-5482	#79-5272	#80-5608
#81-5596	#82-5447	#83-5520	#84-5370	#85-5265	#86-5689	#87-5545	#88-5304	#89-5380	#90-5650
#91-5521	#92-5505	#93-5382	#94-5436	#95-5716	#96-5698	#97-5441	#98-5714	#99-5467	#100-5361

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 116 of 177

Type 6 #10 [Back to Summary]									
#01-5584	#02-5252	#03-5342	#04-5273	#05-5481	#06-5495	#07-5572	#08-5306	#09-5473	#10-5515
#11-5272	#12-5397	#13-5485	#14-5264	#15-5523	#16-5667	#17-5336	#18-5700	#19-5316	#20-5712
#21-5623	#22-5594	#23-5408	#24-5349	#25-5684	#26-5422	#27-5325	#28-5297	#29-5400	#30-5372
#31-5458	#32-5274	#33-5655	#34-5258	#35-5544	#36-5263	#37-5596	#38-5521	#39-5526	#40-5533
#41-5593	#42-5298	#43-5715	#44-5359	#45-5640	#46-5676	#47-5702	#48-5275	#49-5281	#50-5354
#51-5429	#52-5479	#53-5463	#54-5569	#55-5717	#56-5314	#57-5309	#58-5420	#59-5525	#60-5631
#61-5350	#62-5307	#63-5723	#64-5466	#65-5476	#66-5445	#67-5510	#68-5320	#69-5540	#70-5423
#71-5508	#72-5428	#73-5279	#74-5545	#75-5418	#76-5714	#77-5293	#78-5470	#79-5348	#80-5271
#81-5369	#82-5268	#83-5444	#84-5425	#85-5520	#86-5554	#87-5419	#88-5603	#89-5457	#90-5467
#91-5363	#92-5687	#93-5672	#94-5657	#95-5361	#96-5424	#97-5449	#98-5506	#99-5490	#100-5685

Type 6 #11 [Back to Summary]									
#01-5539	#02-5565	#03-5646	#04-5301	#05-5433	#06-5419	#07-5400	#08-5253	#09-5270	#10-5563
#11-5322	#12-5503	#13-5512	#14-5332	#15-5588	#16-5403	#17-5290	#18-5680	#19-5616	#20-5340
#21-5442	#22-5681	#23-5395	#24-5420	#25-5316	#26-5598	#27-5485	#28-5602	#29-5594	#30-5271
#31-5566	#32-5506	#33-5408	#34-5454	#35-5603	#36-5648	#37-5374	#38-5336	#39-5385	#40-5268
#41-5600	#42-5436	#43-5629	#44-5291	#45-5480	#46-5425	#47-5590	#48-5319	#49-5683	#50-5383
#51-5494	#52-5615	#53-5399	#54-5493	#55-5456	#56-5608	#57-5501	#58-5605	#59-5367	#60-5545
#61-5640	#62-5375	#63-5401	#64-5541	#65-5721	#66-5353	#67-5709	#68-5479	#69-5641	#70-5593
#71-5567	#72-5621	#73-5302	#74-5665	#75-5258	#76-5415	#77-5644	#78-5461	#79-5502	#80-5675
#81-5356	#82-5722	#83-5720	#84-5397	#85-5694	#86-5564	#87-5352	#88-5474	#89-5285	#90-5337
#91-5535	#92-5483	#93-5321	#94-5711	#95-5335	#96-5453	#97-5466	#98-5625	#99-5384	#100-5327

Type 6 #12 [Back to Summary]									
#01-5651	#02-5560	#03-5556	#04-5397	#05-5665	#06-5475	#07-5537	#08-5455	#09-5289	#10-5529
#11-5614	#12-5437	#13-5605	#14-5714	#15-5332	#16-5623	#17-5641	#18-5694	#19-5342	#20-5585
#21-5690	#22-5543	#23-5431	#24-5544	#25-5271	#26-5329	#27-5441	#28-5719	#29-5602	#30-5540
#31-5279	#32-5412	#33-5413	#34-5250	#35-5553	#36-5468	#37-5277	#38-5268	#39-5345	#40-5297
#41-5255	#42-5593	#43-5609	#44-5356	#45-5346	#46-5370	#47-5319	#48-5251	#49-5358	#50-5558
#51-5699	#52-5591	#53-5578	#54-5483	#55-5656	#56-5516	#57-5395	#58-5264	#59-5670	#60-5713
#61-5448	#62-5443	#63-5550	#64-5331	#65-5568	#66-5404	#67-5341	#68-5324	#69-5490	#70-5642
#71-5563	#72-5660	#73-5639	#74-5708	#75-5320	#76-5649	#77-5600	#78-5322	#79-5645	#80-5405
#81-5547	#82-5396	#83-5485	#84-5457	#85-5254	#86-5399	#87-5610	#88-5266	#89-5257	#90-5410
#91-5637	#92-5520	#93-5476	#94-5571	#95-5267	#96-5484	#97-5458	#98-5673	#99-5291	#100-5644

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 117 of 177

Type 6 #13 [Back to Summary]									
#01-5720	#02-5601	#03-5412	#04-5668	#05-5271	#06-5536	#07-5641	#08-5665	#09-5292	#10-5256
#11-5252	#12-5660	#13-5497	#14-5592	#15-5378	#16-5609	#17-5319	#18-5341	#19-5281	#20-5520
#21-5555	#22-5499	#23-5437	#24-5423	#25-5278	#26-5468	#27-5627	#28-5646	#29-5703	#30-5598
#31-5355	#32-5400	#33-5541	#34-5295	#35-5310	#36-5323	#37-5350	#38-5317	#39-5367	#40-5631
#41-5518	#42-5353	#43-5704	#44-5450	#45-5383	#46-5414	#47-5642	#48-5495	#49-5339	#50-5470
#51-5599	#52-5699	#53-5637	#54-5572	#55-5508	#56-5422	#57-5287	#58-5371	#59-5277	#60-5379
#61-5554	#62-5346	#63-5300	#64-5493	#65-5563	#66-5259	#67-5687	#68-5683	#69-5419	#70-5488
#71-5382	#72-5345	#73-5644	#74-5652	#75-5444	#76-5299	#77-5268	#78-5494	#79-5481	#80-5586
#81-5681	#82-5585	#83-5311	#84-5320	#85-5260	#86-5397	#87-5530	#88-5540	#89-5653	#90-5279
#91-5721	#92-5604	#93-5388	#94-5523	#95-5606	#96-5544	#97-5404	#98-5684	#99-5325	#100-5575

Type 6 #14 [Back to Summary]									
#01-5338	#02-5503	#03-5305	#04-5709	#05-5378	#06-5458	#07-5404	#08-5518	#09-5614	#10-5416
#11-5422	#12-5694	#13-5285	#14-5704	#15-5483	#16-5493	#17-5586	#18-5407	#19-5392	#20-5491
#21-5459	#22-5385	#23-5466	#24-5505	#25-5379	#26-5563	#27-5370	#28-5311	#29-5675	#30-5326
#31-5431	#32-5722	#33-5509	#34-5461	#35-5707	#36-5482	#37-5265	#38-5413	#39-5402	#40-5332
#41-5498	#42-5486	#43-5356	#44-5437	#45-5690	#46-5554	#47-5571	#48-5674	#49-5448	#50-5301
#51-5542	#52-5541	#53-5558	#54-5366	#55-5677	#56-5286	#57-5524	#58-5580	#59-5539	#60-5337
#61-5342	#62-5568	#63-5538	#64-5710	#65-5425	#66-5434	#67-5548	#68-5251	#69-5477	#70-5423
#71-5255	#72-5310	#73-5718	#74-5697	#75-5279	#76-5278	#77-5549	#78-5716	#79-5421	#80-5588
#81-5623	#82-5508	#83-5430	#84-5676	#85-5345	#86-5445	#87-5557	#88-5587	#89-5719	#90-5405
#91-5643	#92-5543	#93-5452	#94-5515	#95-5369	#96-5272	#97-5446	#98-5481	#99-5565	#100-5393

Type 6 #15 [Back to Summary]									
#01-5648	#02-5257	#03-5709	#04-5280	#05-5547	#06-5641	#07-5479	#08-5669	#09-5279	#10-5525
#11-5720	#12-5483	#13-5453	#14-5692	#15-5531	#16-5261	#17-5591	#18-5392	#19-5315	#20-5562
#21-5304	#22-5460	#23-5551	#24-5274	#25-5430	#26-5694	#27-5468	#28-5391	#29-5324	#30-5389
#31-5442	#32-5673	#33-5360	#34-5676	#35-5355	#36-5437	#37-5481	#38-5526	#39-5289	#40-5327
#41-5651	#42-5698	#43-5514	#44-5519	#45-5611	#46-5544	#47-5640	#48-5537	#49-5502	#50-5573
#51-5415	#52-5253	#53-5339	#54-5431	#55-5684	#56-5575	#57-5578	#58-5422	#59-5338	#60-5594
#61-5614	#62-5333	#63-5296	#64-5372	#65-5501	#66-5587	#67-5343	#68-5504	#69-5314	#70-5353
#71-5713	#72-5636	#73-5330	#74-5671	#75-5624	#76-5480	#77-5400	#78-5484	#79-5475	#80-5511
#81-5593	#82-5508	#83-5357	#84-5642	#85-5255	#86-5521	#87-5435	#88-5630	#89-5354	#90-5567
#91-5472	#92-5488	#93-5292	#94-5283	#95-5438	#96-5470	#97-5427	#98-5342	#99-5258	#100-5491

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 118 of 177

Type 6 #16 [Back to Summary]									
#01-5531	#02-5454	#03-5281	#04-5428	#05-5662	#06-5587	#07-5332	#08-5252	#09-5465	#10-5513
#11-5265	#12-5638	#13-5669	#14-5338	#15-5708	#16-5362	#17-5642	#18-5323	#19-5701	#20-5297
#21-5307	#22-5257	#23-5305	#24-5357	#25-5653	#26-5478	#27-5423	#28-5372	#29-5330	#30-5579
#31-5401	#32-5448	#33-5316	#34-5645	#35-5692	#36-5699	#37-5271	#38-5621	#39-5352	#40-5684
#41-5473	#42-5379	#43-5427	#44-5458	#45-5299	#46-5325	#47-5552	#48-5344	#49-5268	#50-5282
#51-5444	#52-5474	#53-5447	#54-5700	#55-5321	#56-5550	#57-5659	#58-5578	#59-5554	#60-5342
#61-5432	#62-5724	#63-5309	#64-5518	#65-5614	#66-5641	#67-5442	#68-5635	#69-5365	#70-5348
#71-5680	#72-5400	#73-5679	#74-5557	#75-5703	#76-5660	#77-5347	#78-5544	#79-5710	#80-5721
#81-5546	#82-5682	#83-5594	#84-5670	#85-5392	#86-5290	#87-5417	#88-5317	#89-5259	#90-5501
#91-5319	#92-5634	#93-5569	#94-5383	#95-5608	#96-5704	#97-5327	#98-5293	#99-5519	#100-5393

Type 6 #17 [Back to Summary]									
#01-5343	#02-5614	#03-5465	#04-5400	#05-5456	#06-5522	#07-5446	#08-5253	#09-5487	#10-5561
#11-5640	#12-5296	#13-5497	#14-5699	#15-5698	#16-5308	#17-5512	#18-5333	#19-5669	#20-5520
#21-5633	#22-5276	#23-5599	#24-5295	#25-5464	#26-5627	#27-5256	#28-5326	#29-5469	#30-5638
#31-5429	#32-5443	#33-5526	#34-5567	#35-5502	#36-5550	#37-5267	#38-5585	#39-5462	#40-5305
#41-5470	#42-5557	#43-5323	#44-5654	#45-5336	#46-5360	#47-5667	#48-5255	#49-5586	#50-5539
#51-5685	#52-5574	#53-5604	#54-5309	#55-5435	#56-5588	#57-5590	#58-5354	#59-5717	#60-5620
#61-5439	#62-5651	#63-5268	#64-5647	#65-5460	#66-5578	#67-5695	#68-5381	#69-5483	#70-5495
#71-5472	#72-5457	#73-5587	#74-5325	#75-5678	#76-5670	#77-5683	#78-5353	#79-5684	#80-5251
#81-5655	#82-5677	#83-5579	#84-5564	#85-5467	#86-5382	#87-5637	#88-5592	#89-5544	#90-5390
#91-5535	#92-5534	#93-5293	#94-5463	#95-5367	#96-5388	#97-5447	#98-5359	#99-5635	#100-5644

Type 6 #18 [Back to Summary]									
#01-5396	#02-5613	#03-5660	#04-5438	#05-5437	#06-5337	#07-5695	#08-5606	#09-5263	#10-5478
#11-5724	#12-5533	#13-5523	#14-5583	#15-5604	#16-5615	#17-5600	#18-5293	#19-5511	#20-5527
#21-5477	#22-5449	#23-5688	#24-5398	#25-5442	#26-5360	#27-5611	#28-5464	#29-5462	#30-5425
#31-5270	#32-5273	#33-5252	#34-5290	#35-5490	#36-5703	#37-5631	#38-5401	#39-5357	#40-5451
#41-5430	#42-5562	#43-5470	#44-5637	#45-5536	#46-5250	#47-5555	#48-5435	#49-5476	#50-5513
#51-5403	#52-5572	#53-5358	#54-5417	#55-5672	#56-5650	#57-5721	#58-5326	#59-5480	#60-5394
#61-5457	#62-5701	#63-5530	#64-5483	#65-5342	#66-5626	#67-5708	#68-5448	#69-5661	#70-5310
#71-5347	#72-5640	#73-5704	#74-5301	#75-5587	#76-5441	#77-5426	#78-5710	#79-5591	#80-5619
#81-5597	#82-5543	#83-5303	#84-5370	#85-5405	#86-5280	#87-5674	#88-5632	#89-5429	#90-5560
#91-5445	#92-5321	#93-5681	#94-5492	#95-5314	#96-5467	#97-5260	#98-5502	#99-5693	#100-5599

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 119 of 177

Type 6 #19 [Back to Summary]									
#01-5649	#02-5529	#03-5520	#04-5274	#05-5598	#06-5408	#07-5650	#08-5591	#09-5525	#10-5636
#11-5610	#12-5524	#13-5572	#14-5588	#15-5293	#16-5630	#17-5310	#18-5397	#19-5472	#20-5321
#21-5596	#22-5276	#23-5721	#24-5458	#25-5334	#26-5468	#27-5373	#28-5639	#29-5608	#30-5345
#31-5575	#32-5429	#33-5445	#34-5600	#35-5485	#36-5700	#37-5325	#38-5259	#39-5706	#40-5562
#41-5285	#42-5534	#43-5436	#44-5542	#45-5359	#46-5628	#47-5270	#48-5451	#49-5280	#50-5621
#51-5252	#52-5622	#53-5533	#54-5311	#55-5665	#56-5674	#57-5328	#58-5467	#59-5277	#60-5514
#61-5393	#62-5418	#63-5395	#64-5335	#65-5463	#66-5340	#67-5283	#68-5716	#69-5437	#70-5272
#71-5517	#72-5540	#73-5564	#74-5551	#75-5536	#76-5269	#77-5315	#78-5678	#79-5426	#80-5547
#81-5316	#82-5424	#83-5284	#84-5376	#85-5319	#86-5399	#87-5506	#88-5647	#89-5592	#90-5690
#91-5577	#92-5417	#93-5365	#94-5530	#95-5693	#96-5631	#97-5346	#98-5289	#99-5398	#100-5384

Type 6 #20 [Back to Summary]									
#01-5350	#02-5501	#03-5655	#04-5422	#05-5257	#06-5449	#07-5720	#08-5692	#09-5570	#10-5351
#11-5695	#12-5300	#13-5669	#14-5393	#15-5437	#16-5663	#17-5566	#18-5649	#19-5574	#20-5329
#21-5698	#22-5369	#23-5322	#24-5477	#25-5498	#26-5398	#27-5457	#28-5641	#29-5384	#30-5611
#31-5717	#32-5694	#33-5376	#34-5414	#35-5701	#36-5448	#37-5597	#38-5723	#39-5640	#40-5476
#41-5446	#42-5315	#43-5572	#44-5343	#45-5280	#46-5314	#47-5415	#48-5473	#49-5534	#50-5271
#51-5527	#52-5535	#53-5505	#54-5675	#55-5484	#56-5653	#57-5380	#58-5560	#59-5413	#60-5677
#61-5424	#62-5310	#63-5590	#64-5407	#65-5627	#66-5301	#67-5575	#68-5472	#69-5648	#70-5256
#71-5630	#72-5304	#73-5427	#74-5577	#75-5530	#76-5445	#77-5387	#78-5432	#79-5673	#80-5573
#81-5604	#82-5600	#83-5718	#84-5497	#85-5274	#86-5489	#87-5711	#88-5346	#89-5610	#90-5626
#91-5619	#92-5283	#93-5507	#94-5286	#95-5684	#96-5582	#97-5305	#98-5599	#99-5517	#100-5307

Type 6 #21 [Back to Summary]									
#01-5326	#02-5575	#03-5364	#04-5275	#05-5494	#06-5476	#07-5461	#08-5619	#09-5714	#10-5414
#11-5379	#12-5276	#13-5336	#14-5426	#15-5375	#16-5288	#17-5355	#18-5261	#19-5376	#20-5271
#21-5645	#22-5378	#23-5522	#24-5409	#25-5690	#26-5473	#27-5340	#28-5518	#29-5717	#30-5506
#31-5368	#32-5647	#33-5481	#34-5432	#35-5635	#36-5496	#37-5495	#38-5600	#39-5374	#40-5472
#41-5546	#42-5612	#43-5458	#44-5568	#45-5632	#46-5395	#47-5598	#48-5405	#49-5655	#50-5573
#51-5713	#52-5588	#53-5448	#54-5387	#55-5673	#56-5302	#57-5680	#58-5310	#59-5385	#60-5668
#61-5626	#62-5295	#63-5457	#64-5519	#65-5628	#66-5516	#67-5604	#68-5479	#69-5611	#70-5629
#71-5449	#72-5282	#73-5644	#74-5679	#75-5501	#76-5545	#77-5660	#78-5394	#79-5505	#80-5710
#81-5687	#82-5443	#83-5539	#84-5540	#85-5352	#86-5603	#87-5711	#88-5250	#89-5523	#90-5425
#91-5694	#92-5614	#93-5300	#94-5304	#95-5483	#96-5701	#97-5544	#98-5296	#99-5354	#100-5278

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 120 of 177

Type 6 #22 [Back to Summary]									
#01-5348	#02-5429	#03-5489	#04-5396	#05-5450	#06-5330	#07-5482	#08-5665	#09-5515	#10-5258
#11-5534	#12-5583	#13-5553	#14-5410	#15-5704	#16-5664	#17-5508	#18-5543	#19-5571	#20-5296
#21-5643	#22-5406	#23-5326	#24-5670	#25-5631	#26-5295	#27-5537	#28-5339	#29-5284	#30-5528
#31-5629	#32-5663	#33-5658	#34-5345	#35-5359	#36-5300	#37-5681	#38-5610	#39-5522	#40-5478
#41-5310	#42-5417	#43-5315	#44-5360	#45-5615	#46-5325	#47-5544	#48-5442	#49-5251	#50-5308
#51-5667	#52-5353	#53-5404	#54-5517	#55-5393	#56-5630	#57-5711	#58-5596	#59-5619	#60-5594
#61-5613	#62-5551	#63-5657	#64-5298	#65-5542	#66-5398	#67-5633	#68-5604	#69-5520	#70-5709
#71-5647	#72-5263	#73-5464	#74-5335	#75-5628	#76-5462	#77-5606	#78-5548	#79-5403	#80-5256
#81-5481	#82-5441	#83-5456	#84-5255	#85-5334	#86-5271	#87-5313	#88-5444	#89-5416	#90-5549
#91-5656	#92-5616	#93-5318	#94-5401	#95-5490	#96-5501	#97-5519	#98-5694	#99-5419	#100-5595

Type 6 #23 [Back to Summary]									
#01-5379	#02-5416	#03-5625	#04-5449	#05-5383	#06-5286	#07-5320	#08-5637	#09-5587	#10-5381
#11-5359	#12-5451	#13-5293	#14-5458	#15-5428	#16-5376	#17-5569	#18-5410	#19-5328	#20-5543
#21-5347	#22-5532	#23-5444	#24-5559	#25-5311	#26-5366	#27-5297	#28-5608	#29-5536	#30-5542
#31-5472	#32-5384	#33-5680	#34-5712	#35-5371	#36-5589	#37-5310	#38-5406	#39-5345	#40-5593
#41-5524	#42-5506	#43-5592	#44-5358	#45-5282	#46-5323	#47-5392	#48-5599	#49-5503	#50-5616
#51-5601	#52-5498	#53-5572	#54-5430	#55-5614	#56-5322	#57-5644	#58-5273	#59-5278	#60-5300
#61-5564	#62-5612	#63-5414	#64-5633	#65-5502	#66-5440	#67-5254	#68-5705	#69-5349	#70-5646
#71-5448	#72-5434	#73-5664	#74-5258	#75-5663	#76-5692	#77-5677	#78-5333	#79-5698	#80-5465
#81-5662	#82-5288	#83-5581	#84-5611	#85-5357	#86-5354	#87-5665	#88-5699	#89-5713	#90-5486
#91-5321	#92-5609	#93-5685	#94-5619	#95-5504	#96-5607	#97-5388	#98-5618	#99-5403	#100-5694

Type 6 #24 [Back to Summary]									
#01-5402	#02-5313	#03-5633	#04-5600	#05-5492	#06-5647	#07-5369	#08-5560	#09-5299	#10-5537
#11-5363	#12-5525	#13-5280	#14-5253	#15-5272	#16-5394	#17-5336	#18-5314	#19-5256	#20-5360
#21-5410	#22-5376	#23-5550	#24-5371	#25-5297	#26-5294	#27-5513	#28-5478	#29-5554	#30-5341
#31-5327	#32-5293	#33-5610	#34-5612	#35-5257	#36-5548	#37-5449	#38-5423	#39-5301	#40-5594
#41-5651	#42-5271	#43-5321	#44-5428	#45-5588	#46-5424	#47-5427	#48-5359	#49-5521	#50-5324
#51-5292	#52-5534	#53-5276	#54-5487	#55-5511	#56-5552	#57-5448	#58-5383	#59-5616	#60-5683
#61-5459	#62-5320	#63-5640	#64-5393	#65-5721	#66-5669	#67-5582	#68-5615	#69-5680	#70-5491
#71-5484	#72-5354	#73-5479	#74-5668	#75-5430	#76-5339	#77-5300	#78-5444	#79-5545	#80-5406
#81-5567	#82-5706	#83-5310	#84-5663	#85-5650	#86-5700	#87-5642	#88-5702	#89-5644	#90-5586
#91-5358	#92-5495	#93-5445	#94-5703	#95-5414	#96-5433	#97-5656	#98-5526	#99-5646	#100-5258

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 121 of 177

Type 6 #25 [Back to Summary]									
#01-5568	#02-5665	#03-5267	#04-5294	#05-5565	#06-5536	#07-5388	#08-5456	#09-5638	#10-5322
#11-5315	#12-5264	#13-5256	#14-5656	#15-5640	#16-5287	#17-5513	#18-5564	#19-5291	#20-5617
#21-5559	#22-5367	#23-5710	#24-5636	#25-5279	#26-5606	#27-5545	#28-5474	#29-5277	#30-5309
#31-5302	#32-5345	#33-5682	#34-5598	#35-5387	#36-5357	#37-5650	#38-5380	#39-5444	#40-5422
#41-5379	#42-5413	#43-5408	#44-5257	#45-5517	#46-5619	#47-5262	#48-5460	#49-5605	#50-5366
#51-5258	#52-5548	#53-5282	#54-5382	#55-5492	#56-5507	#57-5506	#58-5635	#59-5414	#60-5281
#61-5288	#62-5680	#63-5335	#64-5671	#65-5376	#66-5365	#67-5486	#68-5669	#69-5580	#70-5473
#71-5482	#72-5596	#73-5599	#74-5579	#75-5541	#76-5428	#77-5661	#78-5337	#79-5411	#80-5465
#81-5575	#82-5393	#83-5469	#84-5280	#85-5390	#86-5341	#87-5457	#88-5478	#89-5497	#90-5310
#91-5455	#92-5610	#93-5254	#94-5490	#95-5604	#96-5426	#97-5634	#98-5259	#99-5632	#100-5608

Type 6 #26 [Back to Summary]									
#01-5559	#02-5252	#03-5471	#04-5501	#05-5399	#06-5548	#07-5510	#08-5282	#09-5673	#10-5481
#11-5606	#12-5697	#13-5266	#14-5335	#15-5528	#16-5489	#17-5265	#18-5254	#19-5348	#20-5538
#21-5442	#22-5374	#23-5393	#24-5537	#25-5663	#26-5306	#27-5444	#28-5532	#29-5473	#30-5555
#31-5610	#32-5664	#33-5485	#34-5586	#35-5445	#36-5388	#37-5594	#38-5681	#39-5329	#40-5674
#41-5525	#42-5527	#43-5506	#44-5378	#45-5373	#46-5517	#47-5587	#48-5325	#49-5662	#50-5619
#51-5255	#52-5344	#53-5415	#54-5434	#55-5583	#56-5659	#57-5563	#58-5342	#59-5354	#60-5702
#61-5534	#62-5368	#63-5596	#64-5666	#65-5462	#66-5405	#67-5614	#68-5390	#69-5309	#70-5649
#71-5262	#72-5640	#73-5592	#74-5264	#75-5413	#76-5396	#77-5636	#78-5456	#79-5536	#80-5660
#81-5604	#82-5376	#83-5420	#84-5260	#85-5529	#86-5367	#87-5711	#88-5569	#89-5547	#90-5718
#91-5507	#92-5431	#93-5305	#94-5432	#95-5642	#96-5292	#97-5560	#98-5330	#99-5332	#100-5500

Type 6 #27 [Back to Summary]									
#01-5567	#02-5568	#03-5495	#04-5417	#05-5623	#06-5442	#07-5496	#08-5722	#09-5432	#10-5717
#11-5539	#12-5321	#13-5709	#14-5604	#15-5585	#16-5684	#17-5666	#18-5663	#19-5554	#20-5439
#21-5647	#22-5454	#23-5482	#24-5707	#25-5340	#26-5261	#27-5718	#28-5521	#29-5493	#30-5349
#31-5523	#32-5713	#33-5308	#34-5645	#35-5418	#36-5685	#37-5414	#38-5675	#39-5337	#40-5376
#41-5301	#42-5720	#43-5680	#44-5514	#45-5616	#46-5708	#47-5448	#48-5288	#49-5324	#50-5332
#51-5619	#52-5392	#53-5558	#54-5617	#55-5578	#56-5362	#57-5336	#58-5513	#59-5326	#60-5611
#61-5449	#62-5699	#63-5479	#64-5333	#65-5443	#66-5551	#67-5262	#68-5313	#69-5435	#70-5624
#71-5520	#72-5715	#73-5576	#74-5427	#75-5387	#76-5651	#77-5498	#78-5693	#79-5356	#80-5538
#81-5679	#82-5446	#83-5411	#84-5381	#85-5404	#86-5416	#87-5317	#88-5305	#89-5599	#90-5625
#91-5450	#92-5652	#93-5327	#94-5491	#95-5597	#96-5315	#97-5696	#98-5384	#99-5425	#100-5536

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 122 of 177

Type 6 #28 [Back to Summary]									
#01-5628	#02-5540	#03-5381	#04-5479	#05-5651	#06-5589	#07-5368	#08-5422	#09-5694	#10-5322
#11-5494	#12-5502	#13-5317	#14-5603	#15-5311	#16-5396	#17-5571	#18-5721	#19-5380	#20-5274
#21-5620	#22-5366	#23-5375	#24-5500	#25-5310	#26-5410	#27-5625	#28-5621	#29-5275	#30-5385
#31-5404	#32-5351	#33-5271	#34-5599	#35-5551	#36-5565	#37-5273	#38-5661	#39-5390	#40-5440
#41-5481	#42-5453	#43-5629	#44-5377	#45-5407	#46-5549	#47-5423	#48-5719	#49-5259	#50-5643
#51-5374	#52-5387	#53-5447	#54-5400	#55-5641	#56-5512	#57-5415	#58-5605	#59-5419	#60-5491
#61-5689	#62-5471	#63-5559	#64-5392	#65-5443	#66-5302	#67-5470	#68-5373	#69-5634	#70-5581
#71-5664	#72-5517	#73-5416	#74-5462	#75-5722	#76-5342	#77-5486	#78-5712	#79-5630	#80-5611
#81-5357	#82-5260	#83-5267	#84-5595	#85-5683	#86-5288	#87-5492	#88-5624	#89-5476	#90-5307
#91-5319	#92-5459	#93-5265	#94-5705	#95-5667	#96-5514	#97-5519	#98-5465	#99-5530	#100-5508

Type 6 #29 [Back to Summary]									
#01-5607	#02-5474	#03-5299	#04-5418	#05-5513	#06-5657	#07-5504	#08-5308	#09-5584	#10-5288
#11-5548	#12-5625	#13-5488	#14-5611	#15-5484	#16-5263	#17-5320	#18-5705	#19-5392	#20-5682
#21-5438	#22-5507	#23-5359	#24-5327	#25-5256	#26-5687	#27-5347	#28-5562	#29-5520	#30-5461
#31-5370	#32-5712	#33-5458	#34-5713	#35-5707	#36-5604	#37-5559	#38-5417	#39-5401	#40-5268
#41-5496	#42-5558	#43-5501	#44-5431	#45-5470	#46-5654	#47-5443	#48-5539	#49-5322	#50-5573
#51-5350	#52-5365	#53-5632	#54-5630	#55-5435	#56-5489	#57-5497	#58-5346	#59-5486	#60-5450
#61-5278	#62-5414	#63-5367	#64-5623	#65-5276	#66-5274	#67-5338	#68-5557	#69-5270	#70-5356
#71-5341	#72-5621	#73-5679	#74-5550	#75-5711	#76-5511	#77-5283	#78-5629	#79-5273	#80-5447
#81-5613	#82-5300	#83-5612	#84-5342	#85-5331	#86-5326	#87-5319	#88-5597	#89-5321	#90-5639
#91-5542	#92-5467	#93-5394	#94-5383	#95-5533	#96-5444	#97-5355	#98-5261	#99-5719	#100-5260

Type 6 #30 [Back to Summary]									
#01-5675	#02-5610	#03-5503	#04-5711	#05-5312	#06-5581	#07-5427	#08-5555	#09-5526	#10-5316
#11-5261	#12-5658	#13-5668	#14-5657	#15-5487	#16-5689	#17-5674	#18-5441	#19-5523	#20-5403
#21-5535	#22-5417	#23-5317	#24-5378	#25-5524	#26-5560	#27-5682	#28-5602	#29-5251	#30-5617
#31-5318	#32-5320	#33-5376	#34-5533	#35-5541	#36-5611	#37-5258	#38-5307	#39-5365	#40-5636
#41-5593	#42-5522	#43-5510	#44-5686	#45-5343	#46-5506	#47-5296	#48-5350	#49-5527	#50-5476
#51-5390	#52-5443	#53-5325	#54-5643	#55-5659	#56-5591	#57-5597	#58-5649	#59-5315	#60-5368
#61-5590	#62-5373	#63-5671	#64-5328	#65-5665	#66-5383	#67-5407	#68-5492	#69-5667	#70-5630
#71-5531	#72-5416	#73-5430	#74-5303	#75-5681	#76-5625	#77-5340	#78-5567	#79-5463	#80-5710
#81-5466	#82-5692	#83-5324	#84-5724	#85-5498	#86-5288	#87-5645	#88-5339	#89-5458	#90-5382
#91-5305	#92-5693	#93-5410	#94-5393	#95-5448	#96-5342	#97-5419	#98-5362	#99-5493	#100-5537

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 123 of 177

Type 5 #1 5564 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	9	131353	92	0	0	574437	705882
2	3	9	180345	60	1048	1325	522984	705882
3	2	9	125062	82	1487	0	579169	705882
4	3	9	16038	97	1747	1542	686264	705882
5	2	9	119670	96	1406	0	584614	705882
6	1	9	129009	96	0	0	576777	705882
7	2	9	354840	77	1310	0	349578	705882
8	3	9	691092	90	1807	1905	10808	705882
9	2	9	608971	80	1361	0	95390	705882
10	1	9	381308	52	0	0	324522	705882
11	3	9	475707	76	1853	1258	226836	705882
12	3	9	96740	91	1195	1518	606156	705882
13	2	9	229622	70	1888	0	474232	705882
14	3	9	593013	93	1316	1091	110183	705882
15	3	9	272207	76	1494	1001	430952	705882
16	1	9	507518	53	0	0	198311	705882
17	2	9	36748	71	1849	0	667143	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 124 of 177

Type 5 #2 5562 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	14	117382	89	1845	0	480595	600000
2	2	14	119314	95	1538	0	478958	600000
3	3	14	445640	72	1627	1678	150839	600000
4	3	14	273689	84	1378	1437	323244	600000
5	3	14	259043	71	1993	1970	336781	600000
6	1	14	231058	76	0	0	368866	600000
7	1	14	597365	76	0	0	2559	600000
8	3	14	352997	68	1806	1077	243916	600000
9	3	14	101942	99	1841	1949	493971	600000
10	2	14	331548	65	1540	0	266782	600000
11	2	14	255245	77	1930	0	342671	600000
12	1	14	278289	61	0	0	321650	600000
13	1	14	296257	86	0	0	303657	600000
14	1	14	51564	55	0	0	548381	600000
15	1	14	181028	72	0	0	418900	600000
16	3	14	26095	74	1645	1855	570183	600000
17	1	14	582067	94	0	0	17839	600000
18	3	14	314125	94	1832	1589	282172	600000
19	1	14	348689	62	0	0	251249	600000
20	2	14	473478	51	1326	0	125094	600000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 125 of 177

Type 5 #3 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	13	151658	55	0	0	448287	600000
2	2	13	507722	53	1284	0	90888	600000
3	1	13	384157	52	0	0	215791	600000
4	1	13	397668	87	0	0	202245	600000
5	3	13	141201	56	1698	1051	455882	600000
6	1	13	91255	83	0	0	508662	600000
7	2	13	288685	53	1231	0	309978	600000
8	3	13	346215	65	1740	1889	249961	600000
9	1	13	559207	96	0	0	40697	600000
10	2	13	232644	55	1526	0	365720	600000
11	1	13	412690	68	0	0	187242	600000
12	3	13	516117	78	1249	1473	80927	600000
13	3	13	23853	80	1665	1916	572326	600000
14	2	13	203170	84	1573	0	395089	600000
15	2	13	439270	93	1726	0	158818	600000
16	1	13	265268	73	0	0	334659	600000
17	1	13	320219	88	0	0	279693	600000
18	1	13	327866	59	0	0	272075	600000
19	2	13	208865	97	1672	0	389269	600000
20	1	13	204042	79	0	0	395879	600000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 126 of 177

Type 5 #4 5563 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	11	501704	72	1049	1472	162225	666666
2	2	11	234945	57	1330	0	430277	666666
3	3	11	527743	87	1235	1014	136413	666666
4	2	11	432770	73	1070	0	232680	666666
5	3	11	64960	76	1209	1818	598451	666666
6	2	11	440409	62	1949	0	224184	666666
7	3	11	452700	91	1147	1483	211063	666666
8	3	11	315797	97	1384	1594	347600	666666
9	2	11	137748	65	1351	0	527437	666666
10	1	11	474014	99	0	0	192553	666666
11	1	11	359201	65	0	0	307400	666666
12	1	11	338245	85	0	0	328336	666666
13	3	11	8677	54	1844	1121	654862	666666
14	2	11	570358	94	1650	0	94470	666666
15	2	11	61393	56	1763	0	603398	666666
16	1	11	527078	91	0	0	139497	666666
17	1	11	651366	59	0	0	15241	666666
18	3	11	628707	98	1443	1507	34715	666666

Type 5 #5 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	15	263026	51	1353	0	658595	923076
2	3	15	746469	55	1557	1055	173830	923076
3	2	15	462082	75	1248	0	459596	923076
4	2	15	526131	58	1825	0	395004	923076
5	1	15	311181	94	0	0	611801	923076
6	2	15	697739	96	1178	0	223967	923076
7	3	15	50623	70	1694	1136	869413	923076
8	3	15	580785	85	1235	1864	338937	923076
9	3	15	238446	93	1986	1371	680994	923076
10	1	15	747334	72	0	0	175670	923076
11	2	15	156607	52	1055	0	765310	923076
12	1	15	6312	89	0	0	916675	923076
13	3	15	816686	93	1299	1244	103568	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 127 of 177

[Type 5 #6 5499 \[Back to Summary\]](#)

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	5461	99	1354	1940	657614	666666
2	2	17	571656	99	1636	0	93176	666666
3	1	17	11123	91	0	0	655452	666666
4	2	17	438721	54	1114	0	226723	666666
5	3	17	454509	76	1857	1099	208973	666666
6	2	17	378142	79	1485	0	286881	666666
7	1	17	578725	82	0	0	87859	666666
8	2	17	107602	85	1116	0	557778	666666
9	3	17	394319	91	1079	1347	269648	666666
10	2	17	194213	59	1385	0	470950	666666
11	2	17	281338	71	1159	0	384027	666666
12	1	17	261283	63	0	0	405320	666666
13	2	17	61784	88	1480	0	603226	666666
14	3	17	622610	82	1636	1197	40977	666666
15	3	17	292288	88	1724	1972	370418	666666
16	2	17	290529	51	1185	0	374850	666666
17	1	17	661171	62	0	0	5433	666666
18	2	17	216292	73	1362	0	448866	666666

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 128 of 177

Type 5 #7 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	19	154041	50	0	0	551791	705882
2	3	19	229538	93	1983	1799	472283	705882
3	3	19	419781	85	1187	1702	282957	705882
4	1	19	676470	99	0	0	29313	705882
5	2	19	189404	62	1805	0	514549	705882
6	1	19	185665	63	0	0	520154	705882
7	2	19	30361	50	1771	0	673650	705882
8	3	19	253959	72	1255	1814	448638	705882
9	2	19	112399	70	1925	0	591418	705882
10	3	19	156899	64	1660	1464	545667	705882
11	3	19	140929	90	1812	1369	561502	705882
12	1	19	402995	98	0	0	302789	705882
13	1	19	223780	77	0	0	482025	705882
14	1	19	642865	88	0	0	62929	705882
15	2	19	583463	67	1410	0	120875	705882
16	2	19	666429	58	1317	0	38020	705882
17	2	19	376384	94	1614	0	327696	705882

Type 5 #8 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	15	1053690	61	1104	1865	276491	1333333
2	1	15	837000	94	0	0	496239	1333333
3	1	15	1001716	56	0	0	331561	1333333
4	3	15	411269	69	1813	1226	918818	1333333
5	1	15	277193	89	0	0	1056051	1333333
6	2	15	3191	96	1956	0	1327994	1333333
7	2	15	628070	64	1079	0	704056	1333333
8	1	15	727962	65	0	0	605306	1333333
9	1	15	394251	51	0	0	939031	1333333

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 129 of 177

Type 5 #9 5561 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	16	20014	68	1144	1454	1068093	1090909
2	3	16	333497	73	1940	1896	753357	1090909
3	2	16	596214	92	1284	0	493227	1090909
4	2	16	598659	51	1525	0	490623	1090909
5	2	16	1012602	57	1267	0	76926	1090909
6	1	16	115320	96	0	0	975493	1090909
7	2	16	620717	65	1175	0	468887	1090909
8	3	16	8164	55	1480	1060	1080040	1090909
9	1	16	261229	71	0	0	829609	1090909
10	3	16	970464	60	1995	1434	116836	1090909
11	3	16	1081015	87	1077	1314	7242	1090909

Type 5 #10 5562 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	13	220465	90	1534	0	444487	666666
2	3	13	638401	86	1003	1444	25560	666666
3	3	13	18689	83	1287	1192	645249	666666
4	1	13	320980	87	0	0	345599	666666
5	3	13	517299	60	1538	1561	146088	666666
6	3	13	641739	94	1916	1573	21156	666666
7	2	13	153153	94	1625	0	511700	666666
8	2	13	149825	73	1280	0	515415	666666
9	1	13	279765	94	0	0	386807	666666
10	1	13	105915	79	0	0	560672	666666
11	3	13	383028	68	1770	1067	280597	666666
12	3	13	91856	72	1233	1965	571396	666666
13	2	13	133238	64	1989	0	531311	666666
14	2	13	391446	78	1008	0	274056	666666
15	1	13	439617	88	0	0	226961	666666
16	1	13	453920	84	0	0	212662	666666
17	3	13	404116	61	1688	1757	258922	666666
18	1	13	32607	69	0	0	633990	666666

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 130 of 177

Type 5 #11 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	753716	85	0	0	103341	857142
2	1	10	4391	61	0	0	852690	857142
3	1	10	78139	68	0	0	778935	857142
4	1	10	334705	50	0	0	522387	857142
5	1	10	183091	94	0	0	673957	857142
6	3	10	508007	72	1772	1546	345601	857142
7	3	10	281652	52	1519	1199	572616	857142
8	3	10	678774	69	1759	1963	174439	857142
9	2	10	445243	73	1135	0	410618	857142
10	2	10	320185	75	1517	0	535290	857142
11	2	10	603125	83	1486	0	252365	857142
12	1	10	793464	85	0	0	63593	857142
13	1	10	351596	75	0	0	505471	857142
14	2	10	782167	74	1970	0	72857	857142

Type 5 #12 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	20	284540	74	1093	0	345797	631578
2	3	20	274172	69	1044	1864	354291	631578
3	2	20	394793	93	1713	0	234886	631578
4	2	20	160999	85	1917	0	468492	631578
5	1	20	356383	90	0	0	275105	631578
6	3	20	348285	78	1053	1588	280418	631578
7	1	20	605561	82	0	0	25935	631578
8	2	20	575696	81	1202	0	54518	631578
9	2	20	614728	57	1633	0	15103	631578
10	1	20	149686	81	0	0	481811	631578
11	1	20	216416	91	0	0	415071	631578
12	3	20	323518	85	1232	1690	304883	631578
13	3	20	541778	69	1322	1457	86814	631578
14	1	20	478855	94	0	0	152629	631578
15	3	20	308869	50	1297	1452	319810	631578
16	1	20	48871	83	0	0	582624	631578
17	2	20	189852	55	1293	0	440323	631578
18	2	20	19423	81	1774	0	610219	631578
19	3	20	334449	87	1569	1688	293611	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 131 of 177

Type 5 #13 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	561181	74	0	0	438745	1000000
2	1	15	337124	76	0	0	662800	1000000
3	2	15	963828	79	1568	0	34446	1000000
4	1	15	505105	80	0	0	494815	1000000
5	1	15	546795	63	0	0	453142	1000000
6	1	15	937214	55	0	0	62731	1000000
7	2	15	263881	81	1921	0	734036	1000000
8	2	15	334950	85	1282	0	663598	1000000
9	2	15	874905	90	1257	0	123658	1000000
10	1	15	452400	72	0	0	547528	1000000
11	1	15	685033	83	0	0	314884	1000000
12	3	15	82723	72	1722	1535	913804	1000000

Type 5 #14 5562 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	138805	96	1563	1863	714623	857142
2	3	14	250436	90	1542	1669	603225	857142
3	1	14	92399	56	0	0	764687	857142
4	1	14	753362	82	0	0	103698	857142
5	1	14	847189	92	0	0	9861	857142
6	1	14	845539	77	0	0	11526	857142
7	1	14	218112	66	0	0	638964	857142
8	1	14	831069	82	0	0	25991	857142
9	2	14	237813	79	1351	0	617820	857142
10	3	14	405422	53	1014	1966	448581	857142
11	2	14	386140	65	1976	0	468896	857142
12	3	14	492986	80	1344	1983	360589	857142
13	3	14	194012	77	1280	1894	659725	857142
14	2	14	792331	86	1965	0	62674	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 132 of 177

Type 5 #15 5564 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	22446	71	1780	0	1066541	1090909
2	3	10	343685	53	1475	1672	743918	1090909
3	3	10	1074118	77	1739	1288	13533	1090909
4	3	10	274574	87	1804	1008	813262	1090909
5	3	10	525042	80	1251	1186	563190	1090909
6	3	10	1077793	72	1464	1160	10276	1090909
7	3	10	523081	60	1071	1556	565021	1090909
8	3	10	190536	61	1379	1912	896899	1090909
9	1	10	478559	66	0	0	612284	1090909
10	2	10	235582	90	1487	0	853660	1090909
11	1	10	840431	98	0	0	250380	1090909

Type 5 #16 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	11137	82	1195	1750	652338	666666
2	3	17	107265	72	1786	1323	556076	666666
3	3	17	354276	97	1955	1076	309068	666666
4	3	17	653193	72	1900	1670	9687	666666
5	3	17	175886	88	1259	1750	487507	666666
6	1	17	397325	91	0	0	269250	666666
7	1	17	318883	50	0	0	347733	666666
8	3	17	108353	85	1523	1100	555435	666666
9	1	17	12624	52	0	0	653990	666666
10	2	17	144541	85	1731	0	520224	666666
11	1	17	639689	95	0	0	26882	666666
12	1	17	505861	99	0	0	160706	666666
13	1	17	35253	83	0	0	631330	666666
14	2	17	635828	86	1278	0	29388	666666
15	1	17	59272	74	0	0	607320	666666
16	3	17	477986	90	1662	1511	185237	666666
17	2	17	355609	62	1383	0	309550	666666
18	2	17	586154	80	1107	0	79245	666666

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 133 of 177

Type 5 #17 5560 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	765054	72	1488	0	233314	1000000
2	1	19	413833	51	0	0	586116	1000000
3	2	19	404966	62	1101	0	593809	1000000
4	1	19	387851	76	0	0	612073	1000000
5	1	19	782185	59	0	0	217756	1000000
6	2	19	614741	100	1458	0	383601	1000000
7	2	19	981798	100	1910	0	16092	1000000
8	1	19	353704	58	0	0	646238	1000000
9	1	19	386381	70	0	0	613549	1000000
10	2	19	286416	54	1971	0	711505	1000000
11	2	19	359007	73	1702	0	639145	1000000
12	2	19	414672	69	1243	0	583947	1000000

Type 5 #18 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	20	198020	73	1167	1504	549090	750000
2	3	20	34610	99	1837	1733	711523	750000
3	1	20	322763	94	0	0	427143	750000
4	3	20	682052	53	1701	1966	64122	750000
5	3	20	63290	81	1312	1951	683204	750000
6	3	20	68806	100	1468	1673	677753	750000
7	3	20	16434	99	1920	1466	729883	750000
8	2	20	9970	75	1866	0	738014	750000
9	2	20	738952	52	1372	0	9572	750000
10	3	20	602514	91	1800	1687	143726	750000
11	2	20	394263	77	1191	0	354392	750000
12	3	20	222513	61	1845	1264	524195	750000
13	1	20	383466	60	0	0	366474	750000
14	2	20	626009	92	1679	0	122128	750000
15	1	20	572644	52	0	0	177304	750000
16	3	20	485005	68	1680	1758	261353	750000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 134 of 177

Type 5 #19 5563 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	12	541563	64	1912	0	87975	631578
2	1	12	215659	51	0	0	415868	631578
3	1	12	394314	91	0	0	237173	631578
4	2	12	223466	71	1983	0	405987	631578
5	3	12	263687	88	1458	1927	364242	631578
6	1	12	392748	54	0	0	238776	631578
7	2	12	215526	90	1234	0	414638	631578
8	1	12	585163	56	0	0	46359	631578
9	1	12	16153	74	0	0	615351	631578
10	2	12	124604	63	1509	0	505339	631578
11	1	12	421774	64	0	0	209740	631578
12	3	12	284914	86	1654	1103	343649	631578
13	3	12	252335	75	1337	1763	375918	631578
14	1	12	22897	77	0	0	608604	631578
15	3	12	591483	65	1344	1352	37204	631578
16	3	12	580455	61	1734	1034	48172	631578
17	2	12	516566	99	1038	0	113776	631578
18	3	12	198515	52	1527	1126	430254	631578
19	3	12	484139	61	1432	1846	143978	631578

Type 5 #20 5566 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	5	520919	88	1939	0	334108	857142
2	3	5	684418	92	1419	1369	169660	857142
3	3	5	498352	57	1375	1725	355519	857142
4	1	5	781112	75	0	0	75955	857142
5	2	5	535638	100	1666	0	319638	857142
6	1	5	93262	58	0	0	763822	857142
7	2	5	507463	96	1431	0	348056	857142
8	1	5	292830	62	0	0	564250	857142
9	1	5	745765	85	0	0	111292	857142
10	2	5	402646	94	1301	0	453007	857142
11	3	5	854370	58	1042	1347	209	857142
12	1	5	234256	89	0	0	622797	857142
13	1	5	564691	100	0	0	292351	857142
14	3	5	738236	63	1347	1879	115491	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 135 of 177

Type 5 #21 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	16	866802	90	0	0	333108	1200000
2	2	16	748581	90	1826	0	449413	1200000
3	1	16	331161	65	0	0	868774	1200000
4	3	16	1170495	72	1156	1813	26320	1200000
5	1	16	49671	68	0	0	1150261	1200000
6	3	16	495991	80	1999	1000	700770	1200000
7	3	16	1177452	77	1797	1828	18692	1200000
8	1	16	144224	97	0	0	1055679	1200000
9	2	16	567182	75	1634	0	631034	1200000
10	2	16	73017	59	1071	0	1125794	1200000

Type 5 #22 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	7	114064	87	1752	0	884010	1000000
2	2	7	938056	90	1017	0	60747	1000000
3	2	7	698049	76	1239	0	300560	1000000
4	1	7	401747	61	0	0	598192	1000000
5	2	7	568161	77	1724	0	429961	1000000
6	1	7	803748	71	0	0	196181	1000000
7	3	7	654246	86	1717	1627	342152	1000000
8	1	7	483859	62	0	0	516079	1000000
9	3	7	156400	74	1701	1481	840196	1000000
10	3	7	832025	56	1956	1421	164430	1000000
11	2	7	626887	60	1518	0	371475	1000000
12	2	7	701312	66	1183	0	297373	1000000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 136 of 177

Type 5 #23 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	8	468019	54	0	0	731927	1200000
2	2	8	1112173	89	1741	0	85908	1200000
3	3	8	1165094	53	1024	1267	32456	1200000
4	2	8	269153	75	1302	0	929395	1200000
5	2	8	745021	55	1519	0	453350	1200000
6	3	8	859155	63	1140	1242	338274	1200000
7	1	8	986848	74	0	0	213078	1200000
8	1	8	55732	69	0	0	1144199	1200000
9	1	8	709810	87	0	0	490103	1200000
10	1	8	57632	78	0	0	1142290	1200000

Type 5 #24 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	15	693998	50	1719	0	504183	1200000
2	2	15	719599	89	1525	0	478698	1200000
3	2	15	662797	58	1073	0	536014	1200000
4	1	15	101132	96	0	0	1098772	1200000
5	2	15	117645	63	1854	0	1080375	1200000
6	2	15	1056811	71	1466	0	141581	1200000
7	3	15	1023738	89	1998	1542	172455	1200000
8	2	15	981836	61	1918	0	216124	1200000
9	1	15	171273	76	0	0	1028651	1200000
10	3	15	858744	71	1030	1711	338302	1200000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 137 of 177

Type 5 #25 5497 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	114991	76	1621	0	589118	705882
2	1	11	482185	88	0	0	223609	705882
3	3	11	58543	79	1630	1038	644434	705882
4	1	11	187816	100	0	0	517966	705882
5	1	11	239945	87	0	0	465850	705882
6	1	11	533728	55	0	0	172099	705882
7	3	11	566974	58	1287	1332	136115	705882
8	2	11	374975	67	1948	0	328825	705882
9	1	11	621209	87	0	0	84586	705882
10	3	11	503163	65	1263	1790	199471	705882
11	3	11	369888	80	1539	1965	332250	705882
12	3	11	548007	60	1182	1357	155156	705882
13	2	11	351037	91	1479	0	353184	705882
14	3	11	365152	92	1430	1645	337379	705882
15	2	11	604056	58	1535	0	100175	705882
16	2	11	277983	51	1000	0	426797	705882
17	1	11	529123	99	0	0	176660	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 138 of 177

Type 5 #26 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	7	427657	62	1245	1519	200971	631578
2	2	7	608303	74	1816	0	21311	631578
3	2	7	46676	53	1846	0	582950	631578
4	3	7	97862	68	1813	1837	529862	631578
5	2	7	542796	99	1384	0	87200	631578
6	3	7	323344	82	1129	1791	305068	631578
7	2	7	414883	68	1280	0	215279	631578
8	1	7	595500	51	0	0	36027	631578
9	1	7	526771	74	0	0	104733	631578
10	3	7	367664	55	1479	1674	260596	631578
11	2	7	557104	54	1360	0	73006	631578
12	1	7	518103	56	0	0	113419	631578
13	2	7	263490	92	1686	0	366218	631578
14	1	7	508072	79	0	0	123427	631578
15	3	7	531855	56	1220	1779	96556	631578
16	3	7	468154	95	1631	1552	159956	631578
17	2	7	50743	99	1550	0	579087	631578
18	2	7	600896	57	1760	0	28808	631578
19	2	7	67758	51	1215	0	562503	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 139 of 177

Type 5 #27 5497 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	11	242021	84	1820	0	422657	666666
2	3	11	423496	85	1516	1666	239733	666666
3	2	11	573705	89	1075	0	91708	666666
4	1	11	410920	77	0	0	255669	666666
5	2	11	406152	86	1404	0	258938	666666
6	1	11	492527	78	0	0	174061	666666
7	2	11	613399	57	1703	0	51450	666666
8	1	11	67901	88	0	0	598677	666666
9	3	11	266848	70	1732	1623	396253	666666
10	1	11	93240	97	0	0	573329	666666
11	3	11	112549	62	1390	1200	551341	666666
12	3	11	118653	97	1272	1918	544532	666666
13	1	11	165442	65	0	0	501159	666666
14	3	11	187408	97	1816	1862	475289	666666
15	3	11	537049	51	1689	1944	125831	666666
16	2	11	620717	50	1587	0	44262	666666
17	2	11	633770	74	1491	0	31257	666666
18	1	11	118843	80	0	0	547743	666666

Type 5 #28 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	9	285861	93	1847	0	462106	750000
2	1	9	487025	70	0	0	262905	750000
3	2	9	214567	68	1512	0	533785	750000
4	1	9	249001	65	0	0	500934	750000
5	1	9	616411	62	0	0	133527	750000
6	1	9	619061	61	0	0	130878	750000
7	1	9	595463	96	0	0	154441	750000
8	2	9	334736	89	1023	0	414063	750000
9	3	9	403380	89	1445	1205	343703	750000
10	1	9	505221	92	0	0	244687	750000
11	2	9	655955	73	1312	0	92587	750000
12	1	9	313720	96	0	0	436184	750000
13	2	9	497715	81	1557	0	250566	750000
14	2	9	641941	96	1480	0	106387	750000
15	1	9	732629	79	0	0	17292	750000
16	3	9	466357	60	1528	1825	280110	750000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 140 of 177

Type 5 #29 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	13	919362	68	1905	0	78597	1000000
2	2	13	101158	79	1679	0	897005	1000000
3	3	13	638381	70	1148	1782	358479	1000000
4	1	13	888912	95	0	0	110993	1000000
5	1	13	472901	98	0	0	527001	1000000
6	2	13	468763	67	1395	0	529708	1000000
7	3	13	209436	56	1624	1222	787550	1000000
8	1	13	453387	50	0	0	546563	1000000
9	1	13	884487	75	0	0	115438	1000000
10	3	13	478208	50	1793	1380	518469	1000000
11	3	13	459387	83	1557	1023	537784	1000000
12	2	13	574057	94	1433	0	424322	1000000

Type 5 #30 5530 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	20	361619	59	0	0	269900	631578
2	2	20	433323	82	1703	0	196388	631578
3	2	20	291553	59	1067	0	338840	631578
4	3	20	37312	99	1351	1298	591320	631578
5	2	20	446155	80	1775	0	183488	631578
6	1	20	556491	79	0	0	75008	631578
7	1	20	624552	85	0	0	6941	631578
8	3	20	18466	91	1609	1311	609919	631578
9	2	20	35520	98	1125	0	594737	631578
10	1	20	614579	72	0	0	16927	631578
11	3	20	527284	80	1826	1495	100733	631578
12	2	20	546139	80	1410	0	83869	631578
13	1	20	350058	53	0	0	281467	631578
14	2	20	448170	85	1487	0	181751	631578
15	2	20	169580	59	1655	0	460225	631578
16	1	20	167132	55	0	0	464391	631578
17	3	20	47475	67	1271	1064	581567	631578
18	1	20	612891	64	0	0	18623	631578
19	1	20	125867	75	0	0	505636	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 141 of 177

Type 6 #1 [Back to Summary]

#01-5286	#02-5395	#03-5589	#04-5340	#05-5692	#06-5565	#07-5612	#08-5288	#09-5558	#10-5721
#11-5398	#12-5673	#13-5599	#14-5593	#15-5655	#16-5616	#17-5511	#18-5303	#19-5719	#20-5331
#21-5313	#22-5557	#23-5315	#24-5381	#25-5400	#26-5697	#27-5440	#28-5332	#29-5667	#30-5482
#31-5600	#32-5518	#33-5327	#34-5366	#35-5700	#36-5598	#37-5687	#38-5383	#39-5678	#40-5432
#41-5561	#42-5714	#43-5306	#44-5415	#45-5268	#46-5698	#47-5378	#48-5330	#49-5396	#50-5346
#51-5441	#52-5424	#53-5453	#54-5457	#55-5664	#56-5720	#57-5375	#58-5530	#59-5325	#60-5370
#61-5604	#62-5596	#63-5483	#64-5617	#65-5307	#66-5653	#67-5350	#68-5536	#69-5495	#70-5323
#71-5723	#72-5258	#73-5300	#74-5710	#75-5467	#76-5679	#77-5587	#78-5336	#79-5504	#80-5494
#81-5666	#82-5496	#83-5517	#84-5479	#85-5443	#86-5682	#87-5281	#88-5618	#89-5661	#90-5451
#91-5543	#92-5510	#93-5320	#94-5401	#95-5629	#96-5455	#97-5322	#98-5407	#99-5291	#100-5633

Type 6 #2 [Back to Summary]

#01-5576	#02-5483	#03-5714	#04-5590	#05-5526	#06-5352	#07-5541	#08-5371	#09-5514	#10-5424
#11-5659	#12-5392	#13-5479	#14-5463	#15-5430	#16-5490	#17-5322	#18-5573	#19-5416	#20-5417
#21-5386	#22-5608	#23-5436	#24-5317	#25-5509	#26-5423	#27-5565	#28-5291	#29-5445	#30-5488
#31-5641	#32-5399	#33-5384	#34-5492	#35-5320	#36-5649	#37-5441	#38-5694	#39-5683	#40-5531
#41-5701	#42-5333	#43-5578	#44-5400	#45-5574	#46-5645	#47-5689	#48-5724	#49-5558	#50-5512
#51-5598	#52-5496	#53-5692	#54-5297	#55-5647	#56-5331	#57-5353	#58-5646	#59-5329	#60-5319
#61-5421	#62-5476	#63-5283	#64-5296	#65-5722	#66-5252	#67-5699	#68-5448	#69-5428	#70-5327
#71-5459	#72-5708	#73-5655	#74-5273	#75-5581	#76-5700	#77-5292	#78-5628	#79-5462	#80-5337
#81-5570	#82-5546	#83-5520	#84-5718	#85-5604	#86-5461	#87-5599	#88-5637	#89-5540	#90-5691
#91-5634	#92-5537	#93-5318	#94-5615	#95-5562	#96-5664	#97-5315	#98-5305	#99-5588	#100-5433

Type 6 #3 [Back to Summary]

#01-5426	#02-5546	#03-5683	#04-5402	#05-5262	#06-5352	#07-5429	#08-5455	#09-5548	#10-5590
#11-5584	#12-5320	#13-5553	#14-5678	#15-5290	#16-5296	#17-5361	#18-5448	#19-5579	#20-5413
#21-5616	#22-5560	#23-5571	#24-5500	#25-5630	#26-5564	#27-5467	#28-5454	#29-5662	#30-5601
#31-5587	#32-5261	#33-5442	#34-5643	#35-5618	#36-5719	#37-5640	#38-5538	#39-5709	#40-5531
#41-5357	#42-5670	#43-5494	#44-5275	#45-5702	#46-5593	#47-5376	#48-5274	#49-5259	#50-5400
#51-5258	#52-5282	#53-5542	#54-5591	#55-5700	#56-5433	#57-5496	#58-5423	#59-5610	#60-5699
#61-5518	#62-5672	#63-5252	#64-5573	#65-5602	#66-5635	#67-5309	#68-5381	#69-5547	#70-5463
#71-5298	#72-5305	#73-5671	#74-5315	#75-5545	#76-5522	#77-5286	#78-5717	#79-5341	#80-5430
#81-5652	#82-5710	#83-5436	#84-5253	#85-5410	#86-5351	#87-5277	#88-5268	#89-5456	#90-5291
#91-5536	#92-5646	#93-5382	#94-5401	#95-5272	#96-5379	#97-5716	#98-5660	#99-5316	#100-5603

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 142 of 177

Type 6 #4 [Back to Summary]									
#01-5318	#02-5662	#03-5684	#04-5702	#05-5595	#06-5525	#07-5404	#08-5636	#09-5459	#10-5431
#11-5519	#12-5590	#13-5686	#14-5541	#15-5570	#16-5442	#17-5534	#18-5282	#19-5278	#20-5649
#21-5505	#22-5652	#23-5377	#24-5647	#25-5493	#26-5523	#27-5393	#28-5295	#29-5306	#30-5274
#31-5452	#32-5299	#33-5641	#34-5499	#35-5293	#36-5433	#37-5480	#38-5476	#39-5589	#40-5545
#41-5557	#42-5354	#43-5376	#44-5588	#45-5536	#46-5585	#47-5456	#48-5284	#49-5674	#50-5678
#51-5538	#52-5260	#53-5305	#54-5325	#55-5281	#56-5605	#57-5492	#58-5414	#59-5374	#60-5494
#61-5316	#62-5540	#63-5291	#64-5526	#65-5259	#66-5303	#67-5530	#68-5673	#69-5547	#70-5250
#71-5308	#72-5708	#73-5633	#74-5317	#75-5584	#76-5497	#77-5655	#78-5715	#79-5503	#80-5346
#81-5353	#82-5489	#83-5460	#84-5378	#85-5405	#86-5445	#87-5302	#88-5392	#89-5705	#90-5606
#91-5521	#92-5720	#93-5257	#94-5514	#95-5323	#96-5479	#97-5510	#98-5573	#99-5437	#100-5721

Type 6 #5 [Back to Summary]									
#01-5342	#02-5373	#03-5538	#04-5633	#05-5641	#06-5444	#07-5504	#08-5666	#09-5527	#10-5315
#11-5605	#12-5623	#13-5334	#14-5430	#15-5302	#16-5530	#17-5566	#18-5368	#19-5512	#20-5712
#21-5343	#22-5627	#23-5577	#24-5707	#25-5581	#26-5485	#27-5717	#28-5497	#29-5488	#30-5301
#31-5628	#32-5381	#33-5313	#34-5321	#35-5419	#36-5394	#37-5475	#38-5511	#39-5351	#40-5525
#41-5598	#42-5612	#43-5425	#44-5329	#45-5521	#46-5309	#47-5595	#48-5438	#49-5459	#50-5354
#51-5280	#52-5636	#53-5306	#54-5659	#55-5587	#56-5269	#57-5546	#58-5672	#59-5428	#60-5412
#61-5474	#62-5559	#63-5262	#64-5261	#65-5632	#66-5304	#67-5305	#68-5267	#69-5529	#70-5436
#71-5469	#72-5264	#73-5635	#74-5324	#75-5406	#76-5341	#77-5637	#78-5700	#79-5431	#80-5439
#81-5647	#82-5683	#83-5291	#84-5508	#85-5337	#86-5541	#87-5648	#88-5332	#89-5411	#90-5578
#91-5420	#92-5387	#93-5503	#94-5409	#95-5590	#96-5317	#97-5613	#98-5254	#99-5540	#100-5421

Type 6 #6 [Back to Summary]									
#01-5654	#02-5642	#03-5535	#04-5621	#05-5395	#06-5585	#07-5430	#08-5652	#09-5633	#10-5697
#11-5724	#12-5294	#13-5551	#14-5601	#15-5696	#16-5478	#17-5544	#18-5487	#19-5382	#20-5659
#21-5368	#22-5583	#23-5299	#24-5602	#25-5381	#26-5639	#27-5541	#28-5685	#29-5569	#30-5336
#31-5423	#32-5615	#33-5268	#34-5718	#35-5290	#36-5481	#37-5612	#38-5667	#39-5681	#40-5467
#41-5405	#42-5502	#43-5605	#44-5420	#45-5343	#46-5531	#47-5713	#48-5410	#49-5564	#50-5319
#51-5491	#52-5407	#53-5486	#54-5536	#55-5308	#56-5263	#57-5670	#58-5613	#59-5692	#60-5313
#61-5610	#62-5550	#63-5403	#64-5679	#65-5558	#66-5560	#67-5465	#68-5591	#69-5504	#70-5590
#71-5702	#72-5604	#73-5509	#74-5575	#75-5306	#76-5553	#77-5525	#78-5255	#79-5267	#80-5656
#81-5458	#82-5506	#83-5431	#84-5706	#85-5720	#86-5593	#87-5653	#88-5260	#89-5579	#90-5438
#91-5439	#92-5594	#93-5665	#94-5577	#95-5274	#96-5402	#97-5698	#98-5441	#99-5493	#100-5707

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 143 of 177

Type 6 #7 [Back to Summary]									
#01-5671	#02-5331	#03-5607	#04-5484	#05-5413	#06-5614	#07-5310	#08-5416	#09-5308	#10-5593
#11-5618	#12-5670	#13-5422	#14-5376	#15-5579	#16-5470	#17-5722	#18-5674	#19-5520	#20-5316
#21-5400	#22-5707	#23-5259	#24-5568	#25-5723	#26-5281	#27-5580	#28-5550	#29-5696	#30-5689
#31-5523	#32-5485	#33-5625	#34-5362	#35-5358	#36-5490	#37-5371	#38-5518	#39-5271	#40-5381
#41-5700	#42-5720	#43-5404	#44-5623	#45-5548	#46-5450	#47-5492	#48-5414	#49-5433	#50-5641
#51-5348	#52-5597	#53-5640	#54-5582	#55-5635	#56-5561	#57-5276	#58-5292	#59-5647	#60-5705
#61-5616	#62-5678	#63-5357	#64-5613	#65-5434	#66-5399	#67-5516	#68-5295	#69-5269	#70-5581
#71-5283	#72-5573	#73-5569	#74-5383	#75-5576	#76-5380	#77-5305	#78-5532	#79-5505	#80-5690
#81-5527	#82-5442	#83-5325	#84-5514	#85-5354	#86-5333	#87-5303	#88-5264	#89-5256	#90-5595
#91-5342	#92-5337	#93-5596	#94-5501	#95-5491	#96-5564	#97-5317	#98-5570	#99-5448	#100-5309

Type 6 #8 [Back to Summary]									
#01-5431	#02-5695	#03-5709	#04-5365	#05-5449	#06-5266	#07-5651	#08-5401	#09-5591	#10-5420
#11-5358	#12-5610	#13-5634	#14-5585	#15-5639	#16-5497	#17-5704	#18-5559	#19-5313	#20-5376
#21-5706	#22-5287	#23-5693	#24-5250	#25-5517	#26-5589	#27-5260	#28-5439	#29-5285	#30-5375
#31-5479	#32-5315	#33-5548	#34-5252	#35-5384	#36-5349	#37-5663	#38-5539	#39-5489	#40-5330
#41-5444	#42-5476	#43-5641	#44-5674	#45-5379	#46-5257	#47-5586	#48-5719	#49-5584	#50-5482
#51-5507	#52-5322	#53-5327	#54-5394	#55-5708	#56-5572	#57-5255	#58-5462	#59-5665	#60-5295
#61-5604	#62-5544	#63-5336	#64-5582	#65-5505	#66-5398	#67-5291	#68-5269	#69-5512	#70-5535
#71-5302	#72-5301	#73-5387	#74-5724	#75-5577	#76-5317	#77-5618	#78-5697	#79-5718	#80-5470
#81-5583	#82-5381	#83-5340	#84-5679	#85-5483	#86-5593	#87-5328	#88-5595	#89-5319	#90-5645
#91-5403	#92-5571	#93-5542	#94-5463	#95-5683	#96-5276	#97-5540	#98-5657	#99-5435	#100-5253

Type 6 #9 [Back to Summary]									
#01-5256	#02-5609	#03-5324	#04-5598	#05-5401	#06-5631	#07-5551	#08-5590	#09-5724	#10-5373
#11-5282	#12-5675	#13-5315	#14-5427	#15-5434	#16-5431	#17-5706	#18-5552	#19-5661	#20-5571
#21-5496	#22-5444	#23-5499	#24-5405	#25-5264	#26-5691	#27-5655	#28-5432	#29-5433	#30-5629
#31-5477	#32-5709	#33-5253	#34-5662	#35-5413	#36-5257	#37-5305	#38-5403	#39-5682	#40-5538
#41-5591	#42-5397	#43-5617	#44-5573	#45-5356	#46-5583	#47-5493	#48-5607	#49-5317	#50-5409
#51-5363	#52-5604	#53-5348	#54-5721	#55-5585	#56-5660	#57-5250	#58-5666	#59-5574	#60-5296
#61-5364	#62-5563	#63-5443	#64-5430	#65-5312	#66-5712	#67-5543	#68-5544	#69-5605	#70-5418
#71-5539	#72-5632	#73-5371	#74-5367	#75-5548	#76-5390	#77-5664	#78-5482	#79-5272	#80-5608
#81-5596	#82-5447	#83-5520	#84-5370	#85-5265	#86-5689	#87-5545	#88-5304	#89-5380	#90-5650
#91-5521	#92-5505	#93-5382	#94-5436	#95-5716	#96-5698	#97-5441	#98-5714	#99-5467	#100-5361

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 144 of 177

Type 6 #10 [Back to Summary]									
#01-5584	#02-5252	#03-5342	#04-5273	#05-5481	#06-5495	#07-5572	#08-5306	#09-5473	#10-5515
#11-5272	#12-5397	#13-5485	#14-5264	#15-5523	#16-5667	#17-5336	#18-5700	#19-5316	#20-5712
#21-5623	#22-5594	#23-5408	#24-5349	#25-5684	#26-5422	#27-5325	#28-5297	#29-5400	#30-5372
#31-5458	#32-5274	#33-5655	#34-5258	#35-5544	#36-5263	#37-5596	#38-5521	#39-5526	#40-5533
#41-5593	#42-5298	#43-5715	#44-5359	#45-5640	#46-5676	#47-5702	#48-5275	#49-5281	#50-5354
#51-5429	#52-5479	#53-5463	#54-5569	#55-5717	#56-5314	#57-5309	#58-5420	#59-5525	#60-5631
#61-5350	#62-5307	#63-5723	#64-5466	#65-5476	#66-5445	#67-5510	#68-5320	#69-5540	#70-5423
#71-5508	#72-5428	#73-5279	#74-5545	#75-5418	#76-5714	#77-5293	#78-5470	#79-5348	#80-5271
#81-5369	#82-5268	#83-5444	#84-5425	#85-5520	#86-5554	#87-5419	#88-5603	#89-5457	#90-5467
#91-5363	#92-5687	#93-5672	#94-5657	#95-5361	#96-5424	#97-5449	#98-5506	#99-5490	#100-5685

Type 6 #11 [Back to Summary]									
#01-5539	#02-5565	#03-5646	#04-5301	#05-5433	#06-5419	#07-5400	#08-5253	#09-5270	#10-5563
#11-5322	#12-5503	#13-5512	#14-5332	#15-5588	#16-5403	#17-5290	#18-5680	#19-5616	#20-5340
#21-5442	#22-5681	#23-5395	#24-5420	#25-5316	#26-5598	#27-5485	#28-5602	#29-5594	#30-5271
#31-5566	#32-5506	#33-5408	#34-5454	#35-5603	#36-5648	#37-5374	#38-5336	#39-5385	#40-5268
#41-5600	#42-5436	#43-5629	#44-5291	#45-5480	#46-5425	#47-5590	#48-5319	#49-5683	#50-5383
#51-5494	#52-5615	#53-5399	#54-5493	#55-5456	#56-5608	#57-5501	#58-5605	#59-5367	#60-5545
#61-5640	#62-5375	#63-5401	#64-5541	#65-5721	#66-5353	#67-5709	#68-5479	#69-5641	#70-5593
#71-5567	#72-5621	#73-5302	#74-5665	#75-5258	#76-5415	#77-5644	#78-5461	#79-5502	#80-5675
#81-5356	#82-5722	#83-5720	#84-5397	#85-5694	#86-5564	#87-5352	#88-5474	#89-5285	#90-5337
#91-5535	#92-5483	#93-5321	#94-5711	#95-5335	#96-5453	#97-5466	#98-5625	#99-5384	#100-5327

Type 6 #12 [Back to Summary]									
#01-5651	#02-5560	#03-5556	#04-5397	#05-5665	#06-5475	#07-5537	#08-5455	#09-5289	#10-5529
#11-5614	#12-5437	#13-5605	#14-5714	#15-5332	#16-5623	#17-5641	#18-5694	#19-5342	#20-5585
#21-5690	#22-5543	#23-5431	#24-5544	#25-5271	#26-5329	#27-5441	#28-5719	#29-5602	#30-5540
#31-5279	#32-5412	#33-5413	#34-5250	#35-5553	#36-5468	#37-5277	#38-5268	#39-5345	#40-5297
#41-5255	#42-5593	#43-5609	#44-5356	#45-5346	#46-5370	#47-5319	#48-5251	#49-5358	#50-5558
#51-5699	#52-5591	#53-5578	#54-5483	#55-5656	#56-5516	#57-5395	#58-5264	#59-5670	#60-5713
#61-5448	#62-5443	#63-5550	#64-5331	#65-5568	#66-5404	#67-5341	#68-5324	#69-5490	#70-5642
#71-5563	#72-5660	#73-5639	#74-5708	#75-5320	#76-5649	#77-5600	#78-5322	#79-5645	#80-5405
#81-5547	#82-5396	#83-5485	#84-5457	#85-5254	#86-5399	#87-5610	#88-5266	#89-5257	#90-5410
#91-5637	#92-5520	#93-5476	#94-5571	#95-5267	#96-5484	#97-5458	#98-5673	#99-5291	#100-5644

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 145 of 177

Type 6 #13 [Back to Summary]									
#01-5720	#02-5601	#03-5412	#04-5668	#05-5271	#06-5536	#07-5641	#08-5665	#09-5292	#10-5256
#11-5252	#12-5660	#13-5497	#14-5592	#15-5378	#16-5609	#17-5319	#18-5341	#19-5281	#20-5520
#21-5555	#22-5499	#23-5437	#24-5423	#25-5278	#26-5468	#27-5627	#28-5646	#29-5703	#30-5598
#31-5355	#32-5400	#33-5541	#34-5295	#35-5310	#36-5323	#37-5350	#38-5317	#39-5367	#40-5631
#41-5518	#42-5353	#43-5704	#44-5450	#45-5383	#46-5414	#47-5642	#48-5495	#49-5339	#50-5470
#51-5599	#52-5699	#53-5637	#54-5572	#55-5508	#56-5422	#57-5287	#58-5371	#59-5277	#60-5379
#61-5554	#62-5346	#63-5300	#64-5493	#65-5563	#66-5259	#67-5687	#68-5683	#69-5419	#70-5488
#71-5382	#72-5345	#73-5644	#74-5652	#75-5444	#76-5299	#77-5268	#78-5494	#79-5481	#80-5586
#81-5681	#82-5585	#83-5311	#84-5320	#85-5260	#86-5397	#87-5530	#88-5540	#89-5653	#90-5279
#91-5721	#92-5604	#93-5388	#94-5523	#95-5606	#96-5544	#97-5404	#98-5684	#99-5325	#100-5575

Type 6 #14 [Back to Summary]									
#01-5338	#02-5503	#03-5305	#04-5709	#05-5378	#06-5458	#07-5404	#08-5518	#09-5614	#10-5416
#11-5422	#12-5694	#13-5285	#14-5704	#15-5483	#16-5493	#17-5586	#18-5407	#19-5392	#20-5491
#21-5459	#22-5385	#23-5466	#24-5505	#25-5379	#26-5563	#27-5370	#28-5311	#29-5675	#30-5326
#31-5431	#32-5722	#33-5509	#34-5461	#35-5707	#36-5482	#37-5265	#38-5413	#39-5402	#40-5332
#41-5498	#42-5486	#43-5356	#44-5437	#45-5690	#46-5554	#47-5571	#48-5674	#49-5448	#50-5301
#51-5542	#52-5541	#53-5558	#54-5366	#55-5677	#56-5286	#57-5524	#58-5580	#59-5539	#60-5337
#61-5342	#62-5568	#63-5538	#64-5710	#65-5425	#66-5434	#67-5548	#68-5251	#69-5477	#70-5423
#71-5255	#72-5310	#73-5718	#74-5697	#75-5279	#76-5278	#77-5549	#78-5716	#79-5421	#80-5588
#81-5623	#82-5508	#83-5430	#84-5676	#85-5345	#86-5445	#87-5557	#88-5587	#89-5719	#90-5405
#91-5643	#92-5543	#93-5452	#94-5515	#95-5369	#96-5272	#97-5446	#98-5481	#99-5565	#100-5393

Type 6 #15 [Back to Summary]									
#01-5648	#02-5257	#03-5709	#04-5280	#05-5547	#06-5641	#07-5479	#08-5669	#09-5279	#10-5525
#11-5720	#12-5483	#13-5453	#14-5692	#15-5531	#16-5261	#17-5591	#18-5392	#19-5315	#20-5562
#21-5304	#22-5460	#23-5551	#24-5274	#25-5430	#26-5694	#27-5468	#28-5391	#29-5324	#30-5389
#31-5442	#32-5673	#33-5360	#34-5676	#35-5355	#36-5437	#37-5481	#38-5526	#39-5289	#40-5327
#41-5651	#42-5698	#43-5514	#44-5519	#45-5611	#46-5544	#47-5640	#48-5537	#49-5502	#50-5573
#51-5415	#52-5253	#53-5339	#54-5431	#55-5684	#56-5575	#57-5578	#58-5422	#59-5338	#60-5594
#61-5614	#62-5333	#63-5296	#64-5372	#65-5501	#66-5587	#67-5343	#68-5504	#69-5314	#70-5353
#71-5713	#72-5636	#73-5330	#74-5671	#75-5624	#76-5480	#77-5400	#78-5484	#79-5475	#80-5511
#81-5593	#82-5508	#83-5357	#84-5642	#85-5255	#86-5521	#87-5435	#88-5630	#89-5354	#90-5567
#91-5472	#92-5488	#93-5292	#94-5283	#95-5438	#96-5470	#97-5427	#98-5342	#99-5258	#100-5491

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 146 of 177

Type 6 #16 [Back to Summary]									
#01-5531	#02-5454	#03-5281	#04-5428	#05-5662	#06-5587	#07-5332	#08-5252	#09-5465	#10-5513
#11-5265	#12-5638	#13-5669	#14-5338	#15-5708	#16-5362	#17-5642	#18-5323	#19-5701	#20-5297
#21-5307	#22-5257	#23-5305	#24-5357	#25-5653	#26-5478	#27-5423	#28-5372	#29-5330	#30-5579
#31-5401	#32-5448	#33-5316	#34-5645	#35-5692	#36-5699	#37-5271	#38-5621	#39-5352	#40-5684
#41-5473	#42-5379	#43-5427	#44-5458	#45-5299	#46-5325	#47-5552	#48-5344	#49-5268	#50-5282
#51-5444	#52-5474	#53-5447	#54-5700	#55-5321	#56-5550	#57-5659	#58-5578	#59-5554	#60-5342
#61-5432	#62-5724	#63-5309	#64-5518	#65-5614	#66-5641	#67-5442	#68-5635	#69-5365	#70-5348
#71-5680	#72-5400	#73-5679	#74-5557	#75-5703	#76-5660	#77-5347	#78-5544	#79-5710	#80-5721
#81-5546	#82-5682	#83-5594	#84-5670	#85-5392	#86-5290	#87-5417	#88-5317	#89-5259	#90-5501
#91-5319	#92-5634	#93-5569	#94-5383	#95-5608	#96-5704	#97-5327	#98-5293	#99-5519	#100-5393

Type 6 #17 [Back to Summary]									
#01-5343	#02-5614	#03-5465	#04-5400	#05-5456	#06-5522	#07-5446	#08-5253	#09-5487	#10-5561
#11-5640	#12-5296	#13-5497	#14-5699	#15-5698	#16-5308	#17-5512	#18-5333	#19-5669	#20-5520
#21-5633	#22-5276	#23-5599	#24-5295	#25-5464	#26-5627	#27-5256	#28-5326	#29-5469	#30-5638
#31-5429	#32-5443	#33-5526	#34-5567	#35-5502	#36-5550	#37-5267	#38-5585	#39-5462	#40-5305
#41-5470	#42-5557	#43-5323	#44-5654	#45-5336	#46-5360	#47-5667	#48-5255	#49-5586	#50-5539
#51-5685	#52-5574	#53-5604	#54-5309	#55-5435	#56-5588	#57-5590	#58-5354	#59-5717	#60-5620
#61-5439	#62-5651	#63-5268	#64-5647	#65-5460	#66-5578	#67-5695	#68-5381	#69-5483	#70-5495
#71-5472	#72-5457	#73-5587	#74-5325	#75-5678	#76-5670	#77-5683	#78-5353	#79-5684	#80-5251
#81-5655	#82-5677	#83-5579	#84-5564	#85-5467	#86-5382	#87-5637	#88-5592	#89-5544	#90-5390
#91-5535	#92-5534	#93-5293	#94-5463	#95-5367	#96-5388	#97-5447	#98-5359	#99-5635	#100-5644

Type 6 #18 [Back to Summary]									
#01-5396	#02-5613	#03-5660	#04-5438	#05-5437	#06-5337	#07-5695	#08-5606	#09-5263	#10-5478
#11-5724	#12-5533	#13-5523	#14-5583	#15-5604	#16-5615	#17-5600	#18-5293	#19-5511	#20-5527
#21-5477	#22-5449	#23-5688	#24-5398	#25-5442	#26-5360	#27-5611	#28-5464	#29-5462	#30-5425
#31-5270	#32-5273	#33-5252	#34-5290	#35-5490	#36-5703	#37-5631	#38-5401	#39-5357	#40-5451
#41-5430	#42-5562	#43-5470	#44-5637	#45-5536	#46-5250	#47-5555	#48-5435	#49-5476	#50-5513
#51-5403	#52-5572	#53-5358	#54-5417	#55-5672	#56-5650	#57-5721	#58-5326	#59-5480	#60-5394
#61-5457	#62-5701	#63-5530	#64-5483	#65-5342	#66-5626	#67-5708	#68-5448	#69-5661	#70-5310
#71-5347	#72-5640	#73-5704	#74-5301	#75-5587	#76-5441	#77-5426	#78-5710	#79-5591	#80-5619
#81-5597	#82-5543	#83-5303	#84-5370	#85-5405	#86-5280	#87-5674	#88-5632	#89-5429	#90-5560
#91-5445	#92-5321	#93-5681	#94-5492	#95-5314	#96-5467	#97-5260	#98-5502	#99-5693	#100-5599

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 147 of 177

Type 6 #19 [Back to Summary]									
#01-5649	#02-5529	#03-5520	#04-5274	#05-5598	#06-5408	#07-5650	#08-5591	#09-5525	#10-5636
#11-5610	#12-5524	#13-5572	#14-5588	#15-5293	#16-5630	#17-5310	#18-5397	#19-5472	#20-5321
#21-5596	#22-5276	#23-5721	#24-5458	#25-5334	#26-5468	#27-5373	#28-5639	#29-5608	#30-5345
#31-5575	#32-5429	#33-5445	#34-5600	#35-5485	#36-5700	#37-5325	#38-5259	#39-5706	#40-5562
#41-5285	#42-5534	#43-5436	#44-5542	#45-5359	#46-5628	#47-5270	#48-5451	#49-5280	#50-5621
#51-5252	#52-5622	#53-5533	#54-5311	#55-5665	#56-5674	#57-5328	#58-5467	#59-5277	#60-5514
#61-5393	#62-5418	#63-5395	#64-5335	#65-5463	#66-5340	#67-5283	#68-5716	#69-5437	#70-5272
#71-5517	#72-5540	#73-5564	#74-5551	#75-5536	#76-5269	#77-5315	#78-5678	#79-5426	#80-5547
#81-5316	#82-5424	#83-5284	#84-5376	#85-5319	#86-5399	#87-5506	#88-5647	#89-5592	#90-5690
#91-5577	#92-5417	#93-5365	#94-5530	#95-5693	#96-5631	#97-5346	#98-5289	#99-5398	#100-5384

Type 6 #20 [Back to Summary]									
#01-5350	#02-5501	#03-5655	#04-5422	#05-5257	#06-5449	#07-5720	#08-5692	#09-5570	#10-5351
#11-5695	#12-5300	#13-5669	#14-5393	#15-5437	#16-5663	#17-5566	#18-5649	#19-5574	#20-5329
#21-5698	#22-5369	#23-5322	#24-5477	#25-5498	#26-5398	#27-5457	#28-5641	#29-5384	#30-5611
#31-5717	#32-5694	#33-5376	#34-5414	#35-5701	#36-5448	#37-5597	#38-5723	#39-5640	#40-5476
#41-5446	#42-5315	#43-5572	#44-5343	#45-5280	#46-5314	#47-5415	#48-5473	#49-5534	#50-5271
#51-5527	#52-5535	#53-5505	#54-5675	#55-5484	#56-5653	#57-5380	#58-5560	#59-5413	#60-5677
#61-5424	#62-5310	#63-5590	#64-5407	#65-5627	#66-5301	#67-5575	#68-5472	#69-5648	#70-5256
#71-5630	#72-5304	#73-5427	#74-5577	#75-5530	#76-5445	#77-5387	#78-5432	#79-5673	#80-5573
#81-5604	#82-5600	#83-5718	#84-5497	#85-5274	#86-5489	#87-5711	#88-5346	#89-5610	#90-5626
#91-5619	#92-5283	#93-5507	#94-5286	#95-5684	#96-5582	#97-5305	#98-5599	#99-5517	#100-5307

Type 6 #21 [Back to Summary]									
#01-5326	#02-5575	#03-5364	#04-5275	#05-5494	#06-5476	#07-5461	#08-5619	#09-5714	#10-5414
#11-5379	#12-5276	#13-5336	#14-5426	#15-5375	#16-5288	#17-5355	#18-5261	#19-5376	#20-5271
#21-5645	#22-5378	#23-5522	#24-5409	#25-5690	#26-5473	#27-5340	#28-5518	#29-5717	#30-5506
#31-5368	#32-5647	#33-5481	#34-5432	#35-5635	#36-5496	#37-5495	#38-5600	#39-5374	#40-5472
#41-5546	#42-5612	#43-5458	#44-5568	#45-5632	#46-5395	#47-5598	#48-5405	#49-5655	#50-5573
#51-5713	#52-5588	#53-5448	#54-5387	#55-5673	#56-5302	#57-5680	#58-5310	#59-5385	#60-5668
#61-5626	#62-5295	#63-5457	#64-5519	#65-5628	#66-5516	#67-5604	#68-5479	#69-5611	#70-5629
#71-5449	#72-5282	#73-5644	#74-5679	#75-5501	#76-5545	#77-5660	#78-5394	#79-5505	#80-5710
#81-5687	#82-5443	#83-5539	#84-5540	#85-5352	#86-5603	#87-5711	#88-5250	#89-5523	#90-5425
#91-5694	#92-5614	#93-5300	#94-5304	#95-5483	#96-5701	#97-5544	#98-5296	#99-5354	#100-5278

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 148 of 177

Type 6 #22 [Back to Summary]									
#01-5348	#02-5429	#03-5489	#04-5396	#05-5450	#06-5330	#07-5482	#08-5665	#09-5515	#10-5258
#11-5534	#12-5583	#13-5553	#14-5410	#15-5704	#16-5664	#17-5508	#18-5543	#19-5571	#20-5296
#21-5643	#22-5406	#23-5326	#24-5670	#25-5631	#26-5295	#27-5537	#28-5339	#29-5284	#30-5528
#31-5629	#32-5663	#33-5658	#34-5345	#35-5359	#36-5300	#37-5681	#38-5610	#39-5522	#40-5478
#41-5310	#42-5417	#43-5315	#44-5360	#45-5615	#46-5325	#47-5544	#48-5442	#49-5251	#50-5308
#51-5667	#52-5353	#53-5404	#54-5517	#55-5393	#56-5630	#57-5711	#58-5596	#59-5619	#60-5594
#61-5613	#62-5551	#63-5657	#64-5298	#65-5542	#66-5398	#67-5633	#68-5604	#69-5520	#70-5709
#71-5647	#72-5263	#73-5464	#74-5335	#75-5628	#76-5462	#77-5606	#78-5548	#79-5403	#80-5256
#81-5481	#82-5441	#83-5456	#84-5255	#85-5334	#86-5271	#87-5313	#88-5444	#89-5416	#90-5549
#91-5656	#92-5616	#93-5318	#94-5401	#95-5490	#96-5501	#97-5519	#98-5694	#99-5419	#100-5595

Type 6 #23 [Back to Summary]									
#01-5379	#02-5416	#03-5625	#04-5449	#05-5383	#06-5286	#07-5320	#08-5637	#09-5587	#10-5381
#11-5359	#12-5451	#13-5293	#14-5458	#15-5428	#16-5376	#17-5569	#18-5410	#19-5328	#20-5543
#21-5347	#22-5532	#23-5444	#24-5559	#25-5311	#26-5366	#27-5297	#28-5608	#29-5536	#30-5542
#31-5472	#32-5384	#33-5680	#34-5712	#35-5371	#36-5589	#37-5310	#38-5406	#39-5345	#40-5593
#41-5524	#42-5506	#43-5592	#44-5358	#45-5282	#46-5323	#47-5392	#48-5599	#49-5503	#50-5616
#51-5601	#52-5498	#53-5572	#54-5430	#55-5614	#56-5322	#57-5644	#58-5273	#59-5278	#60-5300
#61-5564	#62-5612	#63-5414	#64-5633	#65-5502	#66-5440	#67-5254	#68-5705	#69-5349	#70-5646
#71-5448	#72-5434	#73-5664	#74-5258	#75-5663	#76-5692	#77-5677	#78-5333	#79-5698	#80-5465
#81-5662	#82-5288	#83-5581	#84-5611	#85-5357	#86-5354	#87-5665	#88-5699	#89-5713	#90-5486
#91-5321	#92-5609	#93-5685	#94-5619	#95-5504	#96-5607	#97-5388	#98-5618	#99-5403	#100-5694

Type 6 #24 [Back to Summary]									
#01-5402	#02-5313	#03-5633	#04-5600	#05-5492	#06-5647	#07-5369	#08-5560	#09-5299	#10-5537
#11-5363	#12-5525	#13-5280	#14-5253	#15-5272	#16-5394	#17-5336	#18-5314	#19-5256	#20-5360
#21-5410	#22-5376	#23-5550	#24-5371	#25-5297	#26-5294	#27-5513	#28-5478	#29-5554	#30-5341
#31-5327	#32-5293	#33-5610	#34-5612	#35-5257	#36-5548	#37-5449	#38-5423	#39-5301	#40-5594
#41-5651	#42-5271	#43-5321	#44-5428	#45-5588	#46-5424	#47-5427	#48-5359	#49-5521	#50-5324
#51-5292	#52-5534	#53-5276	#54-5487	#55-5511	#56-5552	#57-5448	#58-5383	#59-5616	#60-5683
#61-5459	#62-5320	#63-5640	#64-5393	#65-5721	#66-5669	#67-5582	#68-5615	#69-5680	#70-5491
#71-5484	#72-5354	#73-5479	#74-5668	#75-5430	#76-5339	#77-5300	#78-5444	#79-5545	#80-5406
#81-5567	#82-5706	#83-5310	#84-5663	#85-5650	#86-5700	#87-5642	#88-5702	#89-5644	#90-5586
#91-5358	#92-5495	#93-5445	#94-5703	#95-5414	#96-5433	#97-5656	#98-5526	#99-5646	#100-5258

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 149 of 177

Type 6 #25 [Back to Summary]									
#01-5568	#02-5665	#03-5267	#04-5294	#05-5565	#06-5536	#07-5388	#08-5456	#09-5638	#10-5322
#11-5315	#12-5264	#13-5256	#14-5656	#15-5640	#16-5287	#17-5513	#18-5564	#19-5291	#20-5617
#21-5559	#22-5367	#23-5710	#24-5636	#25-5279	#26-5606	#27-5545	#28-5474	#29-5277	#30-5309
#31-5302	#32-5345	#33-5682	#34-5598	#35-5387	#36-5357	#37-5650	#38-5380	#39-5444	#40-5422
#41-5379	#42-5413	#43-5408	#44-5257	#45-5517	#46-5619	#47-5262	#48-5460	#49-5605	#50-5366
#51-5258	#52-5548	#53-5282	#54-5382	#55-5492	#56-5507	#57-5506	#58-5635	#59-5414	#60-5281
#61-5288	#62-5680	#63-5335	#64-5671	#65-5376	#66-5365	#67-5486	#68-5669	#69-5580	#70-5473
#71-5482	#72-5596	#73-5599	#74-5579	#75-5541	#76-5428	#77-5661	#78-5337	#79-5411	#80-5465
#81-5575	#82-5393	#83-5469	#84-5280	#85-5390	#86-5341	#87-5457	#88-5478	#89-5497	#90-5310
#91-5455	#92-5610	#93-5254	#94-5490	#95-5604	#96-5426	#97-5634	#98-5259	#99-5632	#100-5608

Type 6 #26 [Back to Summary]									
#01-5559	#02-5252	#03-5471	#04-5501	#05-5399	#06-5548	#07-5510	#08-5282	#09-5673	#10-5481
#11-5606	#12-5697	#13-5266	#14-5335	#15-5528	#16-5489	#17-5265	#18-5254	#19-5348	#20-5538
#21-5442	#22-5374	#23-5393	#24-5537	#25-5663	#26-5306	#27-5444	#28-5532	#29-5473	#30-5555
#31-5610	#32-5664	#33-5485	#34-5586	#35-5445	#36-5388	#37-5594	#38-5681	#39-5329	#40-5674
#41-5525	#42-5527	#43-5506	#44-5378	#45-5373	#46-5517	#47-5587	#48-5325	#49-5662	#50-5619
#51-5255	#52-5344	#53-5415	#54-5434	#55-5583	#56-5659	#57-5563	#58-5342	#59-5354	#60-5702
#61-5534	#62-5368	#63-5596	#64-5666	#65-5462	#66-5405	#67-5614	#68-5390	#69-5309	#70-5649
#71-5262	#72-5640	#73-5592	#74-5264	#75-5413	#76-5396	#77-5636	#78-5456	#79-5536	#80-5660
#81-5604	#82-5376	#83-5420	#84-5260	#85-5529	#86-5367	#87-5711	#88-5569	#89-5547	#90-5718
#91-5507	#92-5431	#93-5305	#94-5432	#95-5642	#96-5292	#97-5560	#98-5330	#99-5332	#100-5500

Type 6 #27 [Back to Summary]									
#01-5567	#02-5568	#03-5495	#04-5417	#05-5623	#06-5442	#07-5496	#08-5722	#09-5432	#10-5717
#11-5539	#12-5321	#13-5709	#14-5604	#15-5585	#16-5684	#17-5666	#18-5663	#19-5554	#20-5439
#21-5647	#22-5454	#23-5482	#24-5707	#25-5340	#26-5261	#27-5718	#28-5521	#29-5493	#30-5349
#31-5523	#32-5713	#33-5308	#34-5645	#35-5418	#36-5685	#37-5414	#38-5675	#39-5337	#40-5376
#41-5301	#42-5720	#43-5680	#44-5514	#45-5616	#46-5708	#47-5448	#48-5288	#49-5324	#50-5332
#51-5619	#52-5392	#53-5558	#54-5617	#55-5578	#56-5362	#57-5336	#58-5513	#59-5326	#60-5611
#61-5449	#62-5699	#63-5479	#64-5333	#65-5443	#66-5551	#67-5262	#68-5313	#69-5435	#70-5624
#71-5520	#72-5715	#73-5576	#74-5427	#75-5387	#76-5651	#77-5498	#78-5693	#79-5356	#80-5538
#81-5679	#82-5446	#83-5411	#84-5381	#85-5404	#86-5416	#87-5317	#88-5305	#89-5599	#90-5625
#91-5450	#92-5652	#93-5327	#94-5491	#95-5597	#96-5315	#97-5696	#98-5384	#99-5425	#100-5536

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 150 of 177

Type 6 #28 [Back to Summary]									
#01-5628	#02-5540	#03-5381	#04-5479	#05-5651	#06-5589	#07-5368	#08-5422	#09-5694	#10-5322
#11-5494	#12-5502	#13-5317	#14-5603	#15-5311	#16-5396	#17-5571	#18-5721	#19-5380	#20-5274
#21-5620	#22-5366	#23-5375	#24-5500	#25-5310	#26-5410	#27-5625	#28-5621	#29-5275	#30-5385
#31-5404	#32-5351	#33-5271	#34-5599	#35-5551	#36-5565	#37-5273	#38-5661	#39-5390	#40-5440
#41-5481	#42-5453	#43-5629	#44-5377	#45-5407	#46-5549	#47-5423	#48-5719	#49-5259	#50-5643
#51-5374	#52-5387	#53-5447	#54-5400	#55-5641	#56-5512	#57-5415	#58-5605	#59-5419	#60-5491
#61-5689	#62-5471	#63-5559	#64-5392	#65-5443	#66-5302	#67-5470	#68-5373	#69-5634	#70-5581
#71-5664	#72-5517	#73-5416	#74-5462	#75-5722	#76-5342	#77-5486	#78-5712	#79-5630	#80-5611
#81-5357	#82-5260	#83-5267	#84-5595	#85-5683	#86-5288	#87-5492	#88-5624	#89-5476	#90-5307
#91-5319	#92-5459	#93-5265	#94-5705	#95-5667	#96-5514	#97-5519	#98-5465	#99-5530	#100-5508

Type 6 #29 [Back to Summary]									
#01-5607	#02-5474	#03-5299	#04-5418	#05-5513	#06-5657	#07-5504	#08-5308	#09-5584	#10-5288
#11-5548	#12-5625	#13-5488	#14-5611	#15-5484	#16-5263	#17-5320	#18-5705	#19-5392	#20-5682
#21-5438	#22-5507	#23-5359	#24-5327	#25-5256	#26-5687	#27-5347	#28-5562	#29-5520	#30-5461
#31-5370	#32-5712	#33-5458	#34-5713	#35-5707	#36-5604	#37-5559	#38-5417	#39-5401	#40-5268
#41-5496	#42-5558	#43-5501	#44-5431	#45-5470	#46-5654	#47-5443	#48-5539	#49-5322	#50-5573
#51-5350	#52-5365	#53-5632	#54-5630	#55-5435	#56-5489	#57-5497	#58-5346	#59-5486	#60-5450
#61-5278	#62-5414	#63-5367	#64-5623	#65-5276	#66-5274	#67-5338	#68-5557	#69-5270	#70-5356
#71-5341	#72-5621	#73-5679	#74-5550	#75-5711	#76-5511	#77-5283	#78-5629	#79-5273	#80-5447
#81-5613	#82-5300	#83-5612	#84-5342	#85-5331	#86-5326	#87-5319	#88-5597	#89-5321	#90-5639
#91-5542	#92-5467	#93-5394	#94-5383	#95-5533	#96-5444	#97-5355	#98-5261	#99-5719	#100-5260

Type 6 #30 [Back to Summary]									
#01-5675	#02-5610	#03-5503	#04-5711	#05-5312	#06-5581	#07-5427	#08-5555	#09-5526	#10-5316
#11-5261	#12-5658	#13-5668	#14-5657	#15-5487	#16-5689	#17-5674	#18-5441	#19-5523	#20-5403
#21-5535	#22-5417	#23-5317	#24-5378	#25-5524	#26-5560	#27-5682	#28-5602	#29-5251	#30-5617
#31-5318	#32-5320	#33-5376	#34-5533	#35-5541	#36-5611	#37-5258	#38-5307	#39-5365	#40-5636
#41-5593	#42-5522	#43-5510	#44-5686	#45-5343	#46-5506	#47-5296	#48-5350	#49-5527	#50-5476
#51-5390	#52-5443	#53-5325	#54-5643	#55-5659	#56-5591	#57-5597	#58-5649	#59-5315	#60-5368
#61-5590	#62-5373	#63-5671	#64-5328	#65-5665	#66-5383	#67-5407	#68-5492	#69-5667	#70-5630
#71-5531	#72-5416	#73-5430	#74-5303	#75-5681	#76-5625	#77-5340	#78-5567	#79-5463	#80-5710
#81-5466	#82-5692	#83-5324	#84-5724	#85-5498	#86-5288	#87-5645	#88-5339	#89-5458	#90-5382
#91-5305	#92-5693	#93-5410	#94-5393	#95-5448	#96-5342	#97-5419	#98-5362	#99-5493	#100-5537

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 151 of 177

Type 5 #1 5521 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	17	1176128	83	1924	1293	20406	1200000
2	1	17	17365	64	0	0	1182571	1200000
3	2	17	694946	53	1015	0	503933	1200000
4	2	17	1164370	95	1190	0	34250	1200000
5	2	17	810890	99	1418	0	387494	1200000
6	1	17	1047215	72	0	0	152713	1200000
7	2	17	107709	77	1196	0	1090941	1200000
8	1	17	351228	78	0	0	848694	1200000
9	1	17	1160564	100	0	0	39336	1200000
10	1	17	705930	71	0	0	493999	1200000

Type 5 #2 5524 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	398404	60	0	0	801536	1200000
2	3	10	645745	62	1747	1617	550705	1200000
3	1	10	562120	70	0	0	637810	1200000
4	2	10	13792	50	1926	0	1184182	1200000
5	1	10	934917	80	0	0	265003	1200000
6	2	10	1062864	74	1643	0	135345	1200000
7	1	10	1050615	56	0	0	149329	1200000
8	2	10	966185	59	1247	0	232450	1200000
9	3	10	1162748	57	1323	1564	34194	1200000
10	2	10	1142357	61	1556	0	55965	1200000

Type 5 #3 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	656721	89	0	0	843190	1500000
2	3	5	792479	93	1336	1246	704660	1500000
3	1	5	1147250	87	0	0	352663	1500000
4	3	5	657016	61	1409	1203	840189	1500000
5	3	5	284927	82	1925	1923	1210979	1500000
6	3	5	165989	60	1046	1985	1330800	1500000
7	3	5	815015	91	1622	1419	681671	1500000
8	3	5	219888	96	1812	1076	1276936	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 152 of 177

Type 5 #4 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	16	243369	75	1377	1852	419843	666666
2	2	16	431233	93	1484	0	233763	666666
3	3	16	56998	56	1199	1877	606424	666666
4	3	16	575862	82	1142	1280	88136	666666
5	1	16	409122	63	0	0	257481	666666
6	3	16	88254	89	1149	1600	575396	666666
7	2	16	172535	66	1493	0	492506	666666
8	1	16	380638	73	0	0	285955	666666
9	2	16	457837	71	1319	0	207368	666666
10	3	16	93387	92	1126	1688	570189	666666
11	2	16	93888	73	1351	0	571281	666666
12	2	16	47268	100	1754	0	617444	666666
13	2	16	431644	76	1231	0	233639	666666
14	3	16	119643	69	1889	1827	543100	666666
15	3	16	185361	86	1023	1439	478585	666666
16	3	16	579398	87	1107	1652	84248	666666
17	1	16	643272	74	0	0	23320	666666
18	3	16	521385	100	1668	1140	142173	666666

Type 5 #5 5524 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	8	317498	100	0	0	1015735	1333333
2	3	8	435956	94	1961	1743	893391	1333333
3	1	8	64695	61	0	0	1268577	1333333
4	1	8	1165196	67	0	0	168070	1333333
5	2	8	1228605	98	1310	0	103222	1333333
6	2	8	640889	95	1159	0	691095	1333333
7	1	8	705437	60	0	0	627836	1333333
8	3	8	550525	54	1902	1744	779000	1333333
9	2	8	376109	50	1316	0	955808	1333333

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 153 of 177

Type 5 #6 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	6	134206	72	1079	1148	863351	1000000
2	3	6	700290	71	1070	1928	296499	1000000
3	1	6	532750	74	0	0	467176	1000000
4	1	6	223962	83	0	0	775955	1000000
5	1	6	5965	64	0	0	993971	1000000
6	1	6	571212	82	0	0	428706	1000000
7	2	6	804367	64	1837	0	193668	1000000
8	2	6	852450	90	1684	0	145686	1000000
9	1	6	485290	85	0	0	514625	1000000
10	3	6	834938	87	1073	1899	161829	1000000
11	1	6	20716	88	0	0	979196	1000000
12	2	6	756360	56	1946	0	241582	1000000

Type 5 #7 5524 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	9	179042	90	0	0	678010	857142
2	3	9	403862	76	1681	1936	449435	857142
3	2	9	516219	85	1012	0	339741	857142
4	3	9	385601	97	1373	1787	468090	857142
5	2	9	577896	99	1817	0	277231	857142
6	3	9	550164	70	1928	1058	303782	857142
7	1	9	762120	96	0	0	94926	857142
8	2	9	133492	94	1002	0	722460	857142
9	1	9	537997	67	0	0	319078	857142
10	2	9	694936	56	1283	0	160811	857142
11	1	9	595395	75	0	0	261672	857142
12	3	9	190003	74	1811	1274	663832	857142
13	3	9	643398	64	1008	1342	211202	857142
14	2	9	258749	55	1254	0	597029	857142

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 154 of 177

Type 5 #8 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	9	72591	56	0	0	677353	750000
2	2	9	687153	70	1589	0	61118	750000
3	2	9	689950	91	1504	0	58364	750000
4	1	9	586306	68	0	0	163626	750000
5	2	9	256353	94	1175	0	492284	750000
6	3	9	380897	58	1006	1029	366894	750000
7	1	9	34849	56	0	0	715095	750000
8	2	9	262183	62	1673	0	486020	750000
9	2	9	319080	72	1698	0	429078	750000
10	1	9	49716	98	0	0	700186	750000
11	2	9	442597	82	1932	0	305307	750000
12	3	9	236012	89	1092	1233	511396	750000
13	3	9	631385	78	1371	1499	115511	750000
14	2	9	505383	71	1458	0	243017	750000
15	2	9	49484	64	1068	0	699320	750000
16	1	9	240054	64	0	0	509882	750000

Type 5 #9 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	12	189199	71	1542	0	514999	705882
2	2	12	290850	50	1879	0	413053	705882
3	1	12	200390	53	0	0	505439	705882
4	2	12	432100	84	1520	0	272094	705882
5	2	12	335594	61	1646	0	368520	705882
6	3	12	269984	81	1809	1651	432195	705882
7	3	12	295278	81	1675	1045	407641	705882
8	3	12	370468	100	1189	1956	331969	705882
9	2	12	684219	83	2000	0	19497	705882
10	3	12	231342	50	1638	1411	471341	705882
11	1	12	596706	61	0	0	109115	705882
12	1	12	487538	78	0	0	218266	705882
13	2	12	357613	70	1386	0	346743	705882
14	2	12	622684	57	1252	0	81832	705882
15	2	12	498593	68	1657	0	205496	705882
16	1	12	623361	97	0	0	82424	705882
17	2	12	686439	91	1651	0	17610	705882

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 155 of 177

Type 5 #10 5525 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	177659	87	1434	0	487399	666666
2	1	6	16915	56	0	0	649695	666666
3	2	6	558228	81	1817	0	106459	666666
4	3	6	342296	94	1257	1672	321159	666666
5	3	6	584230	96	1590	1672	78886	666666
6	3	6	499340	78	1413	1461	164218	666666
7	1	6	99966	57	0	0	566643	666666
8	1	6	468917	92	0	0	197657	666666
9	2	6	179962	50	1900	0	484704	666666
10	3	6	606614	53	1814	1082	56997	666666
11	2	6	438563	80	1309	0	226634	666666
12	1	6	258443	88	0	0	408135	666666
13	2	6	177805	78	1717	0	486988	666666
14	3	6	518553	74	1595	1251	145045	666666
15	2	6	534427	64	1335	0	130776	666666
16	1	6	135558	80	0	0	531028	666666
17	3	6	410533	95	1483	1319	253046	666666
18	1	6	620375	51	0	0	46240	666666

Type 5 #11 5525 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	6	1075829	64	0	0	424107	1500000
2	2	6	714445	67	1467	0	783954	1500000
3	1	6	400477	74	0	0	1099449	1500000
4	2	6	539284	75	1639	0	958927	1500000
5	1	6	114595	79	0	0	1385326	1500000
6	2	6	697581	50	1650	0	800669	1500000
7	3	6	417185	66	1599	1442	1079576	1500000
8	1	6	1026044	96	0	0	473860	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 156 of 177

Type 5 #12 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	10	290560	50	0	0	709390	1000000
2	3	10	976219	82	1355	1289	20891	1000000
3	1	10	948585	72	0	0	51343	1000000
4	3	10	723652	66	1067	1699	273384	1000000
5	1	10	370177	94	0	0	629729	1000000
6	1	10	981773	52	0	0	18175	1000000
7	3	10	349313	82	1367	1434	647640	1000000
8	1	10	360018	69	0	0	639913	1000000
9	3	10	464016	91	1387	1034	533290	1000000
10	1	10	963360	93	0	0	36547	1000000
11	2	10	340	68	1823	0	997701	1000000
12	2	10	697890	55	1129	0	300871	1000000

Type 5 #13 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	875512	81	1582	1216	121447	1000000
2	2	10	48891	69	1708	0	949263	1000000
3	2	10	273682	60	1750	0	724448	1000000
4	1	10	350093	63	0	0	649844	1000000
5	2	10	591422	91	1073	0	407323	1000000
6	1	10	249872	97	0	0	750031	1000000
7	1	10	11862	100	0	0	988038	1000000
8	3	10	707398	65	1855	1514	289038	1000000
9	1	10	115619	56	0	0	884325	1000000
10	2	10	379757	98	1289	0	618758	1000000
11	3	10	25345	71	1037	1575	971830	1000000
12	3	10	827510	50	1537	1148	169655	1000000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 157 of 177

Type 5 #14 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	19	442401	66	1502	0	355965	800000
2	3	19	481150	79	1551	1421	315641	800000
3	3	19	448300	83	1482	1302	348667	800000
4	2	19	775591	92	1079	0	23146	800000
5	3	19	2735	99	1301	1317	794350	800000
6	3	19	435930	57	1900	1867	360132	800000
7	2	19	138071	99	1392	0	660339	800000
8	2	19	649462	73	1023	0	149369	800000
9	1	19	533853	65	0	0	266082	800000
10	1	19	563148	74	0	0	236778	800000
11	1	19	350788	76	0	0	449136	800000
12	2	19	315584	77	1145	0	483117	800000
13	2	19	589054	84	1272	0	209506	800000
14	1	19	271863	55	0	0	528082	800000
15	3	19	316439	82	1361	1161	480793	800000

Type 5 #15 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	11	851546	84	1408	1774	645020	1500000
2	1	11	936535	54	0	0	563411	1500000
3	3	11	528363	90	1937	1269	968161	1500000
4	3	11	1091091	75	1401	1112	406171	1500000
5	3	11	1336967	75	1747	1342	159719	1500000
6	1	11	1078026	86	0	0	421888	1500000
7	1	11	1338688	91	0	0	161221	1500000
8	1	11	252008	75	0	0	1247917	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 158 of 177

Type 5 #16 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	6	519320	71	1892	1728	182729	705882
2	3	6	491011	71	1894	1647	211117	705882
3	3	6	20063	51	1855	1432	682379	705882
4	2	6	92136	73	1133	0	612467	705882
5	2	6	269429	100	1090	0	435163	705882
6	1	6	634398	98	0	0	71386	705882
7	1	6	649585	70	0	0	56227	705882
8	1	6	693705	58	0	0	12119	705882
9	2	6	510079	65	1245	0	194428	705882
10	1	6	184901	68	0	0	520913	705882
11	3	6	689378	52	1986	1445	12917	705882
12	1	6	516305	64	0	0	189513	705882
13	3	6	618847	63	1295	1189	84362	705882
14	1	6	86138	71	0	0	619673	705882
15	3	6	683978	59	1958	1011	18758	705882
16	3	6	511472	70	1972	1852	190376	705882
17	1	6	636577	56	0	0	69249	705882

Type 5 #17 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	16	667171	97	1434	0	254277	923076
2	1	16	260304	55	0	0	662717	923076
3	2	16	299050	89	1859	0	621989	923076
4	2	16	262252	54	1975	0	658741	923076
5	1	16	429771	90	0	0	493215	923076
6	3	16	44842	61	1249	1175	875627	923076
7	1	16	81490	81	0	0	841505	923076
8	2	16	874452	65	1259	0	47235	923076
9	3	16	188445	89	1731	1106	731527	923076
10	1	16	735972	94	0	0	187010	923076
11	3	16	251517	91	1809	1413	668064	923076
12	3	16	437275	65	1463	1508	482635	923076
13	1	16	173335	71	0	0	749670	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 159 of 177

Type 5 #18 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	5	214730	78	0	0	385192	600000
2	2	5	156252	71	1683	0	441923	600000
3	3	5	141210	68	1589	1379	455618	600000
4	1	5	490420	60	0	0	109520	600000
5	2	5	65918	50	1797	0	532185	600000
6	1	5	515617	88	0	0	84295	600000
7	2	5	430725	59	1690	0	167467	600000
8	3	5	132844	83	1249	1782	463876	600000
9	3	5	286286	62	1669	1202	310657	600000
10	3	5	487343	82	1671	1012	109728	600000
11	2	5	296176	98	1459	0	302169	600000
12	2	5	58183	96	1149	0	540476	600000
13	3	5	520940	56	1080	1197	76615	600000
14	2	5	93068	54	1987	0	504837	600000
15	2	5	356279	98	1241	0	242284	600000
16	2	5	386447	82	1322	0	212067	600000
17	3	5	155695	80	1366	1029	441670	600000
18	3	5	285173	58	1701	1865	311087	600000
19	3	5	129500	71	1538	1122	467627	600000
20	1	5	15384	52	0	0	584564	600000

Type 5 #19 5524 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	8	1241613	95	1153	0	257044	1500000
2	2	8	1070124	73	1981	0	427749	1500000
3	1	8	1214187	56	0	0	285757	1500000
4	3	8	286385	64	1640	1249	1210534	1500000
5	3	8	458494	91	1472	1972	1037789	1500000
6	1	8	301714	52	0	0	1198234	1500000
7	3	8	398506	92	1140	1042	1099036	1500000
8	2	8	466931	79	1077	0	1031834	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 160 of 177

Type 5 #20 5525 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	6	828308	62	1667	0	260810	1090909
2	2	6	928031	60	1810	0	160948	1090909
3	2	6	597188	59	1871	0	491732	1090909
4	2	6	364278	58	1330	0	725185	1090909
5	3	6	66387	78	1680	1654	1020954	1090909
6	1	6	423673	56	0	0	667180	1090909
7	3	6	915316	53	1718	1320	172396	1090909
8	2	6	685767	54	1442	0	403592	1090909
9	1	6	915426	83	0	0	175400	1090909
10	2	6	999957	86	1556	0	89224	1090909
11	1	6	1005385	84	0	0	85440	1090909

Type 5 #21 5526 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	5	78494	62	1069	1931	1418320	1500000
2	2	5	1061377	73	1551	0	436926	1500000
3	1	5	1060315	54	0	0	439631	1500000
4	3	5	556975	83	1919	1402	939455	1500000
5	2	5	167853	81	1832	0	1330153	1500000
6	1	5	307454	83	0	0	1192463	1500000
7	1	5	118073	64	0	0	1381863	1500000
8	3	5	337938	53	1560	1400	1158943	1500000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISSED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 161 of 177

Type 5 #22 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	14	277568	59	1788	1697	318770	600000
2	3	14	371941	57	1197	1630	225061	600000
3	1	14	559688	99	0	0	40213	600000
4	3	14	373301	84	1346	1560	223541	600000
5	1	14	87615	57	0	0	512328	600000
6	1	14	205310	64	0	0	394626	600000
7	2	14	29079	59	1681	0	569122	600000
8	3	14	84818	67	1964	1582	511435	600000
9	1	14	239100	59	0	0	360841	600000
10	2	14	177345	66	1433	0	421090	600000
11	3	14	173625	62	1812	1375	423002	600000
12	1	14	41803	82	0	0	558115	600000
13	1	14	515238	82	0	0	84680	600000
14	1	14	2125	57	0	0	597818	600000
15	3	14	361783	99	1595	1741	234584	600000
16	2	14	448700	65	1443	0	149727	600000
17	1	14	317148	92	0	0	282760	600000
18	3	14	36548	79	1233	1383	560599	600000
19	3	14	314517	86	1693	1911	281621	600000
20	2	14	148100	57	1325	0	450461	600000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 162 of 177

Type 5 #23 5499 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	16	639061	57	0	0	27548	666666
2	3	16	163485	93	1640	1895	499367	666666
3	2	16	618376	55	1098	0	47082	666666
4	3	16	600010	82	1943	1160	63307	666666
5	3	16	78378	79	1079	1920	585052	666666
6	1	16	337561	75	0	0	329030	666666
7	1	16	362059	88	0	0	304519	666666
8	1	16	123102	59	0	0	543505	666666
9	3	16	86465	54	1798	1059	577182	666666
10	2	16	319576	52	1040	0	345946	666666
11	3	16	132441	69	1353	1518	531147	666666
12	2	16	486799	56	1036	0	178719	666666
13	2	16	61743	70	1147	0	603636	666666
14	2	16	394028	96	1742	0	270704	666666
15	1	16	113844	88	0	0	552734	666666
16	1	16	633987	89	0	0	32590	666666
17	2	16	14520	54	1077	0	650961	666666
18	3	16	228094	56	1951	1237	435216	666666

Type 5 #24 5495 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	7	18156	70	1913	1525	901272	923076
2	1	7	821062	65	0	0	101949	923076
3	2	7	639332	81	1103	0	282479	923076
4	2	7	584842	63	1178	0	336930	923076
5	2	7	564586	74	1372	0	356970	923076
6	1	7	368937	56	0	0	554083	923076
7	2	7	63669	77	1975	0	857278	923076
8	2	7	841399	85	1859	0	79648	923076
9	2	7	123307	99	1779	0	797792	923076
10	1	7	823465	76	0	0	99535	923076
11	3	7	756707	96	1233	1872	162976	923076
12	2	7	843747	61	1033	0	78174	923076
13	3	7	318845	95	1599	1900	600447	923076

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 163 of 177

Type 5 #25 5520 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	20	423717	74	1266	0	206447	631578
2	3	20	186291	54	1238	1049	442838	631578
3	1	20	68128	93	0	0	563357	631578
4	3	20	419981	58	1482	1540	208401	631578
5	1	20	394168	94	0	0	237316	631578
6	2	20	414802	94	1212	0	215376	631578
7	1	20	441598	91	0	0	189889	631578
8	2	20	95305	87	1606	0	534493	631578
9	2	20	513207	57	1795	0	116462	631578
10	2	20	42576	83	1755	0	587081	631578
11	3	20	204918	72	1832	1494	423118	631578
12	1	20	224861	81	0	0	406636	631578
13	1	20	285462	100	0	0	346016	631578
14	2	20	91977	96	1483	0	537926	631578
15	1	20	205517	68	0	0	425993	631578
16	1	20	551601	95	0	0	79882	631578
17	3	20	292391	52	1417	1961	335653	631578
18	1	20	230897	55	0	0	400626	631578
19	1	20	19784	67	0	0	611727	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 164 of 177

Type 5 #26 5498 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	15	607209	67	0	0	59390	666666
2	1	15	184574	72	0	0	482020	666666
3	3	15	385168	81	1118	1500	278637	666666
4	2	15	263396	81	1568	0	401540	666666
5	3	15	358057	76	1728	1340	305313	666666
6	1	15	71984	94	0	0	594588	666666
7	1	15	325008	86	0	0	341572	666666
8	1	15	361202	90	0	0	305374	666666
9	1	15	829	65	0	0	665772	666666
10	1	15	63188	72	0	0	603406	666666
11	3	15	367368	86	1771	1920	295349	666666
12	2	15	366995	54	1149	0	298414	666666
13	1	15	635444	100	0	0	31122	666666
14	2	15	601821	92	1168	0	63493	666666
15	1	15	520490	50	0	0	146126	666666
16	3	15	462003	53	1422	1532	201550	666666
17	2	15	448961	64	1840	0	215737	666666
18	2	15	460125	55	1854	0	204577	666666

Type 5 #27 5496 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	8	1288331	78	1775	0	43071	1333333
2	1	8	797140	51	0	0	536142	1333333
3	3	8	462957	93	1322	1992	866783	1333333
4	1	8	607744	100	0	0	725489	1333333
5	3	8	659621	63	1164	1897	670462	1333333
6	2	8	956314	100	1480	0	375339	1333333
7	2	8	536924	84	1295	0	794946	1333333
8	2	8	705533	83	1182	0	626452	1333333
9	1	8	352593	65	0	0	980675	1333333

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 165 of 177

Type 5 #28 5524 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	2	10	189345	59	1545	0	440570	631578
2	3	10	325018	68	1663	1078	303615	631578
3	1	10	556664	77	0	0	74837	631578
4	1	10	291906	58	0	0	339614	631578
5	2	10	196537	92	1483	0	433374	631578
6	3	10	548636	73	1963	1922	78838	631578
7	2	10	132095	67	1122	0	498227	631578
8	2	10	345022	99	1797	0	284561	631578
9	1	10	207708	93	0	0	423777	631578
10	2	10	229156	67	1782	0	400506	631578
11	3	10	318500	83	1106	1654	310069	631578
12	1	10	604002	69	0	0	27507	631578
13	3	10	310190	51	1437	1030	318768	631578
14	1	10	2870	53	0	0	628655	631578
15	2	10	577577	67	1376	0	52491	631578
16	2	10	582331	100	1915	0	47132	631578
17	2	10	425872	85	1874	0	203662	631578
18	1	10	540255	63	0	0	91260	631578
19	2	10	532243	56	1139	0	98084	631578

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 166 of 177

Type 5 #29 5510 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	3	10	4739	60	1285	1381	659081	666666
2	2	10	481889	64	1074	0	183575	666666
3	2	10	248993	58	1903	0	415654	666666
4	1	10	237749	57	0	0	428860	666666
5	3	10	580303	62	1498	1207	83472	666666
6	1	10	578472	80	0	0	88114	666666
7	2	10	430548	97	1166	0	234758	666666
8	3	10	36577	65	1306	1789	626799	666666
9	3	10	644683	59	1944	1131	18731	666666
10	1	10	15248	71	0	0	651347	666666
11	2	10	399367	87	1464	0	265661	666666
12	3	10	11765	53	1614	1212	651916	666666
13	3	10	406075	60	1348	1783	257280	666666
14	1	10	558489	80	0	0	108097	666666
15	2	10	37172	66	1300	0	628062	666666
16	2	10	653006	53	1654	0	11900	666666
17	1	10	8664	53	0	0	657949	666666
18	1	10	30952	85	0	0	635629	666666

Type 5 #30 5521 [Back to Summary]

Burst Segment	Number of Pulses	Chirp Width MHz	t1 usec	Pulse Width (t2) usec	t3 usec	t4 usec	t5 usec	Total Segment Length usec
1	1	17	477195	60	0	0	322745	800000
2	2	17	662995	88	1359	0	135470	800000
3	2	17	130386	59	1018	0	668478	800000
4	2	17	767489	77	1157	0	31200	800000
5	1	17	542269	91	0	0	257640	800000
6	2	17	348671	67	1571	0	449624	800000
7	1	17	115560	80	0	0	684360	800000
8	3	17	765016	78	1263	1839	31648	800000
9	3	17	538768	95	1543	1999	257405	800000
10	2	17	671421	100	1812	0	126567	800000
11	2	17	212711	93	1218	0	585885	800000
12	3	17	620244	60	1526	1606	176444	800000
13	1	17	188600	97	0	0	611303	800000
14	2	17	720137	52	1236	0	78523	800000
15	2	17	52002	73	1198	0	746654	800000

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 167 of 177

Type 6 #1 [Back to Summary]

#01-5286	#02-5395	#03-5589	#04-5340	#05-5692	#06-5565	#07-5612	#08-5288	#09-5558	#10-5721
#11-5398	#12-5673	#13-5599	#14-5593	#15-5655	#16-5616	#17-5511	#18-5303	#19-5719	#20-5331
#21-5313	#22-5557	#23-5315	#24-5381	#25-5400	#26-5697	#27-5440	#28-5332	#29-5667	#30-5482
#31-5600	#32-5518	#33-5327	#34-5366	#35-5700	#36-5598	#37-5687	#38-5383	#39-5678	#40-5432
#41-5561	#42-5714	#43-5306	#44-5415	#45-5268	#46-5698	#47-5378	#48-5330	#49-5396	#50-5346
#51-5441	#52-5424	#53-5453	#54-5457	#55-5664	#56-5720	#57-5375	#58-5530	#59-5325	#60-5370
#61-5604	#62-5596	#63-5483	#64-5617	#65-5307	#66-5653	#67-5350	#68-5536	#69-5495	#70-5323
#71-5723	#72-5258	#73-5300	#74-5710	#75-5467	#76-5679	#77-5587	#78-5336	#79-5504	#80-5494
#81-5666	#82-5496	#83-5517	#84-5479	#85-5443	#86-5682	#87-5281	#88-5618	#89-5661	#90-5451
#91-5543	#92-5510	#93-5320	#94-5401	#95-5629	#96-5455	#97-5322	#98-5407	#99-5291	#100-5633

Type 6 #2 [Back to Summary]

#01-5576	#02-5483	#03-5714	#04-5590	#05-5526	#06-5352	#07-5541	#08-5371	#09-5514	#10-5424
#11-5659	#12-5392	#13-5479	#14-5463	#15-5430	#16-5490	#17-5322	#18-5573	#19-5416	#20-5417
#21-5386	#22-5608	#23-5436	#24-5317	#25-5509	#26-5423	#27-5565	#28-5291	#29-5445	#30-5488
#31-5641	#32-5399	#33-5384	#34-5492	#35-5320	#36-5649	#37-5441	#38-5694	#39-5683	#40-5531
#41-5701	#42-5333	#43-5578	#44-5400	#45-5574	#46-5645	#47-5689	#48-5724	#49-5558	#50-5512
#51-5598	#52-5496	#53-5692	#54-5297	#55-5647	#56-5331	#57-5353	#58-5646	#59-5329	#60-5319
#61-5421	#62-5476	#63-5283	#64-5296	#65-5722	#66-5252	#67-5699	#68-5448	#69-5428	#70-5327
#71-5459	#72-5708	#73-5655	#74-5273	#75-5581	#76-5700	#77-5292	#78-5628	#79-5462	#80-5337
#81-5570	#82-5546	#83-5520	#84-5718	#85-5604	#86-5461	#87-5599	#88-5637	#89-5540	#90-5691
#91-5634	#92-5537	#93-5318	#94-5615	#95-5562	#96-5664	#97-5315	#98-5305	#99-5588	#100-5433

Type 6 #3 [Back to Summary]

#01-5426	#02-5546	#03-5683	#04-5402	#05-5262	#06-5352	#07-5429	#08-5455	#09-5548	#10-5590
#11-5584	#12-5320	#13-5553	#14-5678	#15-5290	#16-5296	#17-5361	#18-5448	#19-5579	#20-5413
#21-5616	#22-5560	#23-5571	#24-5500	#25-5630	#26-5564	#27-5467	#28-5454	#29-5662	#30-5601
#31-5587	#32-5261	#33-5442	#34-5643	#35-5618	#36-5719	#37-5640	#38-5538	#39-5709	#40-5531
#41-5357	#42-5670	#43-5494	#44-5275	#45-5702	#46-5593	#47-5376	#48-5274	#49-5259	#50-5400
#51-5258	#52-5282	#53-5542	#54-5591	#55-5700	#56-5433	#57-5496	#58-5423	#59-5610	#60-5699
#61-5518	#62-5672	#63-5252	#64-5573	#65-5602	#66-5635	#67-5309	#68-5381	#69-5547	#70-5463
#71-5298	#72-5305	#73-5671	#74-5315	#75-5545	#76-5522	#77-5286	#78-5717	#79-5341	#80-5430
#81-5652	#82-5710	#83-5436	#84-5253	#85-5410	#86-5351	#87-5277	#88-5268	#89-5456	#90-5291
#91-5536	#92-5646	#93-5382	#94-5401	#95-5272	#96-5379	#97-5716	#98-5660	#99-5316	#100-5603

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 168 of 177

Type 6 #4 [Back to Summary]									
#01-5318	#02-5662	#03-5684	#04-5702	#05-5595	#06-5525	#07-5404	#08-5636	#09-5459	#10-5431
#11-5519	#12-5590	#13-5686	#14-5541	#15-5570	#16-5442	#17-5534	#18-5282	#19-5278	#20-5649
#21-5505	#22-5652	#23-5377	#24-5647	#25-5493	#26-5523	#27-5393	#28-5295	#29-5306	#30-5274
#31-5452	#32-5299	#33-5641	#34-5499	#35-5293	#36-5433	#37-5480	#38-5476	#39-5589	#40-5545
#41-5557	#42-5354	#43-5376	#44-5588	#45-5536	#46-5585	#47-5456	#48-5284	#49-5674	#50-5678
#51-5538	#52-5260	#53-5305	#54-5325	#55-5281	#56-5605	#57-5492	#58-5414	#59-5374	#60-5494
#61-5316	#62-5540	#63-5291	#64-5526	#65-5259	#66-5303	#67-5530	#68-5673	#69-5547	#70-5250
#71-5308	#72-5708	#73-5633	#74-5317	#75-5584	#76-5497	#77-5655	#78-5715	#79-5503	#80-5346
#81-5353	#82-5489	#83-5460	#84-5378	#85-5405	#86-5445	#87-5302	#88-5392	#89-5705	#90-5606
#91-5521	#92-5720	#93-5257	#94-5514	#95-5323	#96-5479	#97-5510	#98-5573	#99-5437	#100-5721

Type 6 #5 [Back to Summary]									
#01-5342	#02-5373	#03-5538	#04-5633	#05-5641	#06-5444	#07-5504	#08-5666	#09-5527	#10-5315
#11-5605	#12-5623	#13-5334	#14-5430	#15-5302	#16-5530	#17-5566	#18-5368	#19-5512	#20-5712
#21-5343	#22-5627	#23-5577	#24-5707	#25-5581	#26-5485	#27-5717	#28-5497	#29-5488	#30-5301
#31-5628	#32-5381	#33-5313	#34-5321	#35-5419	#36-5394	#37-5475	#38-5511	#39-5351	#40-5525
#41-5598	#42-5612	#43-5425	#44-5329	#45-5521	#46-5309	#47-5595	#48-5438	#49-5459	#50-5354
#51-5280	#52-5636	#53-5306	#54-5659	#55-5587	#56-5269	#57-5546	#58-5672	#59-5428	#60-5412
#61-5474	#62-5559	#63-5262	#64-5261	#65-5632	#66-5304	#67-5305	#68-5267	#69-5529	#70-5436
#71-5469	#72-5264	#73-5635	#74-5324	#75-5406	#76-5341	#77-5637	#78-5700	#79-5431	#80-5439
#81-5647	#82-5683	#83-5291	#84-5508	#85-5337	#86-5541	#87-5648	#88-5332	#89-5411	#90-5578
#91-5420	#92-5387	#93-5503	#94-5409	#95-5590	#96-5317	#97-5613	#98-5254	#99-5540	#100-5421

Type 6 #6 [Back to Summary]									
#01-5654	#02-5642	#03-5535	#04-5621	#05-5395	#06-5585	#07-5430	#08-5652	#09-5633	#10-5697
#11-5724	#12-5294	#13-5551	#14-5601	#15-5696	#16-5478	#17-5544	#18-5487	#19-5382	#20-5659
#21-5368	#22-5583	#23-5299	#24-5602	#25-5381	#26-5639	#27-5541	#28-5685	#29-5569	#30-5336
#31-5423	#32-5615	#33-5268	#34-5718	#35-5290	#36-5481	#37-5612	#38-5667	#39-5681	#40-5467
#41-5405	#42-5502	#43-5605	#44-5420	#45-5343	#46-5531	#47-5713	#48-5410	#49-5564	#50-5319
#51-5491	#52-5407	#53-5486	#54-5536	#55-5308	#56-5263	#57-5670	#58-5613	#59-5692	#60-5313
#61-5610	#62-5550	#63-5403	#64-5679	#65-5558	#66-5560	#67-5465	#68-5591	#69-5504	#70-5590
#71-5702	#72-5604	#73-5509	#74-5575	#75-5306	#76-5553	#77-5525	#78-5255	#79-5267	#80-5656
#81-5458	#82-5506	#83-5431	#84-5706	#85-5720	#86-5593	#87-5653	#88-5260	#89-5579	#90-5438
#91-5439	#92-5594	#93-5665	#94-5577	#95-5274	#96-5402	#97-5698	#98-5441	#99-5493	#100-5707

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 169 of 177

Type 6 #7 [Back to Summary]									
#01-5671	#02-5331	#03-5607	#04-5484	#05-5413	#06-5614	#07-5310	#08-5416	#09-5308	#10-5593
#11-5618	#12-5670	#13-5422	#14-5376	#15-5579	#16-5470	#17-5722	#18-5674	#19-5520	#20-5316
#21-5400	#22-5707	#23-5259	#24-5568	#25-5723	#26-5281	#27-5580	#28-5550	#29-5696	#30-5689
#31-5523	#32-5485	#33-5625	#34-5362	#35-5358	#36-5490	#37-5371	#38-5518	#39-5271	#40-5381
#41-5700	#42-5720	#43-5404	#44-5623	#45-5548	#46-5450	#47-5492	#48-5414	#49-5433	#50-5641
#51-5348	#52-5597	#53-5640	#54-5582	#55-5635	#56-5561	#57-5276	#58-5292	#59-5647	#60-5705
#61-5616	#62-5678	#63-5357	#64-5613	#65-5434	#66-5399	#67-5516	#68-5295	#69-5269	#70-5581
#71-5283	#72-5573	#73-5569	#74-5383	#75-5576	#76-5380	#77-5305	#78-5532	#79-5505	#80-5690
#81-5527	#82-5442	#83-5325	#84-5514	#85-5354	#86-5333	#87-5303	#88-5264	#89-5256	#90-5595
#91-5342	#92-5337	#93-5596	#94-5501	#95-5491	#96-5564	#97-5317	#98-5570	#99-5448	#100-5309

Type 6 #8 [Back to Summary]									
#01-5431	#02-5695	#03-5709	#04-5365	#05-5449	#06-5266	#07-5651	#08-5401	#09-5591	#10-5420
#11-5358	#12-5610	#13-5634	#14-5585	#15-5639	#16-5497	#17-5704	#18-5559	#19-5313	#20-5376
#21-5706	#22-5287	#23-5693	#24-5250	#25-5517	#26-5589	#27-5260	#28-5439	#29-5285	#30-5375
#31-5479	#32-5315	#33-5548	#34-5252	#35-5384	#36-5349	#37-5663	#38-5539	#39-5489	#40-5330
#41-5444	#42-5476	#43-5641	#44-5674	#45-5379	#46-5257	#47-5586	#48-5719	#49-5584	#50-5482
#51-5507	#52-5322	#53-5327	#54-5394	#55-5708	#56-5572	#57-5255	#58-5462	#59-5665	#60-5295
#61-5604	#62-5544	#63-5336	#64-5582	#65-5505	#66-5398	#67-5291	#68-5269	#69-5512	#70-5535
#71-5302	#72-5301	#73-5387	#74-5724	#75-5577	#76-5317	#77-5618	#78-5697	#79-5718	#80-5470
#81-5583	#82-5381	#83-5340	#84-5679	#85-5483	#86-5593	#87-5328	#88-5595	#89-5319	#90-5645
#91-5403	#92-5571	#93-5542	#94-5463	#95-5683	#96-5276	#97-5540	#98-5657	#99-5435	#100-5253

Type 6 #9 [Back to Summary]									
#01-5256	#02-5609	#03-5324	#04-5598	#05-5401	#06-5631	#07-5551	#08-5590	#09-5724	#10-5373
#11-5282	#12-5675	#13-5315	#14-5427	#15-5434	#16-5431	#17-5706	#18-5552	#19-5661	#20-5571
#21-5496	#22-5444	#23-5499	#24-5405	#25-5264	#26-5691	#27-5655	#28-5432	#29-5433	#30-5629
#31-5477	#32-5709	#33-5253	#34-5662	#35-5413	#36-5257	#37-5305	#38-5403	#39-5682	#40-5538
#41-5591	#42-5397	#43-5617	#44-5573	#45-5356	#46-5583	#47-5493	#48-5607	#49-5317	#50-5409
#51-5363	#52-5604	#53-5348	#54-5721	#55-5585	#56-5660	#57-5250	#58-5666	#59-5574	#60-5296
#61-5364	#62-5563	#63-5443	#64-5430	#65-5312	#66-5712	#67-5543	#68-5544	#69-5605	#70-5418
#71-5539	#72-5632	#73-5371	#74-5367	#75-5548	#76-5390	#77-5664	#78-5482	#79-5272	#80-5608
#81-5596	#82-5447	#83-5520	#84-5370	#85-5265	#86-5689	#87-5545	#88-5304	#89-5380	#90-5650
#91-5521	#92-5505	#93-5382	#94-5436	#95-5716	#96-5698	#97-5441	#98-5714	#99-5467	#100-5361

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 170 of 177

Type 6 #10 [Back to Summary]									
#01-5584	#02-5252	#03-5342	#04-5273	#05-5481	#06-5495	#07-5572	#08-5306	#09-5473	#10-5515
#11-5272	#12-5397	#13-5485	#14-5264	#15-5523	#16-5667	#17-5336	#18-5700	#19-5316	#20-5712
#21-5623	#22-5594	#23-5408	#24-5349	#25-5684	#26-5422	#27-5325	#28-5297	#29-5400	#30-5372
#31-5458	#32-5274	#33-5655	#34-5258	#35-5544	#36-5263	#37-5596	#38-5521	#39-5526	#40-5533
#41-5593	#42-5298	#43-5715	#44-5359	#45-5640	#46-5676	#47-5702	#48-5275	#49-5281	#50-5354
#51-5429	#52-5479	#53-5463	#54-5569	#55-5717	#56-5314	#57-5309	#58-5420	#59-5525	#60-5631
#61-5350	#62-5307	#63-5723	#64-5466	#65-5476	#66-5445	#67-5510	#68-5320	#69-5540	#70-5423
#71-5508	#72-5428	#73-5279	#74-5545	#75-5418	#76-5714	#77-5293	#78-5470	#79-5348	#80-5271
#81-5369	#82-5268	#83-5444	#84-5425	#85-5520	#86-5554	#87-5419	#88-5603	#89-5457	#90-5467
#91-5363	#92-5687	#93-5672	#94-5657	#95-5361	#96-5424	#97-5449	#98-5506	#99-5490	#100-5685

Type 6 #11 [Back to Summary]									
#01-5539	#02-5565	#03-5646	#04-5301	#05-5433	#06-5419	#07-5400	#08-5253	#09-5270	#10-5563
#11-5322	#12-5503	#13-5512	#14-5332	#15-5588	#16-5403	#17-5290	#18-5680	#19-5616	#20-5340
#21-5442	#22-5681	#23-5395	#24-5420	#25-5316	#26-5598	#27-5485	#28-5602	#29-5594	#30-5271
#31-5566	#32-5506	#33-5408	#34-5454	#35-5603	#36-5648	#37-5374	#38-5336	#39-5385	#40-5268
#41-5600	#42-5436	#43-5629	#44-5291	#45-5480	#46-5425	#47-5590	#48-5319	#49-5683	#50-5383
#51-5494	#52-5615	#53-5399	#54-5493	#55-5456	#56-5608	#57-5501	#58-5605	#59-5367	#60-5545
#61-5640	#62-5375	#63-5401	#64-5541	#65-5721	#66-5353	#67-5709	#68-5479	#69-5641	#70-5593
#71-5567	#72-5621	#73-5302	#74-5665	#75-5258	#76-5415	#77-5644	#78-5461	#79-5502	#80-5675
#81-5356	#82-5722	#83-5720	#84-5397	#85-5694	#86-5564	#87-5352	#88-5474	#89-5285	#90-5337
#91-5535	#92-5483	#93-5321	#94-5711	#95-5335	#96-5453	#97-5466	#98-5625	#99-5384	#100-5327

Type 6 #12 [Back to Summary]									
#01-5651	#02-5560	#03-5556	#04-5397	#05-5665	#06-5475	#07-5537	#08-5455	#09-5289	#10-5529
#11-5614	#12-5437	#13-5605	#14-5714	#15-5332	#16-5623	#17-5641	#18-5694	#19-5342	#20-5585
#21-5690	#22-5543	#23-5431	#24-5544	#25-5271	#26-5329	#27-5441	#28-5719	#29-5602	#30-5540
#31-5279	#32-5412	#33-5413	#34-5250	#35-5553	#36-5468	#37-5277	#38-5268	#39-5345	#40-5297
#41-5255	#42-5593	#43-5609	#44-5356	#45-5346	#46-5370	#47-5319	#48-5251	#49-5358	#50-5558
#51-5699	#52-5591	#53-5578	#54-5483	#55-5656	#56-5516	#57-5395	#58-5264	#59-5670	#60-5713
#61-5448	#62-5443	#63-5550	#64-5331	#65-5568	#66-5404	#67-5341	#68-5324	#69-5490	#70-5642
#71-5563	#72-5660	#73-5639	#74-5708	#75-5320	#76-5649	#77-5600	#78-5322	#79-5645	#80-5405
#81-5547	#82-5396	#83-5485	#84-5457	#85-5254	#86-5399	#87-5610	#88-5266	#89-5257	#90-5410
#91-5637	#92-5520	#93-5476	#94-5571	#95-5267	#96-5484	#97-5458	#98-5673	#99-5291	#100-5644

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 171 of 177

Type 6 #13 [Back to Summary]

#01-5720	#02-5601	#03-5412	#04-5668	#05-5271	#06-5536	#07-5641	#08-5665	#09-5292	#10-5256
#11-5252	#12-5660	#13-5497	#14-5592	#15-5378	#16-5609	#17-5319	#18-5341	#19-5281	#20-5520
#21-5555	#22-5499	#23-5437	#24-5423	#25-5278	#26-5468	#27-5627	#28-5646	#29-5703	#30-5598
#31-5355	#32-5400	#33-5541	#34-5295	#35-5310	#36-5323	#37-5350	#38-5317	#39-5367	#40-5631
#41-5518	#42-5353	#43-5704	#44-5450	#45-5383	#46-5414	#47-5642	#48-5495	#49-5339	#50-5470
#51-5599	#52-5699	#53-5637	#54-5572	#55-5508	#56-5422	#57-5287	#58-5371	#59-5277	#60-5379
#61-5554	#62-5346	#63-5300	#64-5493	#65-5563	#66-5259	#67-5687	#68-5683	#69-5419	#70-5488
#71-5382	#72-5345	#73-5644	#74-5652	#75-5444	#76-5299	#77-5268	#78-5494	#79-5481	#80-5586
#81-5681	#82-5585	#83-5311	#84-5320	#85-5260	#86-5397	#87-5530	#88-5540	#89-5653	#90-5279
#91-5721	#92-5604	#93-5388	#94-5523	#95-5606	#96-5544	#97-5404	#98-5684	#99-5325	#100-5575

Type 6 #14 [Back to Summary]

#01-5338	#02-5503	#03-5305	#04-5709	#05-5378	#06-5458	#07-5404	#08-5518	#09-5614	#10-5416
#11-5422	#12-5694	#13-5285	#14-5704	#15-5483	#16-5493	#17-5586	#18-5407	#19-5392	#20-5491
#21-5459	#22-5385	#23-5466	#24-5505	#25-5379	#26-5563	#27-5370	#28-5311	#29-5675	#30-5326
#31-5431	#32-5722	#33-5509	#34-5461	#35-5707	#36-5482	#37-5265	#38-5413	#39-5402	#40-5332
#41-5498	#42-5486	#43-5356	#44-5437	#45-5690	#46-5554	#47-5571	#48-5674	#49-5448	#50-5301
#51-5542	#52-5541	#53-5558	#54-5366	#55-5677	#56-5286	#57-5524	#58-5580	#59-5539	#60-5337
#61-5342	#62-5568	#63-5538	#64-5710	#65-5425	#66-5434	#67-5548	#68-5251	#69-5477	#70-5423
#71-5255	#72-5310	#73-5718	#74-5697	#75-5279	#76-5278	#77-5549	#78-5716	#79-5421	#80-5588
#81-5623	#82-5508	#83-5430	#84-5676	#85-5345	#86-5445	#87-5557	#88-5587	#89-5719	#90-5405
#91-5643	#92-5543	#93-5452	#94-5515	#95-5369	#96-5272	#97-5446	#98-5481	#99-5565	#100-5393

Type 6 #15 [Back to Summary]

#01-5648	#02-5257	#03-5709	#04-5280	#05-5547	#06-5641	#07-5479	#08-5669	#09-5279	#10-5525
#11-5720	#12-5483	#13-5453	#14-5692	#15-5531	#16-5261	#17-5591	#18-5392	#19-5315	#20-5562
#21-5304	#22-5460	#23-5551	#24-5274	#25-5430	#26-5694	#27-5468	#28-5391	#29-5324	#30-5389
#31-5442	#32-5673	#33-5360	#34-5676	#35-5355	#36-5437	#37-5481	#38-5526	#39-5289	#40-5327
#41-5651	#42-5698	#43-5514	#44-5519	#45-5611	#46-5544	#47-5640	#48-5537	#49-5502	#50-5573
#51-5415	#52-5253	#53-5339	#54-5431	#55-5684	#56-5575	#57-5578	#58-5422	#59-5338	#60-5594
#61-5614	#62-5333	#63-5296	#64-5372	#65-5501	#66-5587	#67-5343	#68-5504	#69-5314	#70-5353
#71-5713	#72-5636	#73-5330	#74-5671	#75-5624	#76-5480	#77-5400	#78-5484	#79-5475	#80-5511
#81-5593	#82-5508	#83-5357	#84-5642	#85-5255	#86-5521	#87-5435	#88-5630	#89-5354	#90-5567
#91-5472	#92-5488	#93-5292	#94-5283	#95-5438	#96-5470	#97-5427	#98-5342	#99-5258	#100-5491

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 172 of 177

Type 6 #16 [Back to Summary]									
#01-5531	#02-5454	#03-5281	#04-5428	#05-5662	#06-5587	#07-5332	#08-5252	#09-5465	#10-5513
#11-5265	#12-5638	#13-5669	#14-5338	#15-5708	#16-5362	#17-5642	#18-5323	#19-5701	#20-5297
#21-5307	#22-5257	#23-5305	#24-5357	#25-5653	#26-5478	#27-5423	#28-5372	#29-5330	#30-5579
#31-5401	#32-5448	#33-5316	#34-5645	#35-5692	#36-5699	#37-5271	#38-5621	#39-5352	#40-5684
#41-5473	#42-5379	#43-5427	#44-5458	#45-5299	#46-5325	#47-5552	#48-5344	#49-5268	#50-5282
#51-5444	#52-5474	#53-5447	#54-5700	#55-5321	#56-5550	#57-5659	#58-5578	#59-5554	#60-5342
#61-5432	#62-5724	#63-5309	#64-5518	#65-5614	#66-5641	#67-5442	#68-5635	#69-5365	#70-5348
#71-5680	#72-5400	#73-5679	#74-5557	#75-5703	#76-5660	#77-5347	#78-5544	#79-5710	#80-5721
#81-5546	#82-5682	#83-5594	#84-5670	#85-5392	#86-5290	#87-5417	#88-5317	#89-5259	#90-5501
#91-5319	#92-5634	#93-5569	#94-5383	#95-5608	#96-5704	#97-5327	#98-5293	#99-5519	#100-5393

Type 6 #17 [Back to Summary]									
#01-5343	#02-5614	#03-5465	#04-5400	#05-5456	#06-5522	#07-5446	#08-5253	#09-5487	#10-5561
#11-5640	#12-5296	#13-5497	#14-5699	#15-5698	#16-5308	#17-5512	#18-5333	#19-5669	#20-5520
#21-5633	#22-5276	#23-5599	#24-5295	#25-5464	#26-5627	#27-5256	#28-5326	#29-5469	#30-5638
#31-5429	#32-5443	#33-5526	#34-5567	#35-5502	#36-5550	#37-5267	#38-5585	#39-5462	#40-5305
#41-5470	#42-5557	#43-5323	#44-5654	#45-5336	#46-5360	#47-5667	#48-5255	#49-5586	#50-5539
#51-5685	#52-5574	#53-5604	#54-5309	#55-5435	#56-5588	#57-5590	#58-5354	#59-5717	#60-5620
#61-5439	#62-5651	#63-5268	#64-5647	#65-5460	#66-5578	#67-5695	#68-5381	#69-5483	#70-5495
#71-5472	#72-5457	#73-5587	#74-5325	#75-5678	#76-5670	#77-5683	#78-5353	#79-5684	#80-5251
#81-5655	#82-5677	#83-5579	#84-5564	#85-5467	#86-5382	#87-5637	#88-5592	#89-5544	#90-5390
#91-5535	#92-5534	#93-5293	#94-5463	#95-5367	#96-5388	#97-5447	#98-5359	#99-5635	#100-5644

Type 6 #18 [Back to Summary]									
#01-5396	#02-5613	#03-5660	#04-5438	#05-5437	#06-5337	#07-5695	#08-5606	#09-5263	#10-5478
#11-5724	#12-5533	#13-5523	#14-5583	#15-5604	#16-5615	#17-5600	#18-5293	#19-5511	#20-5527
#21-5477	#22-5449	#23-5688	#24-5398	#25-5442	#26-5360	#27-5611	#28-5464	#29-5462	#30-5425
#31-5270	#32-5273	#33-5252	#34-5290	#35-5490	#36-5703	#37-5631	#38-5401	#39-5357	#40-5451
#41-5430	#42-5562	#43-5470	#44-5637	#45-5536	#46-5250	#47-5555	#48-5435	#49-5476	#50-5513
#51-5403	#52-5572	#53-5358	#54-5417	#55-5672	#56-5650	#57-5721	#58-5326	#59-5480	#60-5394
#61-5457	#62-5701	#63-5530	#64-5483	#65-5342	#66-5626	#67-5708	#68-5448	#69-5661	#70-5310
#71-5347	#72-5640	#73-5704	#74-5301	#75-5587	#76-5441	#77-5426	#78-5710	#79-5591	#80-5619
#81-5597	#82-5543	#83-5303	#84-5370	#85-5405	#86-5280	#87-5674	#88-5632	#89-5429	#90-5560
#91-5445	#92-5321	#93-5681	#94-5492	#95-5314	#96-5467	#97-5260	#98-5502	#99-5693	#100-5599

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 173 of 177

Type 6 #19 [Back to Summary]									
#01-5649	#02-5529	#03-5520	#04-5274	#05-5598	#06-5408	#07-5650	#08-5591	#09-5525	#10-5636
#11-5610	#12-5524	#13-5572	#14-5588	#15-5293	#16-5630	#17-5310	#18-5397	#19-5472	#20-5321
#21-5596	#22-5276	#23-5721	#24-5458	#25-5334	#26-5468	#27-5373	#28-5639	#29-5608	#30-5345
#31-5575	#32-5429	#33-5445	#34-5600	#35-5485	#36-5700	#37-5325	#38-5259	#39-5706	#40-5562
#41-5285	#42-5534	#43-5436	#44-5542	#45-5359	#46-5628	#47-5270	#48-5451	#49-5280	#50-5621
#51-5252	#52-5622	#53-5533	#54-5311	#55-5665	#56-5674	#57-5328	#58-5467	#59-5277	#60-5514
#61-5393	#62-5418	#63-5395	#64-5335	#65-5463	#66-5340	#67-5283	#68-5716	#69-5437	#70-5272
#71-5517	#72-5540	#73-5564	#74-5551	#75-5536	#76-5269	#77-5315	#78-5678	#79-5426	#80-5547
#81-5316	#82-5424	#83-5284	#84-5376	#85-5319	#86-5399	#87-5506	#88-5647	#89-5592	#90-5690
#91-5577	#92-5417	#93-5365	#94-5530	#95-5693	#96-5631	#97-5346	#98-5289	#99-5398	#100-5384

Type 6 #20 [Back to Summary]									
#01-5350	#02-5501	#03-5655	#04-5422	#05-5257	#06-5449	#07-5720	#08-5692	#09-5570	#10-5351
#11-5695	#12-5300	#13-5669	#14-5393	#15-5437	#16-5663	#17-5566	#18-5649	#19-5574	#20-5329
#21-5698	#22-5369	#23-5322	#24-5477	#25-5498	#26-5398	#27-5457	#28-5641	#29-5384	#30-5611
#31-5717	#32-5694	#33-5376	#34-5414	#35-5701	#36-5448	#37-5597	#38-5723	#39-5640	#40-5476
#41-5446	#42-5315	#43-5572	#44-5343	#45-5280	#46-5314	#47-5415	#48-5473	#49-5534	#50-5271
#51-5527	#52-5535	#53-5505	#54-5675	#55-5484	#56-5653	#57-5380	#58-5560	#59-5413	#60-5677
#61-5424	#62-5310	#63-5590	#64-5407	#65-5627	#66-5301	#67-5575	#68-5472	#69-5648	#70-5256
#71-5630	#72-5304	#73-5427	#74-5577	#75-5530	#76-5445	#77-5387	#78-5432	#79-5673	#80-5573
#81-5604	#82-5600	#83-5718	#84-5497	#85-5274	#86-5489	#87-5711	#88-5346	#89-5610	#90-5626
#91-5619	#92-5283	#93-5507	#94-5286	#95-5684	#96-5582	#97-5305	#98-5599	#99-5517	#100-5307

Type 6 #21 [Back to Summary]									
#01-5326	#02-5575	#03-5364	#04-5275	#05-5494	#06-5476	#07-5461	#08-5619	#09-5714	#10-5414
#11-5379	#12-5276	#13-5336	#14-5426	#15-5375	#16-5288	#17-5355	#18-5261	#19-5376	#20-5271
#21-5645	#22-5378	#23-5522	#24-5409	#25-5690	#26-5473	#27-5340	#28-5518	#29-5717	#30-5506
#31-5368	#32-5647	#33-5481	#34-5432	#35-5635	#36-5496	#37-5495	#38-5600	#39-5374	#40-5472
#41-5546	#42-5612	#43-5458	#44-5568	#45-5632	#46-5395	#47-5598	#48-5405	#49-5655	#50-5573
#51-5713	#52-5588	#53-5448	#54-5387	#55-5673	#56-5302	#57-5680	#58-5310	#59-5385	#60-5668
#61-5626	#62-5295	#63-5457	#64-5519	#65-5628	#66-5516	#67-5604	#68-5479	#69-5611	#70-5629
#71-5449	#72-5282	#73-5644	#74-5679	#75-5501	#76-5545	#77-5660	#78-5394	#79-5505	#80-5710
#81-5687	#82-5443	#83-5539	#84-5540	#85-5352	#86-5603	#87-5711	#88-5250	#89-5523	#90-5425
#91-5694	#92-5614	#93-5300	#94-5304	#95-5483	#96-5701	#97-5544	#98-5296	#99-5354	#100-5278

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 174 of 177

Type 6 #22 [Back to Summary]									
#01-5348	#02-5429	#03-5489	#04-5396	#05-5450	#06-5330	#07-5482	#08-5665	#09-5515	#10-5258
#11-5534	#12-5583	#13-5553	#14-5410	#15-5704	#16-5664	#17-5508	#18-5543	#19-5571	#20-5296
#21-5643	#22-5406	#23-5326	#24-5670	#25-5631	#26-5295	#27-5537	#28-5339	#29-5284	#30-5528
#31-5629	#32-5663	#33-5658	#34-5345	#35-5359	#36-5300	#37-5681	#38-5610	#39-5522	#40-5478
#41-5310	#42-5417	#43-5315	#44-5360	#45-5615	#46-5325	#47-5544	#48-5442	#49-5251	#50-5308
#51-5667	#52-5353	#53-5404	#54-5517	#55-5393	#56-5630	#57-5711	#58-5596	#59-5619	#60-5594
#61-5613	#62-5551	#63-5657	#64-5298	#65-5542	#66-5398	#67-5633	#68-5604	#69-5520	#70-5709
#71-5647	#72-5263	#73-5464	#74-5335	#75-5628	#76-5462	#77-5606	#78-5548	#79-5403	#80-5256
#81-5481	#82-5441	#83-5456	#84-5255	#85-5334	#86-5271	#87-5313	#88-5444	#89-5416	#90-5549
#91-5656	#92-5616	#93-5318	#94-5401	#95-5490	#96-5501	#97-5519	#98-5694	#99-5419	#100-5595

Type 6 #23 [Back to Summary]									
#01-5379	#02-5416	#03-5625	#04-5449	#05-5383	#06-5286	#07-5320	#08-5637	#09-5587	#10-5381
#11-5359	#12-5451	#13-5293	#14-5458	#15-5428	#16-5376	#17-5569	#18-5410	#19-5328	#20-5543
#21-5347	#22-5532	#23-5444	#24-5559	#25-5311	#26-5366	#27-5297	#28-5608	#29-5536	#30-5542
#31-5472	#32-5384	#33-5680	#34-5712	#35-5371	#36-5589	#37-5310	#38-5406	#39-5345	#40-5593
#41-5524	#42-5506	#43-5592	#44-5358	#45-5282	#46-5323	#47-5392	#48-5599	#49-5503	#50-5616
#51-5601	#52-5498	#53-5572	#54-5430	#55-5614	#56-5322	#57-5644	#58-5273	#59-5278	#60-5300
#61-5564	#62-5612	#63-5414	#64-5633	#65-5502	#66-5440	#67-5254	#68-5705	#69-5349	#70-5646
#71-5448	#72-5434	#73-5664	#74-5258	#75-5663	#76-5692	#77-5677	#78-5333	#79-5698	#80-5465
#81-5662	#82-5288	#83-5581	#84-5611	#85-5357	#86-5354	#87-5665	#88-5699	#89-5713	#90-5486
#91-5321	#92-5609	#93-5685	#94-5619	#95-5504	#96-5607	#97-5388	#98-5618	#99-5403	#100-5694

Type 6 #24 [Back to Summary]									
#01-5402	#02-5313	#03-5633	#04-5600	#05-5492	#06-5647	#07-5369	#08-5560	#09-5299	#10-5537
#11-5363	#12-5525	#13-5280	#14-5253	#15-5272	#16-5394	#17-5336	#18-5314	#19-5256	#20-5360
#21-5410	#22-5376	#23-5550	#24-5371	#25-5297	#26-5294	#27-5513	#28-5478	#29-5554	#30-5341
#31-5327	#32-5293	#33-5610	#34-5612	#35-5257	#36-5548	#37-5449	#38-5423	#39-5301	#40-5594
#41-5651	#42-5271	#43-5321	#44-5428	#45-5588	#46-5424	#47-5427	#48-5359	#49-5521	#50-5324
#51-5292	#52-5534	#53-5276	#54-5487	#55-5511	#56-5552	#57-5448	#58-5383	#59-5616	#60-5683
#61-5459	#62-5320	#63-5640	#64-5393	#65-5721	#66-5669	#67-5582	#68-5615	#69-5680	#70-5491
#71-5484	#72-5354	#73-5479	#74-5668	#75-5430	#76-5339	#77-5300	#78-5444	#79-5545	#80-5406
#81-5567	#82-5706	#83-5310	#84-5663	#85-5650	#86-5700	#87-5642	#88-5702	#89-5644	#90-5586
#91-5358	#92-5495	#93-5445	#94-5703	#95-5414	#96-5433	#97-5656	#98-5526	#99-5646	#100-5258

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 175 of 177

Type 6 #25 [Back to Summary]									
#01-5568	#02-5665	#03-5267	#04-5294	#05-5565	#06-5536	#07-5388	#08-5456	#09-5638	#10-5322
#11-5315	#12-5264	#13-5256	#14-5656	#15-5640	#16-5287	#17-5513	#18-5564	#19-5291	#20-5617
#21-5559	#22-5367	#23-5710	#24-5636	#25-5279	#26-5606	#27-5545	#28-5474	#29-5277	#30-5309
#31-5302	#32-5345	#33-5682	#34-5598	#35-5387	#36-5357	#37-5650	#38-5380	#39-5444	#40-5422
#41-5379	#42-5413	#43-5408	#44-5257	#45-5517	#46-5619	#47-5262	#48-5460	#49-5605	#50-5366
#51-5258	#52-5548	#53-5282	#54-5382	#55-5492	#56-5507	#57-5506	#58-5635	#59-5414	#60-5281
#61-5288	#62-5680	#63-5335	#64-5671	#65-5376	#66-5365	#67-5486	#68-5669	#69-5580	#70-5473
#71-5482	#72-5596	#73-5599	#74-5579	#75-5541	#76-5428	#77-5661	#78-5337	#79-5411	#80-5465
#81-5575	#82-5393	#83-5469	#84-5280	#85-5390	#86-5341	#87-5457	#88-5478	#89-5497	#90-5310
#91-5455	#92-5610	#93-5254	#94-5490	#95-5604	#96-5426	#97-5634	#98-5259	#99-5632	#100-5608

Type 6 #26 [Back to Summary]									
#01-5559	#02-5252	#03-5471	#04-5501	#05-5399	#06-5548	#07-5510	#08-5282	#09-5673	#10-5481
#11-5606	#12-5697	#13-5266	#14-5335	#15-5528	#16-5489	#17-5265	#18-5254	#19-5348	#20-5538
#21-5442	#22-5374	#23-5393	#24-5537	#25-5663	#26-5306	#27-5444	#28-5532	#29-5473	#30-5555
#31-5610	#32-5664	#33-5485	#34-5586	#35-5445	#36-5388	#37-5594	#38-5681	#39-5329	#40-5674
#41-5525	#42-5527	#43-5506	#44-5378	#45-5373	#46-5517	#47-5587	#48-5325	#49-5662	#50-5619
#51-5255	#52-5344	#53-5415	#54-5434	#55-5583	#56-5659	#57-5563	#58-5342	#59-5354	#60-5702
#61-5534	#62-5368	#63-5596	#64-5666	#65-5462	#66-5405	#67-5614	#68-5390	#69-5309	#70-5649
#71-5262	#72-5640	#73-5592	#74-5264	#75-5413	#76-5396	#77-5636	#78-5456	#79-5536	#80-5660
#81-5604	#82-5376	#83-5420	#84-5260	#85-5529	#86-5367	#87-5711	#88-5569	#89-5547	#90-5718
#91-5507	#92-5431	#93-5305	#94-5432	#95-5642	#96-5292	#97-5560	#98-5330	#99-5332	#100-5500

Type 6 #27 [Back to Summary]									
#01-5567	#02-5568	#03-5495	#04-5417	#05-5623	#06-5442	#07-5496	#08-5722	#09-5432	#10-5717
#11-5539	#12-5321	#13-5709	#14-5604	#15-5585	#16-5684	#17-5666	#18-5663	#19-5554	#20-5439
#21-5647	#22-5454	#23-5482	#24-5707	#25-5340	#26-5261	#27-5718	#28-5521	#29-5493	#30-5349
#31-5523	#32-5713	#33-5308	#34-5645	#35-5418	#36-5685	#37-5414	#38-5675	#39-5337	#40-5376
#41-5301	#42-5720	#43-5680	#44-5514	#45-5616	#46-5708	#47-5448	#48-5288	#49-5324	#50-5332
#51-5619	#52-5392	#53-5558	#54-5617	#55-5578	#56-5362	#57-5336	#58-5513	#59-5326	#60-5611
#61-5449	#62-5699	#63-5479	#64-5333	#65-5443	#66-5551	#67-5262	#68-5313	#69-5435	#70-5624
#71-5520	#72-5715	#73-5576	#74-5427	#75-5387	#76-5651	#77-5498	#78-5693	#79-5356	#80-5538
#81-5679	#82-5446	#83-5411	#84-5381	#85-5404	#86-5416	#87-5317	#88-5305	#89-5599	#90-5625
#91-5450	#92-5652	#93-5327	#94-5491	#95-5597	#96-5315	#97-5696	#98-5384	#99-5425	#100-5536

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Title: Samsung Electronics Co., Ltd. WEA524i
To: FCC CFR 47 Part 15 Subpart E 15.407 & ISED RSS-247
Serial #: CTKL04-U2 Rev A (Limited to DFS testing)
Issue Date: 16th August 2017
Page: 176 of 177

Type 6 #28 [Back to Summary]									
#01-5628	#02-5540	#03-5381	#04-5479	#05-5651	#06-5589	#07-5368	#08-5422	#09-5694	#10-5322
#11-5494	#12-5502	#13-5317	#14-5603	#15-5311	#16-5396	#17-5571	#18-5721	#19-5380	#20-5274
#21-5620	#22-5366	#23-5375	#24-5500	#25-5310	#26-5410	#27-5625	#28-5621	#29-5275	#30-5385
#31-5404	#32-5351	#33-5271	#34-5599	#35-5551	#36-5565	#37-5273	#38-5661	#39-5390	#40-5440
#41-5481	#42-5453	#43-5629	#44-5377	#45-5407	#46-5549	#47-5423	#48-5719	#49-5259	#50-5643
#51-5374	#52-5387	#53-5447	#54-5400	#55-5641	#56-5512	#57-5415	#58-5605	#59-5419	#60-5491
#61-5689	#62-5471	#63-5559	#64-5392	#65-5443	#66-5302	#67-5470	#68-5373	#69-5634	#70-5581
#71-5664	#72-5517	#73-5416	#74-5462	#75-5722	#76-5342	#77-5486	#78-5712	#79-5630	#80-5611
#81-5357	#82-5260	#83-5267	#84-5595	#85-5683	#86-5288	#87-5492	#88-5624	#89-5476	#90-5307
#91-5319	#92-5459	#93-5265	#94-5705	#95-5667	#96-5514	#97-5519	#98-5465	#99-5530	#100-5508

Type 6 #29 [Back to Summary]									
#01-5607	#02-5474	#03-5299	#04-5418	#05-5513	#06-5657	#07-5504	#08-5308	#09-5584	#10-5288
#11-5548	#12-5625	#13-5488	#14-5611	#15-5484	#16-5263	#17-5320	#18-5705	#19-5392	#20-5682
#21-5438	#22-5507	#23-5359	#24-5327	#25-5256	#26-5687	#27-5347	#28-5562	#29-5520	#30-5461
#31-5370	#32-5712	#33-5458	#34-5713	#35-5707	#36-5604	#37-5559	#38-5417	#39-5401	#40-5268
#41-5496	#42-5558	#43-5501	#44-5431	#45-5470	#46-5654	#47-5443	#48-5539	#49-5322	#50-5573
#51-5350	#52-5365	#53-5632	#54-5630	#55-5435	#56-5489	#57-5497	#58-5346	#59-5486	#60-5450
#61-5278	#62-5414	#63-5367	#64-5623	#65-5276	#66-5274	#67-5338	#68-5557	#69-5270	#70-5356
#71-5341	#72-5621	#73-5679	#74-5550	#75-5711	#76-5511	#77-5283	#78-5629	#79-5273	#80-5447
#81-5613	#82-5300	#83-5612	#84-5342	#85-5331	#86-5326	#87-5319	#88-5597	#89-5321	#90-5639
#91-5542	#92-5467	#93-5394	#94-5383	#95-5533	#96-5444	#97-5355	#98-5261	#99-5719	#100-5260

Type 6 #30 [Back to Summary]									
#01-5675	#02-5610	#03-5503	#04-5711	#05-5312	#06-5581	#07-5427	#08-5555	#09-5526	#10-5316
#11-5261	#12-5658	#13-5668	#14-5657	#15-5487	#16-5689	#17-5674	#18-5441	#19-5523	#20-5403
#21-5535	#22-5417	#23-5317	#24-5378	#25-5524	#26-5560	#27-5682	#28-5602	#29-5251	#30-5617
#31-5318	#32-5320	#33-5376	#34-5533	#35-5541	#36-5611	#37-5258	#38-5307	#39-5365	#40-5636
#41-5593	#42-5522	#43-5510	#44-5686	#45-5343	#46-5506	#47-5296	#48-5350	#49-5527	#50-5476
#51-5390	#52-5443	#53-5325	#54-5643	#55-5659	#56-5591	#57-5597	#58-5649	#59-5315	#60-5368
#61-5590	#62-5373	#63-5671	#64-5328	#65-5665	#66-5383	#67-5407	#68-5492	#69-5667	#70-5630
#71-5531	#72-5416	#73-5430	#74-5303	#75-5681	#76-5625	#77-5340	#78-5567	#79-5463	#80-5710
#81-5466	#82-5692	#83-5324	#84-5724	#85-5498	#86-5288	#87-5645	#88-5339	#89-5458	#90-5382
#91-5305	#92-5693	#93-5410	#94-5393	#95-5448	#96-5342	#97-5419	#98-5362	#99-5493	#100-5537

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